

**bq34210-Q1**

# **Technical Reference Manual**



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## Preface

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This manual discusses the modules and peripherals of the automotive-qualified AEC-Q100, Grade 3 bq34210-Q1 fuel gauge, and how each is used to build a complete battery pack fuel gauge solution. For further information, refer to the *bq34210-Q1 Automotive 1-Series Cell System-Side CEDV Fuel Gauge for Rarely Discharged Batteries Data Sheet* (SLUSCG1).

### Formatting in This Document

The following formatting convention is used in this document:

- SBS commands: *italics* with parentheses and no breaking spaces; for example, *RemainingCapacity()*
- Data memory: *italics*, **bold**, and breaking spaces; for example, **Design Capacity**
- Register bits and flags: *italics* and brackets; for example, *[TDA]*
- Data memory bits: *italics* and bold; for example, **[LED1]**
- Modes and states: ALL CAPITALS; for example, UNSEALED

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### Glossary

<http://www.ti.com> provides a *Battery Glossary* on the *Battery Management FAQ* page and the *TI Glossary*.

### Related Documentation from Texas Instruments

To obtain a copy of any of the following TI documents, click on the links below:

1. *bq34210-Q1 Automotive 1-Series Cell System-Side CEDV Fuel Gauge for Rarely Discharged Batteries Data Sheet* (SLUSCG1)
2. *Going to Production with the bq275xx Application Report* (SLUA449)
3. *Host System Calibration Method Application Report* (SLUA640)

For more documentation and product information, go to the [bq34210-Q1](#) product page or to the TI Web site at [www.ti.com](http://www.ti.com).

## General Description

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The bq34210-Q1 fuel gauge incorporates gas gauging and an End-of-Service (EOS) Determination function to use with a 1-series Li-Ion or Lithium Iron Phosphate (LiFePO<sub>4</sub>) rechargeable cell or a Nickel metal hydride (NiMH) based pack with a configuration of 3-series cells.

The gas gauge uses Compensated End-of-Discharge Voltage (CEDV) gauging technology to accurately predict the battery capacity and other operational characteristics of the battery. It can be interrogated by a system processor to provide cell information, such as remaining capacity, full charge capacity (FCC), time-to-empty (TTE), and relative state-of-charge (RSOC), and provide an interrupt signal to the processor.

The integrated EOS Determination function is specifically intended for applications where the battery is rarely discharged, such as eCall systems, uninterruptible power supplies (UPS), enterprise server backup systems, and telematics or telecommunications backup modules. In such systems, the battery may remain in a fully (or near fully) charged state for much of its lifetime, with it rarely or never undergoing a significant discharge. If the health of the battery in such a system is not monitored regularly, then it may degrade beyond the level required for a system backup/discharge event, and thus fail precisely at the time when it is needed most. Monitoring the battery enables the system to take action before the failure occurs.

The EOS Determination function monitors the health of the battery by using infrequent learning phases, which involve a controlled discharge of ~1% capacity, and provides an alert to the system when the battery is approaching the end of its usable service. By coordinating battery charging with the learning phases, the battery capacity available to the system can be maintained above a preselected level to avoid compromising the ability for the battery to support a system discharge event.

Information is accessed through a series of commands, called Data Commands, and indicated by the general format *Command()*. Read and write information within the device control and status registers, as well as its data memory locations are accessed through these commands. Commands are sent from the system to the gauge using the I<sup>2</sup>C serial communications engine, and can be run during application development, system manufacturing, or end-equipment operation.

The fuel gauge measures charge and discharge activity by monitoring the voltage across a small-value series sense resistor (5 mΩ to 20 mΩ, typical), which may be used in a low-side (at the CELL- connection) or a high-side (at the CELL+ connection) configuration.

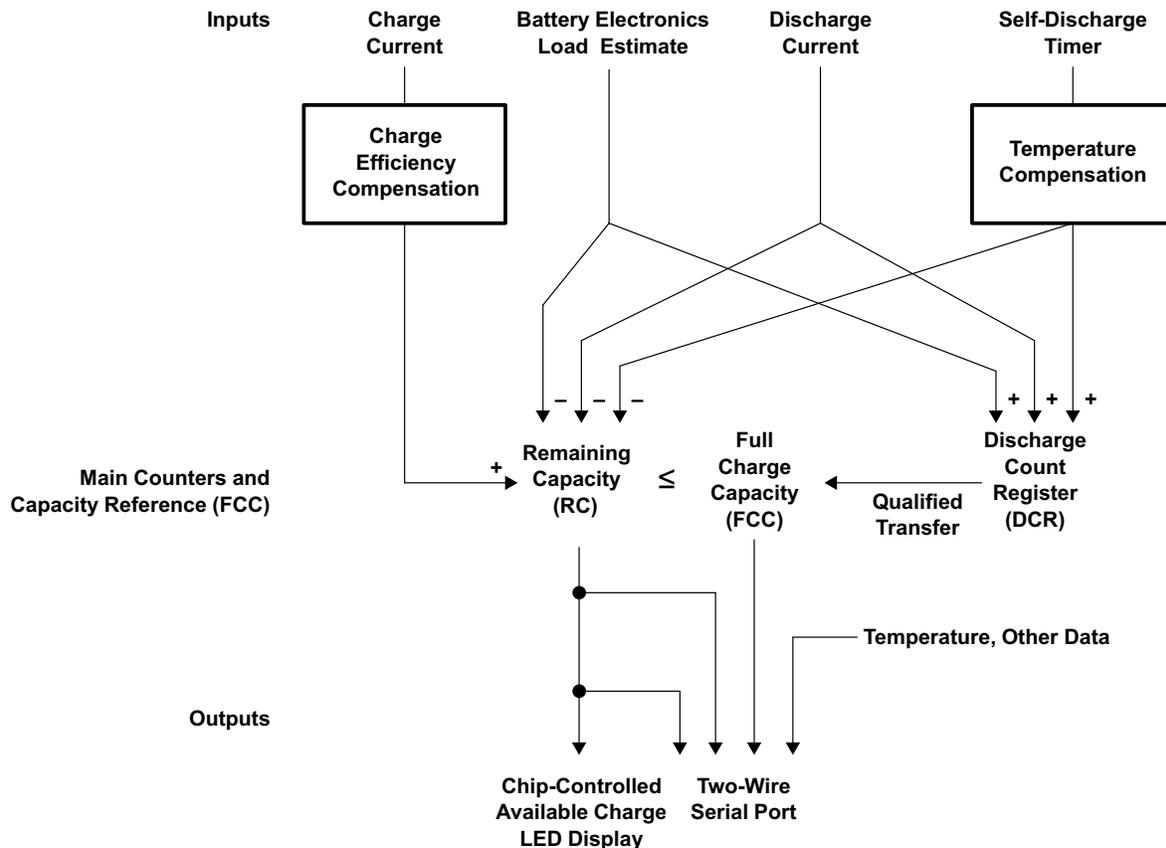
The external temperature sensing is optimized with the use of a high-accuracy negative temperature coefficient (NTC) thermistor with 25°C resistance (R<sub>25</sub>) = 10.0 kΩ ±1% and beta value (B<sub>25/85</sub>, resistance at 25°C and at 85°C) = 3435 kΩ ± 1% (such as Semitec NTC 103AT). Alternatively, the fuel gauge can be configured to use its internal temperature sensor or receive temperature data from the host processor. The fuel gauge uses temperature to monitor the battery-pack environment, which is used for gas gauging and cell protection functionality.

To minimize power consumption, the fuel gauge has several power modes: INITIALIZATION, NORMAL, SLEEP, and SHUTDOWN. The fuel gauge passes automatically between these modes (except for SHUTDOWN exit, which needs an external stimulus), depending upon the occurrence of specific events, though a system processor can initiate some of these modes directly. The device also includes a CONFIG UPDATE mode, which is generally used during initial setup to update various RAM-based parameters used by the gauge.

### 1.1 Gas Gauging

The bq34210-Q1 device features the Compensated End-of-Discharge Voltage (CEDV) gauging algorithm, capable of gauging a maximum capacity of 32 Ah.

Figure 1-1 shows the operational overview of the bq34210-Q1 fuel gauge.



**Figure 1-1. bq34210-Q1 CEDV Gas Gauging Operational Overview**

### 1.1.1 CEDV Gas Gauging Operational Overview

The bq34210-Q1 device accumulates the measured quantities of charge and discharge and estimates self-discharge of the battery. The bq34210-Q1 device compensates the charge current measurement for temperature and the state-of-charge of the battery. The device also adjusts the self-discharge estimation based on temperature. The initial battery state-of-charge estimation on first insertion of the battery pack in the system may display a factor of the true value; the system must go through a full charge and then a full discharge cycle before the correct full-charge capacity (FCC) is estimated.

The main charge counter, *RemainingCapacity()* (RC) register, represents the available capacity or energy in the battery at any given time. The bq34210-Q1 device adjusts RC for charge, self-discharge, and other compensation factors. The information in the RC register is accessible through the I<sup>2</sup>C interface. The *FullChargeCapacity()* (FCC) register represents the initial or last measured full discharge of the battery. It is used as the battery full-charge reference for relative capacity indication. FCC is accessible through the I<sup>2</sup>C interface.

### 1.1.2 Main Fuel Gauge Registers

**Remaining Capacity (RC)** — Remaining capacity in the battery

RC represents the remaining capacity in the battery. The bq34210-Q1 device computes RC in units of mAh.

RC counts up during charge to a maximum value of FCC and down during discharge and self-discharge to a minimum of 0. In addition to charge and self-discharge compensation, the bq34210-Q1 device calibrates RC at three low-battery-voltage thresholds, EDV2, EDV1, and EDV0. This provides a voltage-based calibration to the RC counter.

**Design Capacity (DC)** — User-specified battery full capacity

DC is the user-specified battery full capacity. It is calculated from **Design Capacity mAh** and is represented in units of mAh. It also represents the full-battery reference for the absolute display mode.

**Full Charge Capacity (FCC)** — Last measured discharge capacity of the battery

FCC is the last measured discharge capacity of the battery. It is represented in units of mAh. On initialization, the bq34210-Q1 device sets *FullChargeCapacity()* to the data memory value stored in **Full Charge Capacity (FCC)**. During subsequent discharges, the bq34210-Q1 device updates *FullChargeCapacity()* with the last measured discharge capacity of the battery. Once updated, the bq34210-Q1 device writes the new *FullChargeCapacity()* value to data memory in mAh to **Learned Full Charge Capacity**. *FullChargeCapacity()* represents the full battery reference for the relative display mode and relative state-of-charge calculations.

### 1.1.3 Capacity Learning (FCC Update)

An FCC update occurs if the battery discharges from  $RC \geq FCC - \text{Near Full}$  to the EDV2 voltage threshold with the following conditions:

- No valid charge activity occurs during the discharge period. A valid charge is defined as a charge of 10 mAh into the battery.
- No more than 256 mAh of self-discharge or battery load estimation occurs during the discharge period.
- The temperature does not drop below the low temperature thresholds programmed in **Low Temp** during the discharge period.
- The battery voltage reaches the EDV2 threshold during the discharge period and the voltage is greater than or equal to the EDV2 threshold minus 256 mV when the bq34210-Q1 device detected EDV2.
- Current remains  $\geq 3C/32$  when EDV2 is reached.
- No overload condition exists when EDV2 threshold is reached or if RC has dropped to  $\text{Battery Low \%} \times FCC$ .

The bq34210-Q1 device sets  $[VDQ] = 1$  in *OperationStatus()* when a discharge begins. The bq34210-Q1 device sets  $[VDQ] = 0$  if any disqualifying condition occurs. One complication may arise regarding the state of  $[VDQ]$  if **[CSYNC]** is set in **CEDV Gauging Configuration**. When **[CSYNC]** is enabled, *RemainingCapacity()* is written to equal *FullChargeCapacity()* on valid primary charge termination. This capacity synchronization is done even if the condition  $RC \geq FCC - \text{Near Full}$  is *not* satisfied at charge termination.

FCC cannot be reduced by more than 256 mAh or increased by more than 512 mAh during any single update cycle. If **[FCC\_LIMIT]** is set in **CEDV Gauging Configuration**, then FCC cannot learn above the **Design Capacity mAh**. The bq34210-Q1 device saves the new FCC value to the data memory within 4 s of being updated.

### 1.1.4 End-of-Discharge (EDV) Thresholds and Capacity Correction

The bq34210-Q1 device monitors the battery for three low-voltage thresholds: EDV0, EDV1, and EDV2.

If the **[EDV\_CMP]** bit in **CEDV Gauging Configuration** is clear, fixed EDV thresholds may be programmed in **Fixed EDV0**, **Fixed EDV1**, and **Fixed EDV2** in mV.

If the **[EDV\_CMP]** bit in **CEDV Gauging Configuration** is set, automatic EDV compensation is enabled and the bq34210-Q1 device computes the EDV0, EDV1, and EDV2 thresholds based on values stored in the selected CEDV profile in data memory and the battery's current discharge rate and temperature. If the **[FIXED\_EDV0]** bit in **CEDV Gauging Configuration** is also set, then the EDV0 threshold will be set to the programmed **Fixed EDV0**, and the EDV1 and EDV2 compensated thresholds will not go below the programmed **Fixed EDV0**.

The bq34210-Q1 device disables EDV detection if current exceeds the **Overload Current** threshold. The bq34210-Q1 device resumes EDV threshold detection after current drops below the **Overload Current** threshold. Any EDV threshold detected is reset after charge is applied and  $[VDQ]$  is cleared after 10 mAh of charge.

The bq34210-Q1 device uses the EDV thresholds to apply voltage-based corrections to the RC register (see [Table 1-1](#)).

**Table 1-1. State-of-Charge Based on Low Battery Voltage**

THRESHOLD	RELATIVE STATE OF CHARGE
EDV0	0%
EDV1	3%
EDV2	<b>Battery Low %</b>

The bq34210-Q1 device performs EDV-based RC adjustments with current  $\geq C/32$ . No EDVs are set if current  $< C/32$ . The bq34210-Q1 device adjusts RC as it detects each threshold. If the voltage threshold is reached before the corresponding capacity on discharge, the bq34210-Q1 device reduces RC to the appropriate amount, as shown in [Table 1-1](#).

If an RC % level is reached on discharge before the voltage reaches the corresponding threshold, then RC is held at that % level until the threshold is reached. RC is only held if  $[VDQ] = 1$ , indicating a valid learning cycle is in progress. If **Battery Low %** is set to 0, EDV1 and EDV0 corrections are disabled.

### 1.1.5 EDV Discharge Rate and Temperature Compensation

If EDV compensation is enabled, the bq34210-Q1 device calculates battery voltage to determine EDV0, EDV1, and EDV2 thresholds as a function of battery capacity, temperature, and discharge load. The general equation for EDV0, EDV1, and EDV2 calculation is as follows:

$$EDV_{0,1,2} = n (EMF \times FBL - |I_{LOAD}| \times R0 \times FTZ) \quad (1)$$

- EMF is a no-load cell voltage higher than the highest cell EDV threshold computed. EMF is programmed in mV in the CEDV profile **EMF**.
- $I_{LOAD}$  is the current discharge load magnitude.
- $n$  = the number of series cells. In the bq34210-Q1 case,  $n = 1$ .
- FBL is the factor that adjusts the EDV voltage for battery capacity and temperature to match the no-load characteristics of the battery.

$$FBL = f(C0, C + C1, T) \quad (2)$$

- $C$  (either 0%, 3%, or Battery Low % for EDV0, EDV1, and EDV2, respectively) and  $C0$  are the capacity-related EDV adjustment factors.  $C0$  is programmed in the CEDV profile **C0**.  $C1$  is the desired residual battery capacity remaining at EDV0 ( $RC = 0$ ). The  $C1$  factor is stored in the CEDV profile **C1**.
- $T$  is the current temperature in °K.
- $R0 \times FTZ$  represents the resistance of a cell as a function of temperature and capacity.

$$FTZ = f(R1, T0, C + C1, TC) \quad (3)$$

- $R0$  is the first order rate dependency factor stored in the CEDV profile **R0**.
- $T$  is the current temperature;  $C$  is the battery capacity relating to EDV0, EDV1, and EDV2.
- $R1$  adjusts the variation of impedance with battery capacity.  $R1$  is programmed in the CEDV profile **R1**.
- $T0$  adjusts the variation of impedance with battery temperature.  $T0$  is programmed in the CEDV profile **T0**.
- $TC$  adjusts the variation of impedance for cold temperatures ( $T < 23^\circ\text{C}$ ).  $TC$  is programmed in the CEDV profile **TC**.

The graphs below show the calculated EDV0, EDV1, and EDV2 thresholds versus capacity using the typical compensation values for different temperatures and loads for a Li-Ion 18650 cell. The compensation values vary widely for different cell types and manufacturers and must be matched exactly to the unique characteristics for optimal performance.

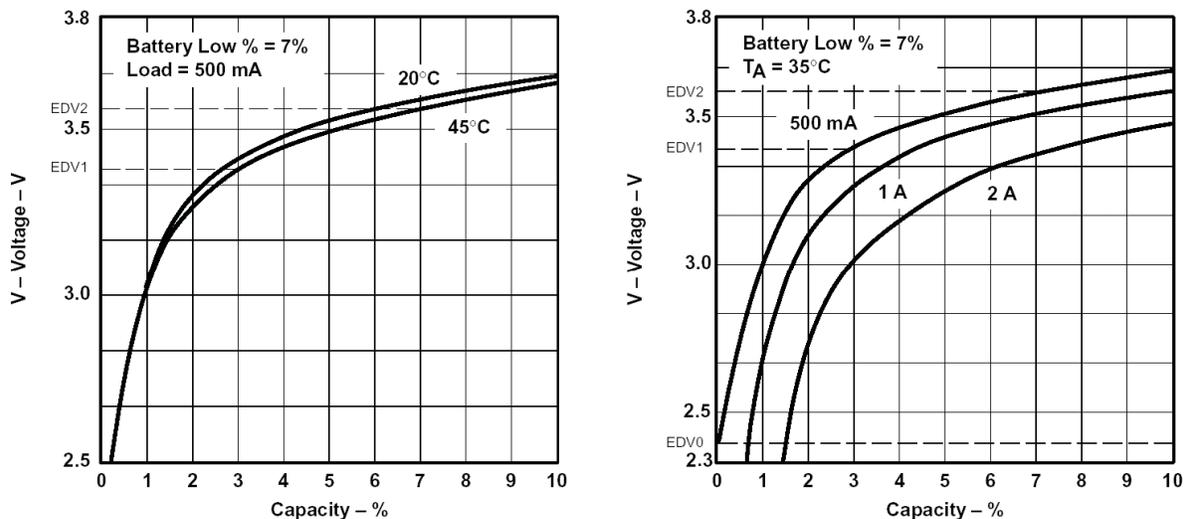


Figure 1-2. (a) EDV Calculations vs Capacity for Various Temperatures, (b) EDV Calculations vs Capacity for Various Loads

### 1.1.6 EDV Age Factor

The EDV **Age Factor** enables the bq34210-Q1 device to correct the EDV detection algorithm to compensate for cell aging. This parameter scales cell impedances as the cycle count increases. This new factor is used to accommodate for much higher impedances observed in larger capacity and/or aged cells. For most applications, the default value of 0 is sufficient; however, for some very specific applications, this new aging factor may be required. In those cases, experimental data must be taken at the 0, 100, 200, and 300 cycle-read points using a typical discharge rate while at ambient temperature. Entering this data into a TI provided MathCAD™ program will yield the appropriate EDV **Age factor** value. Contact TI Applications Support @ <http://www-k.ext.ti.com/sc/technical-support/email-tech-support.asp?AAP> for more detailed information.

### 1.1.7 Self-Discharge

The bq34210-Q1 device estimates the self-discharge of the battery to maintain an accurate measure of the battery capacity during periods of inactivity. The bq34210-Q1 device makes self-discharge adjustments to RC every 1/4 second when awake and periodically when in SLEEP mode. The period is determined by **Sleep Current Time**.

The nominal self-discharge rate, %PERDAY (% per day), is programmed in an 8-bit value **Self-Discharge Rate** by the following relation:

$$\text{Self-Discharge Rate} = \%PERDAY/0.0025$$

### 1.1.8 Battery Electronic Load Compensation

The bq34210-Q1 device can be configured to compensate for a constant load (as from battery electronics) present in the battery pack at all times. The bq34210-Q1 device applies the compensation continuously when the charge or discharge is below the digital filter. The bq34210-Q1 device applies the compensation in addition to self-discharge. The compensation occurs at a rate determined by the value stored in **Electronics Load**. The compensation range is 0 μA–765 μA in steps of approximately 3 μA.

The amount of internal battery electronics load estimate in μA, BEL, is stored as follows:

$$\text{Electronics Load} = BEL/3$$

### 1.1.9 Initial Battery Capacity at Device Reset

The bq34210-Q1 device estimates the initial capacity of a battery pack at device reset, which is the case when battery cells are first attached to the application circuit. The initial *FullChargeCapacity()* (FCC) is a direct copy of the ROM CEDV profile parameter **Full Charge Capacity**. The initial RC and RSOC are estimated using the open-circuit voltage (OCV) characteristics of the programmed Li-Ion (LiFePO4 or NiMH) chemistry, DOD at **EDV2**, and **Design Capacity** (maximum chemical capacity). This gives a reasonably accurate RC and RSOC; however, battery capacity learning is required in order to find the accurate FCC, RC, and RSOC. During battery capacity learning, learned **Full Charge Capacity**, and DOD at **EDV2** will be learned and updated.

The determined value of remaining capacity can be further scaled, if needed, through the value of **RemCap Init Percent**. Upon a reset, the final value of *RemainingCapacity()* is initialized from the **RemCap Init Percent** value of the initial value correlated to the battery voltage table.

### 1.1.10 Fuel Gauge Operating Modes

Entry and exit of each mode is controlled by data memory parameters in the **Current Thresholds** subclass. The *[DSG]* flag referenced below is from the MAC *GaugingStatus()* subcommand and is set in RELAXATION and DISCHARGE modes. The *[DSG]* flag in *BatteryStatus()* is slightly different—it sets only in DISCHARGE mode and not in RELAXATION mode.

CHARGE mode is exited and RELAXATION mode is entered when *Current()* goes below **Quit Current** for a period of **Charge Relax Time**. DISCHARGE mode is entered when *Current()* goes below **(-)Dsg Current Threshold**. DISCHARGE mode is exited and RELAXATION mode is entered when *Current()* goes above **(-)Quit Current** threshold for a period of **Discharge Relax Time**. CHARGE mode is entered when *Current()* goes above **Chg Current Threshold**.

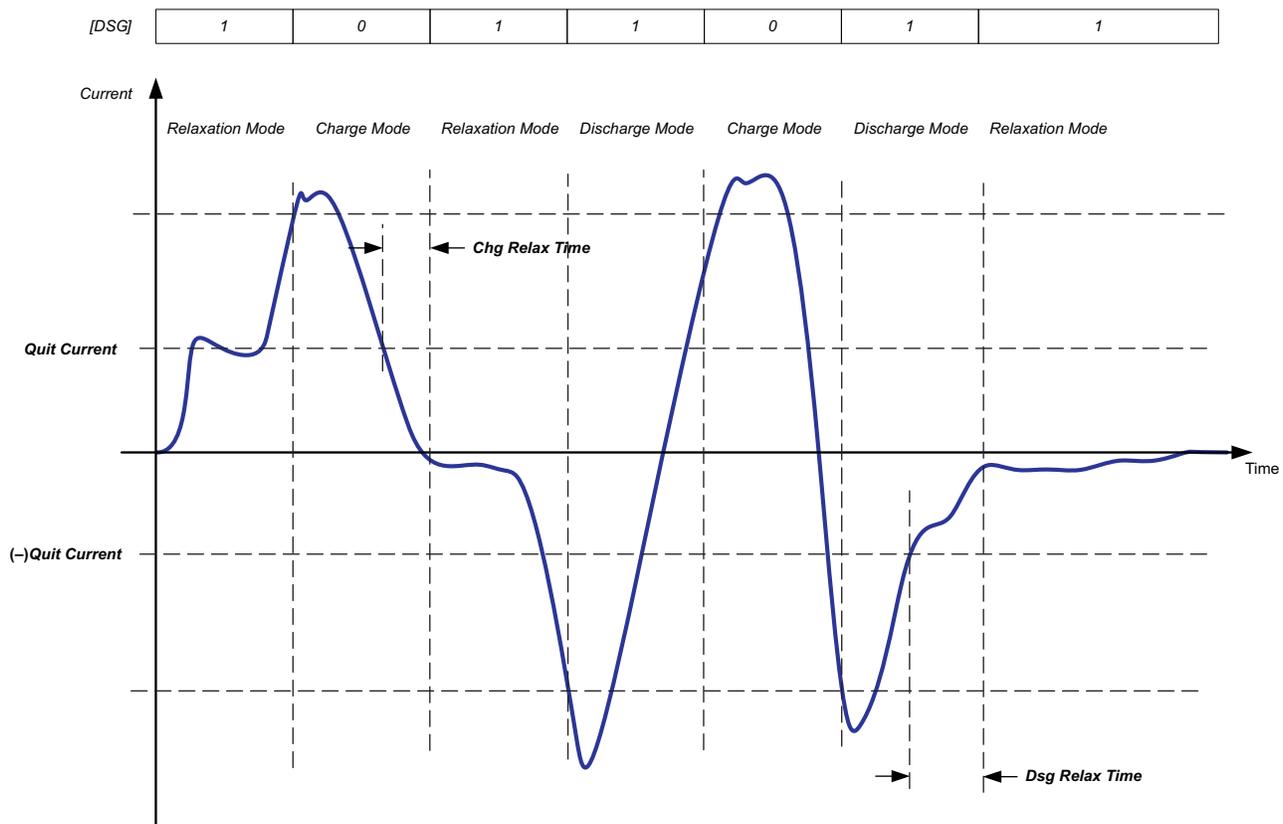


Figure 1-3. Fuel Gauge Operating Mode Example

### 1.1.11 CEDV Smoothing

The bq34210-Q1 device has the ability to smooth the *RemainingCapacity()* during discharge in order to avoid a drop in *RelativeStateOfCharge()* when the EDV thresholds are reached. This feature is enabled by setting the **Smoothing Config [SMEN]** = 1 and configuring the **Smoothing Start Voltage** and **Smoothing Delta Voltage**.

The smoothing will activate only when all of the following conditions are true:

- *Current()* < 0
- *Voltage()* < **Smoothing Start Voltage**
- EDV2 has been reached (*[EDV2]* = 1) OR (*Voltage()* – present EDV2 threshold) < **Smoothing Delta Voltage**.
- Maximum *Voltage()* during the previous one minute is less than the maximum *Voltage()* during the current minute (that is, "drop rate" is greater than 0).
- *RemainingCapacity()* is greater than the capacity at the next EDV point.

While smoothing is active, the "drop rate" is used to estimate the time to the EDV point under the assumption that the rate is constant (linear). This information is then used to estimate how much current would need to be applied in order to have *RemainingCapacity()* reach the expected capacity at the EDV point. The actual *Current()* is then scaled by the "smoothing current." This will either speed up or slow down the *RemainingCapacity()* accumulation to reach the EDV threshold at the correct time.

Whenever the *RemainingCapacity()* accumulation is actively scaled, the *OperationStatus()[SMTH]* bit will be set.

Smoothing deactivates whenever an EDV threshold is reached until the rate to the next EDV threshold can be calculated; however, smoothing past the EDV2 point only occurs if **Smoothing Config [SMEXT]** is set to 1.

To improve smoothing at the end of discharge, the SME0 configuration bit provides additional flexibility. This is particularly useful when **FIXED\_EDV0** is set and the calculated EDV2/EDV1 is lower than EDV0. In this scenario, the State-of-Charge (SOC) smooths to EDV2, then to EDV1, and then to EDV0, leading to SOC jumps. If the SME0 bit is set, then the SOC smooths directly to EDV0, leading to a smooth transition to empty.

Table 1-2 shows the available smoothing configurations.

**Table 1-2. Smoothing Configurations**

Smoothing Config [SMEN]	Smoothing Config [SMEXT]	CEDV Config [SME0]	Description
0	0	0	No Smoothing
0	0	1	No Smoothing
0	1	0	No Smoothing
0	1	1	No Smoothing
1	0	0	Smoothing to EDV2
1	0	1	Smoothing to EDV0 if calculated EDV2/EDV1 is less than EDV0.
1	1	0	Smoothing to EDV2 ≥ EDV1 ≥ EDV0
1	1	1	Smoothing to EDV0 if calculated EDV2/EDV1 is less than EDV0.

The bq34210-Q1 device can also add smoothing during charging. In situations when the FCC is not updated during a discharge cycle or on a subsequent charge cycle, if the valid charge termination is reached, RSOC is synced to 100% regardless of the true RSOC. To help in scenarios like these, the device enables the **SMOOTHEOC\_EN** bit (default is enabled). When enabled, the RSOC value is gradually increased to 100% instead of a sudden jump if the following are true:

- a. Battery is charging.
- b. Cell Voltage > Taper Voltage
- c. **Charge Current** is decreasing AND is below the **EOC Smooth Current** threshold for **EOC Smooth Current Time**.

## 1.2 Accumulated Charge Measurement

The bq34210-Q1 device integrates an **Accumulated Charge** function that measures the integrated charge passed in or out of the cell since the integration is reset. This function can be used to generate an alert to the host when a programmable threshold of **Accumulated Charge** is achieved.

The device also integrates the elapsed time since the integration began, assuming the timer was not interrupted by a power cycle or put into SHUTDOWN mode. This time is read using the command *AccumulatedTime()*. If an event has occurred that interrupted the timer, the value of *AccumulatedTime()* will be fixed unchanging at 0 until the integration is reset.

The charge and time integration is reset at full charge termination or upon issue of the *ACCUM\_RESET* command. While the battery is discharging (that is, the measured *Current()* is negative), then the charge integration counter increases. If the battery starts charging (that is, the measured *Current()* is positive), then the charge integration counter decreases. The integrated charge value in mAh can be read by the host using the command *AccumulatedCharge()*. The elapsed time (which does not decrease in value) is read by issuing the *AccumulatedTime()* command.

The **Accumulated Charge** calculation uses the current measured across the sense resistor and, similar to the coulomb counter integration, ignores currents below a programmed level controlled by **CC Deadband**. In periods when the bq34210-Q1 device is in SLEEP mode, the **Accumulated Charge** integration includes an estimate of the charge integrated based on analysis of the periodic measured current.

If the user prefers to include cell self-discharge in the integration, this capability can be enabled or disabled using the *[IGNORE\_SD\_EN]* configuration bit.

The charge integration can also be limited to only include positive (charging) currents, only negative (discharging) currents, or both, through setting the *[ACCHG\_EN]* and *[ACDSG\_EN]* configuration bits. If both *[ACCHG\_EN]* and *[ACDSG\_EN]* are reset, then the timer is halted. These bits can be set using the *ACCUM\_CHG\_EN()* and *ACCUM\_DSG\_EN()* commands.

When the cell is fully charged and the *FC* bit is set due to normal charge termination, then the integration counter is again reset. At this point, the values of **Accumulated Charge** and time just before reset are stored and can be read using *LastAccumulatedCharge()* and *LastAccumulatedTime()*. The values stored in *LastAccumulatedCharge()* and *LastAccumulatedTime()* are cleared each time the command is issued and the respective value is read. They are also overwritten whenever the integration counter is reset again. The user can set thresholds to alert the host when *AccumulatedCharge()* reaches a particular level in both the charge (positive) and discharge (negative) directions. These thresholds are set by **Accum Charge Positive Threshold** and **Accum Charge Negative Threshold**.

---

**NOTE:** *AccumulatedCharge()* does not reset when a threshold is reached: The reset should be initiated by the host using *ACCUM\_RESET*. When a threshold is passed, a flag is set in *OperationStatus()[ACTHR]*.

It is possible for the integration counter to be reset at normal charge termination, but the charger continues charging the battery for additional time until the charger ceases charging. In this case, the integration counter would reset, then proceed to integrate this additional charge. The user should be aware of this possibility and if it is a concern to plan for a workaround, such as programming the integration to only accumulate discharging currents or to detect when the charger stops charging, then issue an *ACCUM\_RESET* command to clear any residual charging integration.

---

Due to the charge integration and timer information being stored in RAM, any the device's power cycles or putting the device into SHUTDOWN will result in the loss of *AccumulatedCharge()*, *AccumulatedTime()*, *LastAccumulatedCharge()*, and *LastAccumulatedTime()* data.

Command	R/W	Type	Min	Max	Default	Units
<i>AccumulatedCharge()</i>	R	Signed integer, 2 bytes	-32767	32767	0	mAh
<i>LastAccumulatedCharge()</i>	R	Signed integer, 2 bytes	-32767	32767	0	mAh
<i>AccumulatedTime()</i>	R	Unsigned integer, 2 bytes	0	65535	0	5 min
<i>LastAccumulatedTime()</i>	R	Unsigned integer, 2 bytes	0	65535	0	5 min
ACCUM_RESET	W	Boolean	NA	NA	NA	

### 1.3 End-Of-Service Determination

The bq34210-Q1 device incorporates the End-of-Service (EOS) Determination function to determine the end of useful service of the battery and to provide alerts based on this detection. Learning phases are used to gather information about the present state of the battery through its cell resistance. Learning cycles are coordinated by the bq34210-Q1 device with the host, which enables and disables the learning load. LEN or LLEN is used to denote the Learning Load Enable function. The EOS Determination function is enabled when `[EOS_EN]` in `ManufacturingStatus()` = 1. This bit can be toggled using the `EOS_EN()` subcommand. The `ManufacturingStatus[EOS_EN]` bit should not be written directly during CONFIG UPDATE mode, but instead should be done via the `EOS_EN()` subcommand. If the `[EOS_EN]` bit or other data memory values related to this function are changed directly in data memory, they will not take effect until a device reset is issued.

For best results, it is recommended that JEITA-based charging is not enabled when the EOS Determination feature is used.

There are two ways to initiate a learning phase:

- a. To have it automatically controlled by the device (recommended) based on when the internal **Auto Learn Time** timer has expired since the last successful learning phase OR
- b. To have it triggered by the host by writing a `ManufacturerAccessControl() EOS_START_LEARN()` subcommand to the device.

Automatic learning is disabled if **Auto Learn Time** = 0. There is also a special test mode, which is entered using the `[LTEST]` bit and sets several timers to short time durations.

The learning phase can be implemented in two ways, which are controlled by the `[LSM]` bit:

- a. **CHARGE-BEFORE-DISCHARGE:** The system begins a Learn Charge Phase where it enables charging to a voltage given by the charging voltage determined by the selected algorithm (JEITA, for example) incremented by **Learn Charge Voltage Delta**. This increases charging from the level used when not in a learning phase.

---

**NOTE:** The data memory value of **Last Charge Voltage Tx - Ty** is not increased due to this Learn Charge Phase.

---

After this charging is completed through normal charge termination, the device waits for the cell to relax. It then initiates a Learn Discharge Phase, whereby an intended **Learn Discharge Current** is enabled for a length of time given by **Learn Discharge Time**. When this time has expired, the device disables the **Learn Discharge Current**. The bq34210-Q1 device analyzes the response of the battery to this discharge current to estimate the status of the battery regarding its end of usable service.

If needed, the host continues discharging the battery until `Voltage()` reaches the appropriate voltage, as determined by the charging algorithm selected, OR

- b. **DISCHARGE-BEFORE-CHARGE:** The device begins by ensuring it is in a RELAXED state (typically fully or near-fully charged).

The device begins a Learn Discharge Phase by enabling **Learn Discharge Current** for a length of time given by **Learn Discharge Time**. When this time has expired, the device disables the **Learn Discharge Current**.

The device can now be recharged to the appropriate voltage, as determined by the charging algorithm selected, if needed.

---

**NOTE:** The learning discharge current value is set by external components and is not directly controlled by the bq34210-Q1 device. However, this current is monitored throughout the Learn Discharge Phase and evaluated to ensure it is close to the intended value.

---

The **CHARGE-BEFORE-DISCHARGE** approach described above in (a) is appealing in that the battery voltage is not discharged below the appropriate charging voltage level by the learning phase. However, it requires the use of a charger with programmable charging voltage, which may be a limitation in some systems. For those cases, the **DISCHARGE-BEFORE-CHARGE** approach in (b) is provided, whereby a charger with a fixed output voltage can be used with the tradeoff that the battery voltage will be discharged below this level during the Learn Discharge Phase. However, the amount of this reduction in battery voltage, and thus capacity, can be controlled and limited to acceptable levels through appropriate device settings.

The response of the battery to the learning discharge current is analyzed and used to estimate the cell resistance, **Rcell**, and this resistance estimate is used in two different methods to evaluate the cell EOS status:

- a. **Direct Resistance Decisioning (DRD)**: This method uses the newly measured value of **Rcell** and computes the ratio of **Rcell** with that of an **Initial Rcell** captured when the battery was first put into service. The ratios are compared to thresholds to generate an alert and a warning.
  - Alert if  $(R_{cell}/Initial\ R_{cell}) > DRD\ Alert\ Level$
  - Warning if  $(R_{cell}/Initial\ R_{cell}) > DRD\ Warning\ Level$
- b. **Resistance Slope Decisioning**: This method uses the changes with respect to time of **Rcell**, comparing this to programmable thresholds to generate an alert and a warning.

Use of Resistance Slope Decisioning (RSD) requires an accurate measurement of the time between consecutive learning phases for calculation of the slope of **Rcell** change with respect to time. This will not be possible if the device is powered off between learning phases; in which case, Direct Resistance Decisioning (DRD) can still be used. If the device is programmed to use Resistance Slope Decisioning and a power cycle is detected (or anything that could impact the validity of the time measurement between learning phases), then the device defaults to only using Direct Resistance Decisioning until the device is continuously powered long enough to complete multiple learning phases and accurately evaluate the **Rcell** change over time.

### 1.3.1 Alert Config Registers

The Alert registers are detailed in this section.

**Table 1-3. Alert Config Registers**

Alert_x Config Register	Matching Register
Alert_0 Config	Battery Status Low Byte
Alert_1 Config	Battery Status High Byte
Alert_2 Config	EOS Learn Status Low Byte
Alert_3 Config	EOS Learn Status High Byte
Alert_4 Config	EOS Status
Alert_5 Config	EOS Safety Status Active Bits
Alert_6 Config	Operation Status 2 bits

#### 1.3.1.1 Alert\_0 Config

This register matches the Battery Status register low byte.

**Table 1-4. Alert\_0 Config Register Bit Definitions**

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
	SLEEP	CHGINH	FD	FCSETV	TCA	TDA	CHG	DSG
<b>Default</b>	0	0	0	0	0	0	0	0
	<b>0x00</b>							

SLEEP = Enables *BatteryStatus()*[SLEEP]  
 0 = Disabled (default)  
 1 = Enabled

CHGINH = Enables *BatteryStatus()*[CHGINH]  
 0 = Disabled (default)  
 1 = Enabled

FD = Enables *BatteryStatus()*[FD]  
 0 = Disabled (default)  
 1 = Enabled

FCSETV = Enables *BatteryStatus()*[FCSETV]  
 0 = Disabled (default)  
 1 = Enabled

TCA = Enables *BatteryStatus()*[TDA]  
 0 = Disabled (default)  
 1 = Enabled

TDA = Enables *BatteryStatus()*[TDA]  
 0 = Disabled (default)  
 1 = Enabled

CHG = Enables *BatteryStatus()*[CHG]  
 0 = Disabled (default)  
 1 = Enabled

DSG = Enables *BatteryStatus()*[DSG]  
 0 = Disabled (default)  
 1 = Enabled

### 1.3.1.2 Alert\_1 Config

This register matches the Battery Status register high byte.

**Table 1-5. Alert\_1 Config Register Bit Definitions**

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
	RSVD	SOCLOW	UTC	UTD	OTC	OTD	BATHIGH	BATLOW
<b>Default</b>	0	0	0	0	0	0	0	0
	<b>0x00</b>							

RSVD = Reserved

SOCLOW = Enables *BatteryStatus()*[SOCLOW]  
 0 = Disabled (default)  
 1 = Enabled

UTC = Enables *BatteryStatus()*[UTC]  
 0 = Disabled (default)  
 1 = Enabled

UTD = Enables *BatteryStatus()*[UTD]  
 0 = Disabled (default)  
 1 = Enabled

OTC = Enables *BatteryStatus()*[OTC]  
 0 = Disabled (default)  
 1 = Enabled

OTD = Enables *BatteryStatus()*[OTD]  
 0 = Disabled (default)  
 1 = Enabled

BATHIGH = Enables *BatteryStatus()*[BATHIGH]  
0 = Disabled (default)  
1 = Enabled

BATLOW = Enables *BatteryStatus()*[BATLOW]  
0 = Disabled (default)  
1 = Enabled

### 1.3.1.3 Alert\_2 Config

This register matches the EOS Learn Status register low byte.

**Table 1-6. Alert\_2 Config Register Bit Definitions**

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
	LCT0	LFAULT	LABRT	LCMD	LPER	LRLX	LCHG	LDSG
<b>Default</b>	0	0	0	0	0	0	0	0
	<b>0x00</b>							

LCT0 = Enables *EOSLearnStatus()*[LCT0]  
0 = Disabled (default)  
1 = Enabled

LFAULT = Enables *EOSLearnStatus()*[LFAULT]  
0 = Disabled (default)  
1 = Enabled

LABRT = Enables *EOSLearnStatus()*[LABRT]  
0 = Disabled (default)  
1 = Enabled

LCMD = Enables *EOSLearnStatus()*[LCMD]  
0 = Disabled (default)  
1 = Enabled

LPER = Enables *EOSLearnStatus()*[LPER]  
0 = Disabled (default)  
1 = Enabled

LRLX = Enables *EOSLearnStatus()*[LRLX]  
0 = Disabled (default)  
1 = Enabled

LCHG = Enables *EOSLearnStatus()*[LDSG]  
0 = Disabled (default)  
1 = Enabled

LDSG = Enables *EOSLearnStatus()*[LDSG]  
0 = Disabled (default)  
1 = Enabled

### 1.3.1.4 Alert\_3 Config

This register matches the EOS Learn Status register high byte.

**Table 1-7. Alert\_3 Config Register Bit Definitions**

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
	LDONE	LRES	LRSTOR	LCTLEDGE	LUCD	LDPAM	LDPAT	LDPAI
<b>Default</b>	0	0	0	0	0	0	0	0
	<b>0x00</b>							

LDONE = Enables *EOSLearnStatus()*[LDONE]  
0 = Disabled (default)  
1 = Enabled

LRES = Enables *EOSLearnStatus()*[LRES]  
0 = Disabled (default)  
1 = Enabled

LRSTOR = Enables *EOSLearnStatus()*[LRSTOR]  
0 = Disabled (default)  
1 = Enabled

LCTLEDGE = Enables *EOSLearnStatus()*[LCTLEDGE]  
0 = Disabled (default)  
1 = Enabled

LUCD = Enables *EOSLearnStatus()*[LUCD]  
0 = Disabled (default)  
1 = Enabled

LDPAM = Enables *EOSLearnStatus()*[LDPAM]  
0 = Disabled (default)  
1 = Enabled

LDPAT = Enables *EOSLearnStatus()*[LDPAT]  
0 = Disabled (default)  
1 = Enabled

LDPAI = Enables *EOSLearnStatus()*[LDPAI]  
0 = Disabled (default)  
1 = Enabled

### 1.3.1.5 Alert\_4 Config

This register matches the EOS Status register.

**Table 1-8. Alert\_4 Config Register Bit Definitions**

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
	SRRL	SRCL	RSVD	LTI	RSDLI	RCELLR	IRRCOMP	IRCOMP
<b>Default</b>	0	0	0	0	0	0	0	0
	<b>0x00</b>							

SRRL = Enables *EOSStatus()*[SRRL]  
0 = Disabled (default)  
1 = Enabled

SRCL = Enables *EOSStatus()*[SRCL]  
0 = Disabled (default)  
1 = Enabled

RSVD = Reserved

LTI = Enables *EOSStatus()*[LTI]  
0 = Disabled (default)

1 = Enabled

RSDLI = Enables *EOSStatus()*[RSDLI]  
0 = Disabled (default)  
1 = Enabled

RCELLR = Enables *EOSStatus()*[RCELLR]  
0 = Disabled (default)  
1 = Enabled

IRRCOMP = Enables *EOSStatus()*[IRRCOMP]  
0 = Disabled (default)  
1 = Enabled

IRCOMP = Enables *EOSStatus()*[IRCOMP]  
0 = Disabled (default)  
1 = Enabled

### 1.3.1.6 Alert\_5 Config

This register matches the EOS Safety Status register active bits. Bits 7:4 in the Alert\_5 Config register match the EOS Safety Status register's high byte, Bits 3:0. Bits 3:0 in the Alert\_5 Config register match the EOS Safety Status register's low byte, Bits 3:0.

**Table 1-9. Alert\_5 Config Register Bit Definitions**

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
	RSVD	RSDLWARN	RSDWARN	DRDWARN	RSVD	RSDL ALERT	RSDALERT	DRDALERT
<b>Default</b>	0	0	0	0	0	0	0	0
	<b>0x00</b>							

RSVD = Reserved

RSDLWARN = Enables *EOSSafetyStatus()*[RSDLWARN]  
0 = Disabled (default)  
1 = Enabled

RSDWARN = Enables *EOSSafetyStatus()*[RSDWARN]  
0 = Disabled (default)  
1 = Enabled

DRDWARN = Enables *EOSSafetyStatus()*[DRDWARN]  
0 = Disabled (default)  
1 = Enabled

RSVD = Reserved

RSDLALERT = Enables *EOSSafetyStatus()*[RSDLALERT]  
0 = Disabled (default)  
1 = Enabled

RSDALERT = Enables *EOSSafetyStatus()*[RSDALERT]  
0 = Disabled (default)  
1 = Enabled

DRDALERT = Enables *EOSLearnStatus()*[DRDALERT]  
0 = Disabled (default)  
1 = Enabled

### 1.3.1.7 Alert\_6 Config

This register matches two bits from the Operation Status low byte.

**Table 1-10. Alert\_6 Config Register Bit Definitions**

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
	RSVD	RSVD	RSVD	RSVD	RSVD	RSVD	ACTHR	BLT
<b>Default</b>	0	0	0	0	0	0	0	0
	<b>0x00</b>							

RSVD = Reserved

ACTHR = Enables *OperationStatus()*[ACTHR]

0 = Disabled (default)

1 = Enabled

BLT = Enables *OperationStatus()*[BLT]

0 = Disabled (default)

1 = Enabled

### 1.3.2 Smoothing Config Register

**Table 1-11. Smoothing Config Register Bit Definition**

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
	RSVD	RSVD	RSVD	RSVD	SMOOTH EOC_EN	SMEXT	VAVG	SMEN
<b>Default</b>	0	0	0	0	0	0	0	0
	<b>0x00</b>							

RSVD = Reserved

SMOOTHEOC\_EN = Allows smoothing of RemCap once Current starts decreasing during the end of charge (EOC).

0 = End of charge smoothing is not enabled.

1 = End of charge smoothing is enabled (default).

SMEXT = When set to 1, smoothing continues to EDV1 and EDV0 points. When set to 0, smoothing stops at EDV2. Default is 0.

VAVG = Enables smoothing to use average voltage

When set to 1, smoothing uses average voltage. When set to 0 smoothing uses measured voltage. Default is 0.

SMEN = Smoothing result is reported on *RemainingCapacity()*.

When set to 1, the smoothing result is reported on *RemainingCapacity()*. When set to 0, the normal CEDV remaining capacity is reported. Default is 0.

### 1.3.3 End-Of-Service Determination—Detailed Description

The **EOS Configuration** data memory is used to configure certain settings associated with the EOS Determination function.

**Table 1-12. EOS Configuration**

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
	RSVD	RSVD	RSVD	RSVD	LTEST	LVR	LSM	RSVD

Legend: RSVD = Reserved. Do not use.

LTEST = Learn Test Mode Control

This bit is used to put the device into a test mode for reduced timing testing of the EOS Determination function.

When this bit is set = 1, the following values are set:

**Auto Learn Time** = 10 min

**Auto Learn Retry Time** = 5 min

**Alert-Warn Learn Time** = 10 min

**Minimum Learn Time** = 10 min

0 = The device uses the values programmed in data memory for the above parameters (default).

LVR = Learn Voltage Restore Control

This bit determines whether the device continues discharging during Learn Discharge Phase until *Voltage()* reaches the appropriate **Last Charge Voltage Tx - Ty** (when set = 1), or to simply stop discharge when the timer reaches **Learn Discharge Time** (when set = 0).

1 = The device continues Learn Discharge Phase until *Voltage()* reaches the appropriate **Last Charge Voltage Tx - Ty**.

0 = The device stops Learn Discharge Phase when the timer reaches **Learn Discharge Time** (default).

LSM = Learn Sequence Mode Control

This bit determines whether the EOS algorithm uses CHARGE-BEFORE-DISCHARGE or DISCHARGE-BEFORE-CHARGE mode.

1 = DISCHARGE-BEFORE-CHARGE mode is used.

0 = CHARGE-BEFORE-DISCHARGE mode is used (default).

The device includes a variety of flags to provide visibility into the operation of the EOS Determination Learning process. These are found in [EOSLearnStatus\(\): 0x64 and 0x65](#).

The sequence of steps involved in a learning phase differs depending on the setting of [LSM]. These are depicted in the following figures.

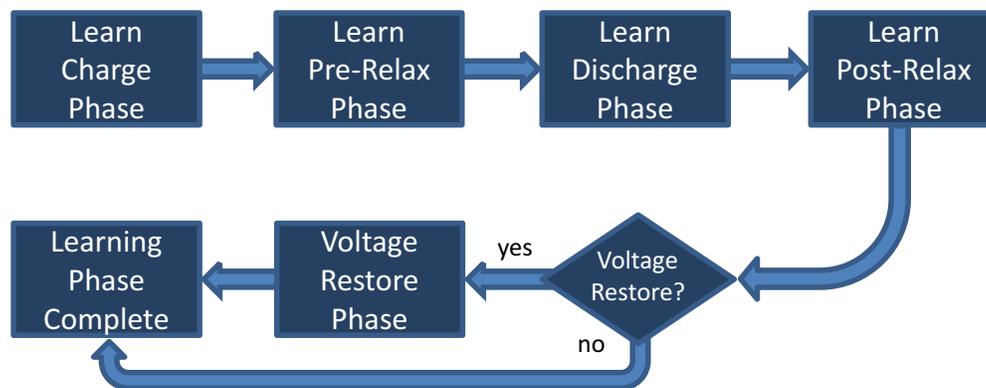


Figure 1-4. State Diagram for LSM = 0

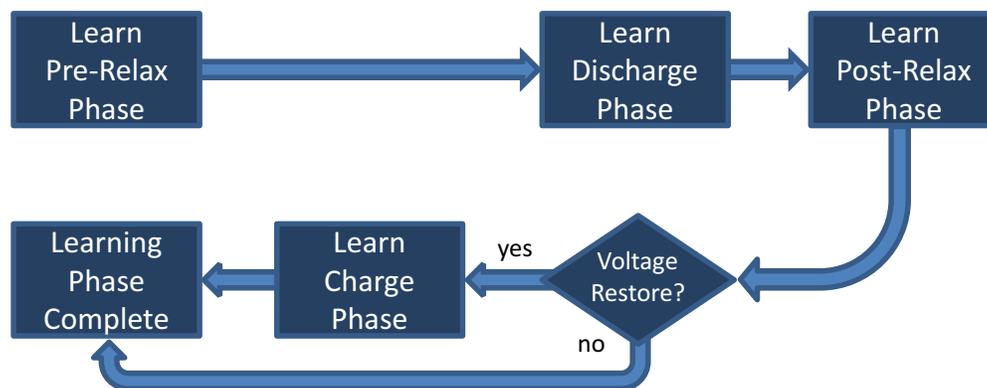


Figure 1-5. State Diagram for LSM = 1

### 1.3.3.1 Periodic and Manual Learn Command

For manual control of learning phases, the *ManufacturerAccessControl()* subcommand *EOS\_START\_LEARN()* is used. When the device receives this command, it sets the *[LCMD]* flag and initiates the learning phase if conditions permit: for example, charger present, no charging or safety faults, and the temperature is within acceptable limits. The *[LDPAT]* and *[LFAULT]* flags will be set if the Learning Discharge Phase is attempted but temperature conditions do not permit it.

If the device is in periodic (automatic) learning mode, then the *[LPER]* bit will be set while the device is in a learning phase.

*EOS\_ABORT\_LEARN()*: This *ManufacturerAccessControl()* subcommand is used to abort a learning phase that is in progress. Use of this command during a learning phase results in a failed learning phase and setting the *[LABRT]* flag, whereupon the device will retry another learning phase after a time period of **Auto Learn Retry Time**.

When the device attempts to initiate a learning phase, but conditions do not permit this, then the device will wait for **Auto Learn Retry Time** to again attempt a learning phase. Note that this will occur whether the device is configured in periodic learning or learning is initiated through a host command.

If the case occurs where an alert or warning is detected, either through Direct Resistance Decisioning or Resistance Slope Decisioning, the **Alert-Warn Learn Time** is used to schedule a new learning phase. If multiple fault events must be detected before the alert or warning flags are set, and an stopped learning phase occurs after the first alert or warning is detected, then **Alert-Warn Learn Time** is used to schedule future **Rcell** measurements rather than **Auto Learn Retry Time**.

---

**NOTE:** If *[LTEST]* is set, special values override the selected timer values to facilitate device operation testing in a shorter time scale.

---

To avoid interruption to the EOS Determination measurements and calculations, automatic offset calibration is not initiated during a learning phase. While it is possible for the host to manually initiate a calibration event during a learning phase, it is recommended that the host avoid this.

---

**NOTE:** **Alert-Warn Learn Time** has priority over **Auto Learn Retry Time**, so if multiple occurrences must be detected before an alert or warning is triggered, and after the first occurrence is detected that a fault occurred that invalidated a following attempted learning phase, the **Alert-Warn Learn Time** will be used to determine the time to the next learning phase attempt. It should also be noted that if **Alert-Warn Learn Time** is set to be lower than **Minimum Learn Time**, then **Minimum Learn Time** will be used to determine the time to the next learning phase attempt.

---

### 1.3.3.2 Learn Charge Phase

The operation of the device is first described for the case of  $[LSM] = 0$ , in which the device uses CHARGE-BEFORE-DISCHARGE mode. In this mode, the device first enters Learn Charge Phase by setting *ChargingVoltage()* to the appropriate charging voltage determined by the selected charging algorithm (JEITA, for example) incremented by **Learn Charge Voltage Delta**. The  $[LCHG]$  flag is set and charge terminates using standard charge termination criteria. Upon termination of charge, then  $[LCHG]$  is cleared. Note that the data memory value of **Last Charge Voltage Tx - Ty** is not incremented due to this Learn Charge Phase.

The time while  $[LCHG]$  is set is measured and compared against a threshold given by **Learn Charge Time Limit** to identify an excessive charging time, which may indicate an issue in the system. When the learn charging time exceeds this limit, the  $[LCTO]$  flag is set, learning is terminated, and the  $[LFAULT]$  flag is set to indicate a fault has occurred. The  $[LCHG]$  flag is reset whenever the device exits from CHARGING mode. If a learning fault occurs, the status flag ( $[LCHG]$  in this case) remains set to enable the host to understand what mode the system was in when the fault occurred.

---

**NOTE:** The standard charge termination criteria voltage condition is relative to *ChargingVoltage()*, so the same settings are used for *Normal* and *Learn* charging phases.

---

### 1.3.3.3 Learn Pre-Relax Phase

If  $[LSM] = 0$ , then the device next waits for relaxation of the cell, during which *Voltage()* is monitored for 100-s time windows. While in this phase, the device sets the  $[LRLX]$  flag. If the change in the consecutive 100-s averages of *Voltage()* is less than 4  $\mu\text{V}$ , then relaxation is deemed achieved. If not, the device continues monitoring for another 100-s time window. It is important that the cell be fully relaxed before the algorithm can continue onto the Learn Discharge Phase. The status of relaxation can be seen by the  $[REST]$  bit in the *Gauging Status* register, after which the algorithm can move onto the Learn Discharge Phase. If a learning fault occurs while in the Learn Pre-Relax Phase or the Learn Post-Relax Phase, the status flag ( $[LRLX]$  in this case) will remain set to enable the host to understand what mode the system was in when the fault occurred.

When the device is in learning mode (but not in the Learn Discharge Phase), and a current is detected differently than what is expected, the  $[LUCD]$  bit will be set. It is set if the device is attempting to charge or relax, and a discharge current in excess of **Discharge Detection Threshold** is detected. It is also set if the device is in a RELAXATION mode and a charging current in excess of **Charge Detection Threshold** is detected. This detection also terminates the learning phase, and this flag will remain set so the host can recognize why the learning phase was stopped. This bit will be reset to 0 when charging is terminated or the register is read.

### 1.3.3.4 Learn Discharge Phase

After achieving relaxation, the bq34210-Q1 device next enters the Learn Discharge Phase, whereby the device enables the **Learn Discharge Current** (depending on the  $[LENCTL]$  setting), sets the  $[LDSG]$  flag, and begins the timer.

External circuitry is required to actively discharge the battery at a constant current rate where the discharge current flows through the sense resistor connected across SRP – SRN. This will be implemented by the host directly controlling the current. To provide sufficient resolution in the associated calculations, it is important that the level of this **Learn Discharge Current** be large enough so that it generates a cell voltage change of approximately 5 mV or greater. A current level of C/20 or higher is generally recommended.

$[LDSG]$  remains enabled until the timer reaches **Learn Discharge Time**, at which point (if  $[LVR] = 0$ ) the  $[LDSG]$  flag is reset and **Learn Discharge Current** is disabled. The device then transitions into the Learn Post-Relax Phase.

The  $[LVR]$  (Learn Voltage Restore) bit is used to tell the device to resume discharging using the learning load after completion of the voltage determined by the charging algorithm selected until *Voltage()* reaches the appropriate voltage determined by the charging algorithm selected (when  $[LVR]$  is set = 1). When this is finished (or when the Learn Post-Relax Phase is complete, if  $[LVR]$  is set = 0), the entire learning phase is complete, at which point the device sets the  $[LDONE]$  flag.

During the time period while the timer is active for the **Learn Discharge Time** period, the average current and average temperature over this time period will be calculated by the device and saved at the conclusion of the Learn Discharge Phase. These values are used in later calculations to provide better accuracy.

While the device is in Learn Discharge Phase, it is also monitoring *Current()* and ensuring it is within an acceptable range around the intended discharge current. The algorithm knows the intended current based on the **Learn Discharge Current**, which is the intended **Learn Discharge Current** implemented using the external circuitry. This current should generally be designed greater than C/20. The boundary the algorithm uses for the acceptable range is determined using the **Learn Discharge Current Boundary**. If the current exceeds the **Learn Discharge Current Boundary**, the *[LDPAI]* and *[LFAULT]* flags are set, and the learning phase is stopped. If a learning fault does occur, the status flag (*[LDSG]* in this case) will remain set to allow the host to understand what mode the system was in when the fault occurred.

The value of **Learn Discharge Current** should be selected large enough to accept variations in the current with temperature and system noise, but low enough to ensure identification of other events, such as an unintended charging session starting or a system load discharge event beginning. The **Learn Discharge Current** should also be chosen well above the **Discharge Detection Threshold** and **Quit Current** to ensure proper operation.

---

**NOTE:** After setting *[LDSG]*, the device will monitor *Current()* for up to **Learn Request Timeout** seconds and start the timer only when the current has entered the acceptable range around **Learn Discharge Current**. This will accommodate delay in the host responding to the ALERT interrupt to see the *[LCTLEDGE]* signal and enable the **Learn Discharge Current**.

If the bq34210-Q1 device does not detect a valid current within a time period of **Learn Request Timeout** after setting *[LDSG]*, then the device will set *[LFAULT]*, delay a time given by **Auto Learn Retry Time**, and then initiate a new learning phase. The *[LDSG]* flag will remain set so the host can read and determine the phase in which the fault occurred. The **Learn Request Timeout** timer is similarly used after the *[LCTLEDGE]* signal asserts when the host should disable the learning load.

---

The Learn Discharge Phase can be terminated for other criteria (beyond its intended valid termination by persisting for the **Learn Discharge Time** period), including *Current()* exiting the acceptable range, a safety fault is detected, or a temperature exceeds the allowed learning temperature limits. If the Learn Discharge Phase is terminated for any reason other than valid termination, then *[LFAULT]* is set, indicating that the learning phase was not completed. *[LFAULT]* is cleared when the learning process is initiated again.

The Learn Discharge Phase is only allowed when the temperature is within an allowed range, which is given by the **Learn Min Temperature** and **Learn Max Temperature**. If a Learn Discharge Phase is attempted when the temperature is outside this allowed range, the *[LDPAT]* and *[LFAULT]* flags are set.

If the *[LSM]* is set = 1, then DISCHARGE-BEFORE-CHARGE mode is used, in which the operation sequence is described below:

1. Check for relaxation by monitoring *Voltage()* as described above, and delay until relaxation is achieved.
2. Enable *[LDSG]*, enable the **Learn Discharge Current**, and reset the timer to begin Learn Discharge Phase.
3. When the timer reaches **Learn Discharge Time**, then disable *[LDSG]* and **Learn Discharge Current**.

### 1.3.3.5 Learn Post-Relax Phase

After the Learn Discharge Phase completes, the bq34210-Q1 device will disable the learning current and enter the Learn Post-Relax Phase, whereby the device again waits for relaxation of the cell, during which *Voltage()* is monitored for 100-s time windows. While in this phase, the device sets the *[LRLX]* flag. If the change in the consecutive 100-s averages of *Voltage()* is less than 4  $\mu\text{V}$ , then relaxation is deemed achieved. If not, the device continues monitoring for another 100-s time window. It is important that the cell be fully relaxed before the algorithm can continue. The status of relaxation can be seen by the *[REST]* bit in the Gauging Status register. If a learning fault occurs while in the Learn Post-Relax Phase, the status flag (*[LRLX]* in this case) remains set to enable the host to understand what mode the system was in when the fault occurred.

As in the Learn Pre-Relax Phase, if a discharge current in excess of **Discharge Detection Threshold** or a charging current in excess of **Charge Detection Threshold** is detected, then the *[LUCD]* flag is set. This detection also terminates the learning phase, and this flag will remain set so the host can recognize why the learning phase was stopped. This bit will be reset to 0 when charging is terminated or the register is read.

At the completion of the Learn Post-Relax Phase, if in CHARGE-BEFORE-DISCHARGE mode and *Voltage()* > the charging voltage determined by the selected charging algorithm and *[LVR]* = 1, then the device will set *[LDSG]* and enable the **Learn Discharge Current** until *Voltage()*  $\leq$  the calculated charging voltage. At which point, *[LDSG]* is reset and the **Learn Discharge Current** is disabled. The *[LRSTOR]* bit will be set while the device is continuing discharge to reach the calculated charging voltage.

If in DISCHARGE-BEFORE-CHARGE mode and *[LVR]* = 0, then the device will set *[LDONE]* and complete learning. If *[LVR]* = 1, then the device will initiate a new charging session to charge the battery back to the appropriate charging voltage determined by the selected charging algorithm using a similar sequence as described above. In this case, the device sets the *[LCHG]* and *[LRSTOR]* flags to indicate to the host that charging can begin. If charging does not terminate within **Learn Charge Time Limit**, then *[LCTO]* and *[LFAULT]* is set. If a learning fault does occur, the status flag (*[LCHG]* in this case) will remain set to allow the host to understand what mode the system was in when the fault occurred.

---

**NOTE:** It is possible that a Learn Discharge Phase has completed, and a new **Rcell** value was calculated and stored, but during a Voltage Restore phase, a fault could occur. This would cause *[LFAULT]* to be set, and the device would retry a new learning phase after **Auto Learn Retry Time**.

---

### 1.3.3.6 Cell Resistance Calculation

The device uses the values obtained during each learning phase to estimate a value of **Rcell** for the battery. Note the actual value of this **Rcell** estimate is not critical here, rather its change as the battery ages is what is important. The *[LRES]* bit indicates when a new **Rcell** value was acquired and stored by the device.

The change in value of **Rcell** must be normalized relative to differences in temperature when they are captured. Therefore, the bq34210-Q1 device uses resistance temperature parameters in **Rcell High & Low Temperature Coefficients** to calculate an expected value of resistance at the **Learn Target Temperature**.

The **Rcell High & Low Temperature Coefficients** are obtained during a preproduction test whereby the customer initiates **Initial Rcell** calculations at temperatures of 5°C, 25°C, and 40°C. These **Initial Rcell** values are put into a spreadsheet provided by TI, which then calculates the values of **Rcell High Temperature Coefficient** and **Rcell Low Temperature Coefficient**. These values are then loaded into data memory and used by the device to normalize effective **Rcell** measurements back to an equivalent value at the **Learn Target Temperature**.

**NOTE:** The **Rcell** and **Initial Rcell** values read by the device are normalized to **Learn Target Temperature**. During the preproduction testing to capture the **Initial Rcell** values as described above, it is important to keep the **Rcell High & Low Temperature Coefficients** set = 0, so the **Initial Rcell** values captured there are not further normalized.

The **Initial Rcell** values should be written using the MAC Commands.

It is important that the temperature remain stable during the learning phase. If the temperature is detected to vary more than 10°C during certain portions of the learning phase, the learning phase will be stopped, and the [LDPAT] and [LFAULT] flags will be set.

**Learn Target Temperature** should be the typical or nominal temperature for intended cell operation.

### 1.3.3.7 End-Of-Service Evaluation

#### 1.3.3.7.1 Direct Resistance Decisioning

The device uses the change in **Rcell** relative to the value of **Initial Rcell** as one method to estimate EOS. The ratio of **Rcell / Initial Rcell** is compared to two thresholds to generate [DRDALERT] and [DRDWARN] flags by:

$$[DRDALERT] \text{ is set if } \frac{R_{cell}}{Initial\ R_{cell}} > \left(1 + \frac{DRD\ Alert\ Level}{100}\right)$$

$$[DRDWARN] \text{ is set if } \frac{R_{cell}}{Initial\ R_{cell}} > \left(1 + \frac{DRD\ Warning\ Level}{100}\right)$$

The EOS alerts and warnings are read using the command *EOSSafetyStatus()*, which will clear the alert bits in this register. There is also a *ManufacturerAccessControl()* subcommand *EOS\_SAFETY\_STATUS()*, which can be read and does not clear the alert bits.

The following data memory values are set to provide levels at which the bq34210-Q1 device will generate an alert or a warning, based on the DRD algorithm.

In normal situations, the value of **Rcell** is expected to increase over time. If the value of **Rcell** is detected to decrease from the previous measurement, this is unexpected and may indicate an abnormal situation, such as a cell having been replaced. The bq34210-Q1 device will set the [RCELLR] flag if a reduction in the value of **Rcell** of more than 2% is detected.

To offer improved robustness, there is the option to enable a filter to help ensure that the condition was detected for a number of consecutive learning phases through programming **DRD Alert Counts** and **DRD Warning Counts**.

If the DRD Alert calculation is positive for **DRD Alert Counts**, then [DRDALERT] is set. If **DRD Alert Counts** is set = 0, then this test is disabled.

If the DRD Warning calculation is positive for **DRD Warning Counts**, then [DRDWARN] is set. If **DRD Warning Counts** is set = 0, then this test is disabled.

Additionally, once the first instance of the either a DRD Alert or DRD Warning condition is detected, then the time between automatic learns can be adjusted and is based on **Alert-Warn Learn Time**. If **Alert-Warn Learn Time** = 0, then the value in **Auto Learn Time** continues to be used.

After **DRD Alert Counts** number of alert conditions have occurred and a [DRDALERT] was triggered, then the timing to the next learning phase returns to **Auto Learn Time**.

When the [DRDALERT] flag is set, it will be cleared after being read by the host. However, if the [DRDWARN] flag is set, it is NOT cleared after being read by the host, but can only be cleared by the host using the *ManufacturerAccessControl()* subcommand *EOS\_WARN\_CLEAR()*.

#### 1.3.3.7.2 Resistance Slope Decisioning

This second method the device uses to evaluate EOS is based on the slope of the change in **Rcell** versus time. The preferred approach is to use Direct Resistance Decisioning with Resistance Slope Decisioning, whereby an even more robust solution is obtained.

Resistance Slope Decisioning requires an accurate measurement of the time between consecutive learning phases, which it uses to calculate the slope of the **Rcell** change with respect to time. For best results, this mode should be used with automatic learning mode enabled and the device experiences no (or few) power cycles during its lifetime.

Here, the device collects **Rcell** information using periodic learning phases, which may be in either CHARGE-BEFORE-DISCHARGE or DISCHARGE-BEFORE-CHARGE mode. The device measures accurately the time between learning phases, and this is then used to calculate the rate of change in **Rcell** with respect to time, which is termed **RRate**. The value of **RRate** is stored in units of  $\mu\Omega/\text{day}$  as a two-byte signed value, which can store values up to a maximum of 32767  $\mu\Omega/\text{day}$ . If a value of **RRate** is calculated exceeding this level, the value stored will be limited at 32767. If this value is read back by the host, it should serve as an indication that the **RRate** value has saturated the range allotted for storing it.

During operation, the algorithm uses the newly measured value of **RRate** and computes the ratio of **RRate** with that of an **Initial RRate** captured when the battery was first put into service. The ratios are compared to thresholds to generate an alert and a warning:

$$[RSDAlert] \text{ is set if } \frac{RRate}{Initial\ RRate} > 1 + \left( \frac{RRate\ Alert\ Level}{100} \right)$$

$$[RSDWarn] \text{ is set if } \frac{RRate}{Initial\ RRate} > 1 + \left( \frac{RRate\ Warning\ Level}{100} \right)$$

The device also maintains a long-term timer value, which counts the time from the completion of the **Initial RRate** learning phases to the present time. This value will only be valid if no power cycles or interruptions to device operation have been encountered since the **Initial RRate** learning phases were completed. If there is a power cycle such that the timer was interrupted, then the **[RDSL]** flag will be set, which indicates that no alerts or warnings based on the long-term RSD value (described below) will be triggered.

A long-term value for the resistance slope (given by **RRate<sub>longterm</sub>**) is calculated as the change in **RRate** from the **Initial RRate** value to the most recent **RRate** measurement.

The ratio of **RRate** to **RRate<sub>longterm</sub>** is compared against thresholds to provide further information as:

$$[RSDLAlert] \text{ is set if } \frac{RRate}{RRate_{longterm}} > \left( 1 + \frac{RSDL\ Alert\ Level}{100} \right)$$

$$[RSDLWarn] \text{ is set if } \frac{RRate}{RRate_{longterm}} > \left( 1 + \frac{RSDL\ Warning\ Level}{100} \right)$$

---

**NOTE:** It is important that the delay between successive **Rcell** calculations be long enough such that the slope of resistance change can be accurately calculated. If the triggering of learning phases is being performed manually (rather than automatically using the **Auto Learn Time**), then it is possible for the host to request successive learning phases with too short of a time delay between them. The minimum time required for successive learning phases is set by **Minimum Learn Time**. If the host manually requests a new learning phase without waiting for **Minimum Learn Time**, then the **[LDPAM]** flag will be set and the request for a new learning phase will be declined. The **[LFAULT]** flag is not set here because the learning phase was never started.

The **Initial RRate** values should be written using the MAC Commands.

---

It is important that **Auto Learn Time** be set larger than **Minimum Learn Time**; otherwise, **Minimum Learn Time** will be used in place of **Auto Learn Time**. It is also recommended that, if Resistance Slope Decisioning is used, the value of **RRate** be  $\sim 10$  in practice, to enable appropriate resolution during mathematical computation within the device.

---

**NOTE:** **Minimum Learn Time** also limits the time between successive **Rcell** measurements even when DRD Decisioning is used and RSD/RSDL Decisioning is not used. In the case where RSD/RSDL Decisioning is not being used, the user can set the **Minimum Learn Time** to 0 if frequent **Rcell** measurements are needed.

---

To offer improved robustness, there is the option to enable a filter to help ensure that the condition was detected for a number of consecutive learning phases through programming **RSD Alert Counts** and **RSD Warning Counts**.

If the RSD Alert calculation is positive for **RSD Alert Counts**, then `[RSDALERT]` is set. Similarly, if the RSDL Alert calculation is positive for **RSD Alert Counts**, then `[RSDLALERT]` is set. If **RSD Alert Counts** is set = 0, then these tests will not be enabled.

If the RSD Warning calculation is positive for **RSD Warning Counts**, then `[RSDWARN]` is set. Similarly, if the RSDL Warning calculation is positive for **RSD Warning Counts**, then `[RSDLWARN]` is set. If **RSD Warning Counts** is set = 0, then these tests will not be enabled.

Additionally, once the first instance of either an RSD Alert, RSDL Alert, RSD Warning, or RSDL Warning condition is detected, then the time between automatic learns can be adjusted and is based on **Alert-Warn Learn Time**. If **Alert-Warn Learn Time** = 0, then the value in **Auto Learn Time** continues to be used.

When the bq34210-Q1 device is operating in Resistance Slope Decisioning mode and a power cycle is detected, such that the timer is stopped and restarted, then newly calculated values of **RRate** will no longer be compared against the long-term value of the resistance slope. Thus, the `[RSDLAlert]` and `[RSDLWarn]` flags will never be set. The `[RSDLI]` flag is set to indicate an interruption has occurred.

In addition, a new value of **RRate** cannot be calculated until two learning phases are completed with the device maintaining power between them, so a valid time is available for the calculation.

If the system designer is concerned about the power drawn by the bq34210-Q1 timer, another option is for the system to power up the bq34210-Q1 device, maintain power long enough for the device to complete two learning phases and calculate a valid **RRate** value for evaluation. The device can then be powered down until another evaluation is needed, in which case the sequence can be repeated.

### 1.3.3.8 Initial Rcell and RRate Learning Process

When the cell is first put into service, **Initial Learn Pulse Number** learning phases will be initiated, each resulting in a calculated **Rcell** value. These **Rcell** values will be averaged and stored as **Initial Rcell**.

The `EOS_RCELL_RRATE_LEARN()` command is available for the host to initiate the measurement of an **Initial Rcell** value. This command will also reset the timer measuring the time since completion of the **Initial Rcell** measurement.

---

**NOTE:** The **Initial Rcell** measurement can be done while in test mode, but the **Initial RRate** measurement cannot practically be done in test mode with an actual cell, due to the minimal change expected in the values of **Rcell** when using the short time durations of the test mode.

---

If any fault is detected during the **Initial Rcell** or **Initial RRate** measurement process, all learned data associated with the **Rcell** measurement in progress is discarded, and the device will initiate a new learning phase after **Auto Learn Retry Time**. If the **Initial RRate** value measured by the device is 0 or negative, this result is ignored, and the device will still consider **Initial RRate** not yet learned. In this case, the host should initiate a new **Initial RRate** using `EOS_RCELL_RRATE_LEARN()`.

The time since the last successful calculation of **Rcell** is provided via the `EOSSTATUS2()` command. If timing were disrupted since the last **Rcell** calculation, such as caused by a power cycle on the device, then this register will read 0 until a new **Rcell** is calculated.

Similarly, the time since the successful calculation of **Initial Rcell** is also provided via the `EOSSTATUS2()` command. If timing was disrupted since the **Initial Rcell** calculation, this register will read 0, and the `[RSDLI]` flag will be set.

When the cell is first put into service, the first learning phases that are initiated are used to calculate multiple values for **RRate**. These multiple values are averaged and stored as **Initial RRate**. For the **Initial RRate** procedure to operate, the **Auto Learn Time** cannot be set = 0.

---

**NOTE:** For the EOS Determination function to provide best results, it is important that the values of **Rcell** be measured at a consistent level of charge. This means it cannot directly be used together with JEITA charging without additional steps.

---

If the **Initial Learn Pulse Number** is set greater than 1, **Learn Voltage Restore** is set = 1, and **Learn Sequence Mode** is set = 1 (DISCHARGE-BEFORE-CHARGE mode), the bq34210-Q1 device will wait for the cell to be charged after each **Learn Post-Relax Phase** is complete before it completes the learning cycle for a single initial learn pulse. It then initiates the next learning cycle for the next initial learn pulse.

However, if the **Learn Voltage Restore** is set = 0, then the bq34210-Q1 device will wait for the cell to be charged back after the **Learn Post-Relax Phase** is complete, but will immediately complete the learning cycle and initiate a new learning cycle for the next initial learn pulse. This will result in each of the multiple initial learn pulses being captured at slightly different depth-of-discharge, which can introduce an additional error into the measurement, depending on the battery chemistry used. To avoid this error, it is recommended that either the **Learn Voltage Restore** be set = 1 or the **Initial Learn Pulse Number** be set = 1.

Because the Learn Discharge Pulses only discharge the battery a small amount, recharging to compensate for this small discharge may create difficulty in achieving proper charge termination, depending on the battery chemistry used. This case should be evaluated during development, and if necessary, the pertinent charge termination settings can be adjusted to address this issue. For example, the **Current Taper Window** and **Minimum Taper Capacity** may need to be reduced to facilitate proper charge termination.

A possible issue can arise if the bq34210-Q1 gauge is configured for CHARGE-BEFORE-DISCHARGE mode, and a fault occurs after charging, but before the Learn Discharge Phase has completed. Then when the device attempts a new learning phase, it may have difficulty achieving proper charge termination, since the battery was already charged to the required level. In this case, a possible workaround would be to enable the learning load and discharge the battery back to the original level before the next learning phase occurs.

## Functional Description

### 2.1 Device Configuration

The configuration options are configured via the following **Smoothing Config** and **Operation Config A** data memory registers. These registers are programmed and read via the methods described in [Section 5.1, Accessing the Data Memory](#).

#### 2.1.1 Smoothing Config Register

**Table 2-1. Smoothing Config Register Bit Definition**

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
	RSVD	RSVD	RSVD	RSVD	SMOOTH EOC_EN	SMEXT	VAVG	SMEN
<b>Default</b>	0	0	0	0	0	0	0	0
	<b>0x00</b>							

RSVD = Reserved

SMOOTHEOC\_EN = Allows smoothing of RemCap once Current starts decreasing during the end of charge (EOC).  
 0 = End of charge smoothing is not enabled.  
 1 = End of charge smoothing is enabled (default).

SMEXT = When set to 1, smoothing continues to EDV1 and EDV0 points. When set to 0, smoothing stops at EDV2. Default is 0.

VAVG = Enables smoothing to use average voltage

When set to 1, smoothing uses average voltage. When set to 0 smoothing uses measured voltage. Default is 0.

SMEN = Smoothing result is reported on *RemainingCapacity()*.

When set to 1, the smoothing result is reported on *RemainingCapacity()*. When set to 0, the normal CEDV remaining capacity is reported. Default is 0.

#### 2.1.2 Operation Configuration A (Operation Config A) Register

**Table 2-2. Operation Config A Register Bit Definitions**

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
<b>High Byte</b>	TEMPS	Default Seal	ALERT_POL	ALERT_EN	SCALED	SLEEP	SLPWAKE CHG	JEITA
<b>Low Byte</b>	DefaultFA	LFOONLY	NIMH_CHG _EN	NI_DT	NI_DV	WAKE_EN	WK_TH1	WK_TH0

##### High Byte

TEMPS = When set to 1, the external thermistor is selected for *Temperature()* measurements.

Default Seal = Seal during POR

0 = No Seal after POR (default)

1 = Seal after POR

ALERT\_POL = Sets the polarity of the ALERT pin

0 = ALERT is active low.

- 1 = ALERT is active high.
- ALERT\_EN = When set to 1, the ALERT pin is active.
- SCALED = Scaled capacity and/or current bit  
The mA and mAh settings and reports will take on a value that is artificially scaled. This setting has no actual effect within the gauge. It is the responsibility of the host to reinterpret the reported values. Scaled current measurement is achieved by calibrating the current measurement to a value lower than actual.
- SLEEP = The fuel gauge can enter SLEEP, if operating conditions allow. True when set.
- SLPWAKECHG = Accumulate estimated charge on wake from sleep when *Current()* > **Sleep Current**, but not enough to trigger a wake event. Enabled when set.
- JEITA = Enables JEITA Temperature functionality. See [Charging and Charge Termination](#).
- Low Byte**
- DefaultFA = Default to FULL ACCESS mode on power up (1 = yes)
- LFOONLY = Use LFO only for ADC conversions (1 = yes).  
LFOONLY is a lower power mode, but has a reduction in accuracy.
- NIMH\_CHG\_EN = When set, the device performs primary charge termination using the NiXX algorithm. See [Charging and Charge Termination](#).
- NI\_DT = When set, the device performs primary charge termination using the  $\Delta T/\Delta t$  algorithm. See [Charging and Charge Termination](#).
- NI\_DV = When set, the device performs primary charge termination using the  $-\Delta V_t$  algorithm. See [Charging and Charge Termination](#).
- WAKE\_EN, WK\_TH1, WK\_TH0 = These bits configure the current wake function. See the *bq34210-Q1 Automotive 1-Series Cell System-Side CEDV Fuel Gauge for Rarely Discharged Batteries Data Sheet (SLUSCG1)* for threshold values.

## 2.2 External Pin Functions

### 2.2.1 Wake-Up Comparator

The wake-up comparator indicates a change in cell current while the fuel gauge is in SLEEP mode. The **Operation Config A [WK\_TH1:WK\_TH0]** bits select the appropriate comparator threshold for the sense resistor value used. The **Operation Config A [WAKE\_EN]** bit selects one of two possible voltage threshold ranges for the given sense resistor selection. An internal interrupt is generated when the threshold is reached in either the charge or discharge direction. Setting the **[WK\_TH1]** and **[WK\_TH0]** bits to 0 disables this feature.

### 2.2.2 Autocalibration

The fuel gauge provides an autocalibration feature that measures the voltage offset error across SRP and SRN as operating conditions change. It subtracts the resulting offset error from the normal sense resistor voltage,  $V_{SR}$ , for maximum measurement accuracy.

Autocalibration of the coulomb counter begins on entry to SLEEP mode, except if *Temperature()* is  $\leq 5^\circ\text{C}$  or *Temperature()*  $\geq 45^\circ\text{C}$ .

The fuel gauge also performs a single offset when:

- The condition of *AverageCurrent()*  $\leq 100$  mA
- {voltage change since last offset calibration  $\geq 256$  mV} or {temperature change since last offset calibration is greater than  $8^\circ\text{C}$  for  $\geq 60$  s}.

Capacity and current measurements continue at the last measured rate during the offset calibration when these measurements cannot be performed. If the battery voltage drops more than 32 mV during the offset calibration, the load current has likely increased; thus, the offset calibration is stopped. The *CONTROL\_STATUS()[CCA]* bit is set during coulomb counter autocalibration.

## 2.3 Temperature Measurement

The fuel gauge typically measures battery temperature via its TS input to supply battery temperature status information to the gas gauging algorithm and charger-control sections of the gauge. Alternatively, it can be configured to use an internal on-chip temperature sensor or receive temperature data from the host processor. See [Temperature\(\): 0x06 and 0x07](#) for specific information on configuration options. Regardless of which temperature configuration is used, the host processor can request the current battery temperature by reading the *Temperature()*, and for internal temperature, *InternalTemperature()*.

The external thermistor circuit requires the use of an 10K NTC 103AT-type thermistor.

### 2.3.1 Overtemperature Indication

#### 2.3.1.1 Overtemperature: Charge (OT Chg)

If during charging, *Temperature()* reaches the threshold of **OT Chg** for a period of **OT Chg Time**, and *Current()* > **Chg Current Threshold**, then the *BatteryStatus()[OTC]* bit is set. When *Temperature()* falls to **OT Chg Recovery**, the *BatteryStatus()[OTC]* bit is cleared.

If **OT Chg Time** = 0, then the feature is completely disabled.

#### 2.3.1.2 Overtemperature: Discharge (OT Dsg)

If during discharging, *Temperature()* reaches the threshold of **OT Dsg** for a period of **OT Dsg Time**, and *Current()* ≤ **-Dsg Current Threshold**, then the *BatteryStatus()[OTD]* bit is set. When *Temperature()* falls to **OT Dsg Recovery**, the *BatteryStatus()[OTD]* bit is cleared.

If **OT Dsg Time** = 0, then the feature is completely disabled.

### 2.3.2 Undertemperature Indication

#### 2.3.2.1 Undertemperature: Charge (UT Chg)

If during charging, *Temperature()* reaches the threshold of **UT Chg** for a period of **UT Chg Time**, and *Current()* > **Chg Current Threshold**, then the *BatteryStatus()[UTC]* bit is set. When *Temperature()* rises to **UT Chg Recovery**, the *BatteryStatus()[UTC]* bit is cleared.

If **UT Chg Time** = 0, then the feature is completely disabled.

#### 2.3.2.2 Undertemperature: Discharge (UT Dsg)

If during discharging, *Temperature()* reaches the threshold of **UT Dsg** for a period of **UT Dsg Time**, and *Current()* ≤ **-Dsg Current Threshold**, then the *BatteryStatus()[UTD]* bit is set. When *Temperature()* rises to **UT Dsg Recovery**, the *BatteryStatus()[UTD]* bit is cleared.

If **UT Dsg Time** = 0, then the feature is completely disabled.

## 2.4 Battery Condition Warnings

### 2.4.1 Battery Low Warning

The bq34210-Q1 device can indicate, and optionally trigger an alert signal, when the battery voltage falls below a programmable threshold. This feature is disabled if **Battery Low Time** is set to 0.

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**NOTE:** If **Battery Low Time** is set to 30 seconds or higher, the device may initiate an automatic offset calibration during the time window, resulting in the BATLOW signal being delayed approximately an additional 15–20 seconds beyond the **Battery Low Time** setting.

---

Status	Condition	Action
Normal	$Voltage() > \mathbf{BATLOW: Battery Low Set Threshold}$	$BatteryStatus()[BATLOW] = 0$
Trip	$Voltage() \leq \mathbf{BATLOW: Battery Low Set Threshold}$ For $\mathbf{BATLOW: Battery Low Time}$	$BatteryStatus()[BATLOW] = 1$
Recovery	$Voltage() > \mathbf{BATLOW: Battery Low Clear Threshold}$	$BatteryStatus()[BATLOW] = 0$

### 2.4.2 Battery High Warning

The bq34210-Q1 device can indicate, and optionally trigger an alert signal, when the battery voltage falls below a programmable threshold. This feature is disabled if **Battery High Time** is set to 0.

Status	Condition	Action
Normal	$Voltage() > \mathbf{BATHIGH: Battery High Set Threshold}$	$BatteryStatus()[BATHIGH] = 0$
Trip	$Voltage() \leq \mathbf{BATHIGH: Battery High Set Threshold}$ For $\mathbf{BATHIGH: Battery High Time}$ duration	$BatteryStatus()[BATHIGH] = 1$
Recovery	$Voltage() > \mathbf{BATHIGH: Battery High Clear Threshold}$	$BatteryStatus()[BATHIGH] = 0$

### 2.4.3 Battery Low SOC Warning

The bq34210-Q1 device can indicate, and optionally trigger an alert signal, when the battery state-of-charge (SOC) falls below a programmable threshold. This feature is disabled by setting **SOC Low Threshold** and **SOC Low Recovery** to 0.

Status	Condition	Action
Normal	$RelativeStateOfCharge() > \mathbf{SOC Low Threshold}$	$BatteryStatus()[SOCLOW] = 0$
Trip	$RelativeStateOfCharge() \leq \mathbf{SOC Low Threshold}$	$BatteryStatus()[SOCLOW] = 1$
Recovery	$RelativeStateOfCharge() > \mathbf{SOC Low Recovery}$	$BatteryStatus()[SOCLOW] = 0$

### 2.4.4 Battery Level Threshold

The battery level threshold (BLT) feature indicates when the SOC of a battery pack has depleted to a certain value set in a DF register. This feature allows a host to program two capacity-based thresholds that govern the triggering of the BLT flag and the setting or clearing of the  $OperationStatus()[BLT]$  on the basis of  $RemainingCapacity()$ . The interrupt on pins ALERT1 and/or ALERT2 is enabled or disabled via **Alert1\_6[BLT]** and **Alert2\_6[BLT]**, respectively.

- $OperationStatus()[BLT]$  is set when:
  - Current  $> 0$  and  $RemainingCapacity() > BLTChargeSet()$ . This threshold is initialized at reset from **Init Charge Set**.
  - Current  $\leq 0$  and  $RemainingCapacity() < BLTDischargeSet()$ . This threshold is initialized at reset from **Init Discharge Set**.
- When either the  $BLTDischargeSet()$  or  $BLTChargeSet()$  command is received,  $OperationStatus()[BLT]$  will clear and the flag will be deasserted. The new threshold is written to either  $BLTDischargeSet()$  or  $BLTChargeSet()$ .
- At reset, the flag is set to the deasserted state.

**Table 2-3. BLTDischargeSet()**

Name	Access			Protocol	Type	Min	Max	Default	Unit
	SE	US	FA						
BLT Discharge Set	R/W	R/W	R/W	Word	S2	—	65535	150	mAh

This read/write word command updates the BLT set threshold for DISCHARGE mode for the next BLT flag assertion, deasserts the present BLT flag, and clears the  $OperationStatus()[BLT]$  bit.

**Table 2-4. BLTChargeSet()**

Name	Access			Protocol	Type	Min	Max	Default	Unit
	SE	US	FA						
BLT Charge Set	R/W	R/W	R/W	Word	S2	—	65535	175	mAh

The read/write word command updates the BLT set threshold for CHARGE mode for the next BLT flag assertion, deasserts the present BLT flag, and clears the *OperationStatus()*[BLT] bit.

**Table 2-5. Init Discharge Set**

Class	Subclass	Name	Format	Size in Bytes	Min Value	Max Value	Default Value	Unit
Settings	BLT	Init Discharge Set	I2	2	0	32767	150	mAh

**Description:** Initial value for *BLTDischargeSet()*

**Table 2-6. Init Charge Set**

Class	Subclass	Name	Format	Size in Bytes	Min Value	Max Value	Default Value	Unit
Settings	BLT	Init Charge Set	I2	2	0	32767	175	mAh

**Description:** Initial value for *BLTChargeSet()*

## 2.5 Charging and Charge Termination Indication

### 2.5.1 Detecting Charge Termination

For proper fuel gauge operation, the cell **Charging Voltage** must be specified by the user.

The fuel gauge detects charge termination when:

- During two consecutive periods of 40 seconds, the *AverageCurrent()* < **Taper Current**.
- During the same two periods, the accumulated change in capacity must be > 0.25 mAh.
- *Voltage()* > **Charging Voltage – Taper Voltage**.

When this occurs, the *BatteryStatus()*[FC] and [TCA] bits are set depending on the **SOC Flag Config A** [FCSETVCT] and [TCSETVCT] options. Also, if the **CEDV Configuration** [CSYNC] bit is set, then *RemainingCapacity()* is set equal to *FullChargeCapacity()*.

### 2.5.2 Charge Inhibit

The fuel gauge can indicate when battery temperature has fallen below or risen above predefined thresholds **Charge Inhibit Temp Low** or **Charge Inhibit Temp High**, respectively. In this mode, the *BatteryStatus()*[CHGINH] bit is set to indicate this condition. The [CHGINH] bit is cleared once the battery temperature returns to the range [**Charge Inhibit Temp Low + Temp Hys, Charge Inhibit Temp High – Temp Hys**].

The charging should not start when the temperature is below the **Charge Inhibit Temp Low** or above the **Charge Inhibit Temp High**. The charging can continue if the charging starts inside the window [**Charge Inhibit Temp Low, Charge Inhibit Temp High**].

## 2.6 Power Modes

The fuel gauge has different power modes: NORMAL, SLEEP, CONFIG UPDATE, and SHUTDOWN.

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**NOTE:** Prior to NORMAL mode is INITIALIZATION mode, which is the mode immediately following battery attachment. This is when the ROM parameters are moved to volatile memory.

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- In NORMAL mode, the fuel gauge is fully powered and can run any allowable task.

- In SLEEP mode, the fuel gauge turns off the high-frequency oscillator (when in RELAXATION mode) and is in a reduced-power state, periodically taking measurements and performing calculations.
- In CONFIG UPDATE mode, the internal configuration data in the fuel gauge can be modified.
- SHUTDOWN mode is the lowest power mode and requires a power cycle or signal on the ALERT pin.

Figure 2-1 shows the relationship between these modes.

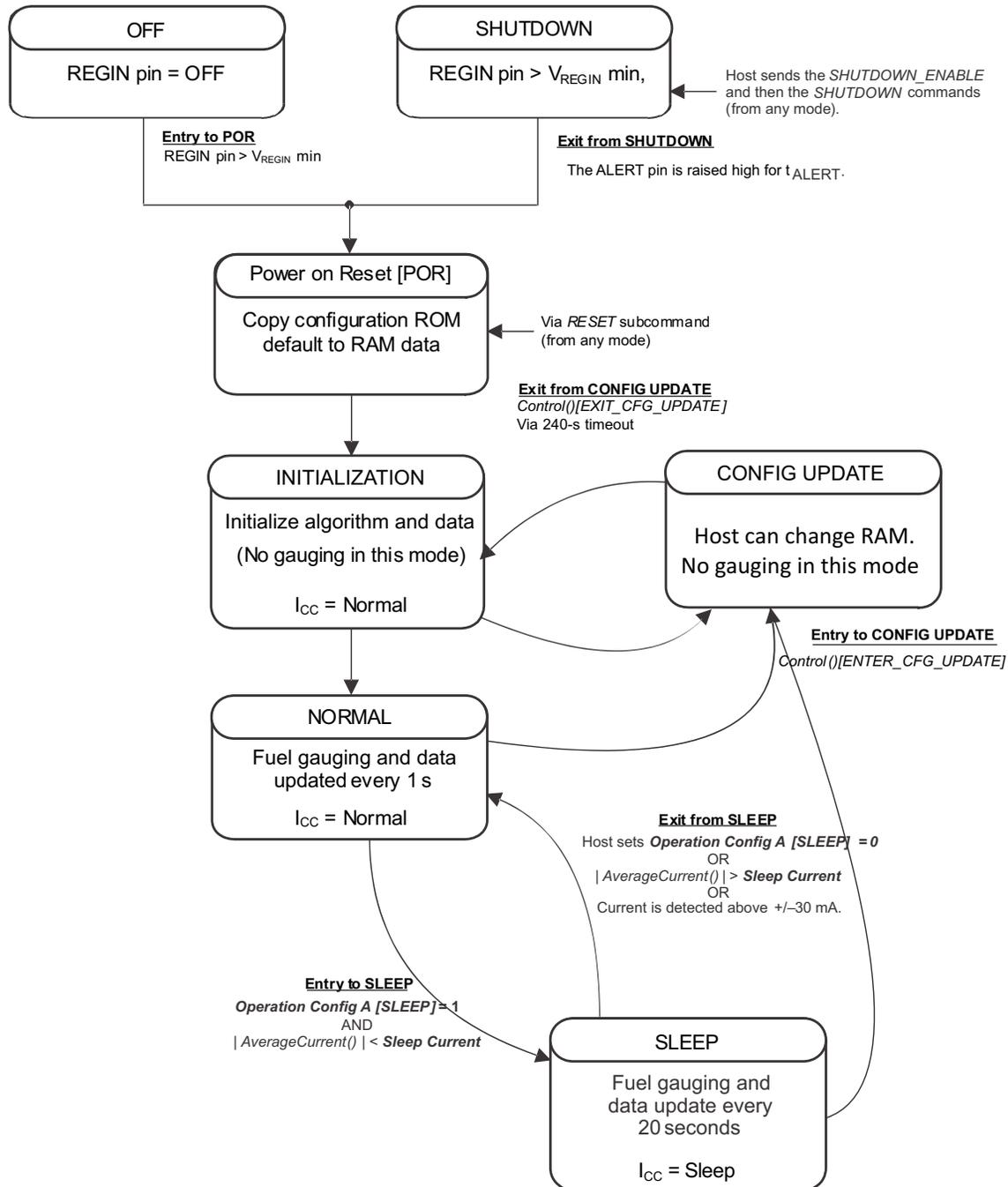


Figure 2-1. Power Mode Diagram for System Shutdown

### 2.6.1 NORMAL Mode

The fuel gauge is in NORMAL mode when not in any other power mode. During this mode, *Current()*, *Voltage()*, and *Temperature()* measurements are taken, and the interface data set is updated. Decisions to change states are also made. This mode is exited by activating a different power mode.

Because the gauge consumes the most power in the NORMAL mode, the CEDV algorithm minimizes the time the fuel gauge remains in this mode.

### 2.6.2 SLEEP Mode

SLEEP mode is entered automatically if the feature is enabled (**Operation Config A [SLEEP]** bit = 1) and *Current()* is below the programmable level **Sleep Current**. Once entry into SLEEP mode is qualified, but prior to entering it, the fuel gauge performs a coulomb counter autocalibration to minimize offset.

During SLEEP mode, the fuel gauge periodically takes data measurements and updates its data set. However, a majority of its time is spent in an idle condition.

The fuel gauge exits the SLEEP mode if any entry condition is broken, specifically when either:

- *Current()* rises above **Sleep Current**.
- A current in excess of  $I_{WAKE}$  through  $R_{SENSE}$  is detected.

### 2.6.3 SHUTDOWN Mode

In SHUTDOWN mode, REG18 is disabled so internal power and all RAM-based volatile data is lost. The host can command the gauge to immediately enter SHUTDOWN mode by first unsealing the gauge then enabling the mode with a **SHUTDOWN\_ENABLE** subcommand (0x001B), followed by the **SHUTDOWN** subcommand (0x001C). To exit SHUTDOWN mode, the ALERT pin must be raised from logic low to logic high for  $t_{ALERT}$ .

Both **SHUTDOWN\_ENABLE** and **SHUTDOWN** are only available while unsealed. Sending **SHUTDOWN\_ENABLE** will set **SHUTDOWN\_EN** in *CONTROL\_STATUS()*. Sending **SHUTDOWN** while **SHUTDOWN\_EN** is set will cause the device to immediately shut down. Sealing the gauge will clear **SHUTDOWN\_EN**.

Once in SHUTDOWN mode, there are two methods to exit. A power cycle (battery removal and insertion) is one method. The second method uses the ALERT pin alternative function. Pulling the ALERT pin high (the time is specified in the data sheet) enables the bq34210-Q1 to exit SHUTDOWN mode and reenter NORMAL mode.

## 2.7 CONFIG UPDATE Mode

If the application requires different configuration data for the fuel gauge, the system processor can update RAM-based data memory parameters using the *Control()* **ENTER\_CFG\_UPDATE** subcommand to enter the CONFIG UPDATE mode. Operation in this mode is indicated by the *OperationStatus()* [**CFGUPDATE**] status bit. In this mode, fuel gauging is suspended while the host uses the data commands to modify the configuration data blocks. To resume fuel gauging, the host sends a *Control()* **EXIT\_CFG\_UPDATE**, or **EXIT\_CFG\_UPDATE\_REINIT** subcommand to exit the CONFIG UPDATE mode, which clears *OperationStatus()* [**CFGUPDATE**]. After a timeout of approximately 240 seconds (4 minutes), the gauge automatically exits the CONFIG UPDATE mode if it has not received an **EXIT\_CFG\_UPDATE** or **EXIT\_CFGUPDATE\_REINIT** subcommand from the host.

## 2.8 Application-Specific Information

### 2.8.1 Battery Profile Storage and Selection

The fuel gauge supports two predefined CEDV profiles in device ROM that customers can use by sending the **SET\_PROFILE\_1** or **SET\_PROFILE\_2** command.

In situations where the user wants to input a custom CEDV profile, they must use the system controller to set the defaults during system initialization.

To send these commands, the gauge must be in CONFIG UPDATE mode.

## 2.8.2 First OCV Measurement

Upon power-up, an open-circuit voltage (OCV) measurement of the battery is made via the BAT pin. For the best gauging results, the system load during the OCV measurement should not exceed a C/20 discharge rate of the battery.

Upon completion of the OCV voltage measurement, `BatteryStatus()[OCVCOMP]` is set.

## 2.9 Additional Data Memory Parameter Descriptions

### 2.9.1 Calibration

The calibration method requires a correction due to offset errors, using a number of samples to get a statistical average for the golden image. The parameters of particular interest are listed in the following sections.

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**NOTE:** Calibrate the gauge only when it is in FULL ACCESS UNSEALED mode.

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#### 2.9.1.1 CC Gain

**CC Gain** sets the mA current scale factor for the coulomb counter. Use calibration routines to set this value.

#### 2.9.1.2 CC Delta

**CC Delta** sets the mAh capacity scale factor for the coulomb counter. Use calibration routines to set this value.

### 2.9.2 Coulomb Counter Offset (CC Offset)

This register value stores the coulomb counter offset compensation. It is set by automatic calibration of the device.

### 2.9.3 Board Offset

This register value stores the compensation for the PCB dependent coulomb counter offset. It is recommended to use characterization data of the actual PCB to set this value.

### 2.9.4 Int Temp Offset

This register value stores the internal temperature sensor offset compensation. Use calibration routines to set this value.

### 2.9.5 Ext Temp Offset

This register value stores the external temperature sensor offset compensation. Use calibration routines to set this value.

### 2.9.6 Pack VOffset

This register value stores the Pack voltage offset measured at the Pack pin. Use calibration routines to set this value.

### 2.9.7 Internal Temp Model

Internal Model Coefficient 1 through 4 characterize the internal thermistor of the device. Do not modify these values without consulting TI.

### 2.9.8 Ext a Coef and Ext b Coef

**External Model Coefficient 1-5** and **Ext Model Coefficient b 1-4** are the thermistor temperature linearization polynomial coefficients. The default values were computed with a Semitec 103AT thermistor. If a different type of thermistor is used, then the coefficients will need to be changed. Contact TI to generate coefficients for a different thermistor.

### 2.9.9 RC0

RC0 is the ideal value for the internal pullup resistor on the TS pin, shown in counts from the ADC based on typical reference voltage. No modifications to this value are required

### 2.9.10 Filter

Defines the filter constant used in  $\pm$  *AverageCurrent()* calculation:

*AverageCurrent()* =  $a \times \text{AverageCurrent}() \text{ old} + (1-a) \times \text{Current}()$  with:

$a = \text{Filter}/256$ ; time constant =  $1 \text{ s}/\ln(1/a)$  (default = 14.5 s)

### 2.9.11 Deadband

Any current within  $\pm$  **Deadband** is reported as 0 mA by the *Current()* function.

### 2.9.12 CC Deadband

This constant defines the deadband voltage for the measured voltage between the SRP and SRN pins used for capacity accumulation in units of 294 nV. Any voltages within  $\pm$ **CC Deadband** do not contribute to capacity accumulation.

### 2.9.13 SOC Flag Configuration A (SOC Flag Config A) Register

The settings in **SOC Flag Config A** configure how the [TC], [FC], and [TD] flags in *GaugingStatus()* set and clear. These flags are also used to set the [TCA], [TDA], and [FC] flags in *BatteryStatus()*.

**Table 2-7. SOC Configuration Flag A Register Bit Definitions**

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
<b>High Byte</b>	RSVD	RSVD	RSVD	RSVD	TCSETVCT	FCSETVCT	RSVD	RSVD
<b>Default</b>	0	0	0	0	1	1	0	0
	<b>0x0C</b>							
<b>Low Byte</b>	TCCLEARRSOC	TCSETRSOC	TCCLEARV	TCSETV	TDCLEARRSOC	TDSETRSOC	TDCLEARV	TDSETV
<b>Default</b>	1	0	0	0	1	1	0	0
	<b>0x8C</b>							

RSVD = Reserved

TCSETVCT = Enables *BatteryStatus()*[TCA] flag set on primary charge termination

0 = Disabled

1 = Enabled (default)

FCSETVCT = Enables *BatteryStatus()*[FC] flag set on primary charge termination

0 = Disabled

1 = Enabled (default)

TCCLEARRSOC = Enables *BatteryStatus()*[TCA] flag clear when *RelativeStateOfCharge()*  $\leq$  **TC:Clear % RSOC Threshold**

0 = Disabled

1 = Enabled (default)

TCSETRSOC = Enables *BatteryStatus()*[TCA] flag set when *RelativeStateOfCharge()*  $\geq$  **TC:Set % RSOC Threshold**

0 = Disabled (default)

- 1 = Enabled
- TCCLEARV = Enables *BatteryStatus()[TCA]* flag clear when *Voltage() ≤ TC:Clear Voltage Threshold*  
 0 = Disabled (default)  
 1 = Enabled
- TCSETV = Enables *BatteryStatus()[TCA]* flag set when *Voltage() ≥ TC:Set Voltage Threshold*  
 0 = Disabled (default)  
 1 = Enabled
- TDCLEARRSOC = Enables *BatteryStatus()[TDA]* flag clear when *RelativeStateOfCharge() ≥ TD:Clear % RSOC Threshold*  
 0 = Disabled  
 1 = Enabled (default)
- TDSETRSOC = Enables *BatteryStatus()[TDA]* flag set when *RelativeStateOfCharge() ≤ TD:Set % RSOC Threshold*  
 0 = Disabled  
 1 = Enabled (default)
- TDCLEARV = Enables *BatteryStatus()[TDA]* flag clear when *Voltage() ≥ TD:Clear Voltage Threshold*  
 0 = Disabled (default)  
 1 = Enabled
- TDSETV = Enables *BatteryStatus()[TDA]* flag set when *Voltage() ≤ TD:Set Voltage Threshold*  
 0 = Disabled (default)  
 1 = Enabled

## 2.9.14 SOC Flag Configuration B (SOC Flag Config B) Register

**Table 2-8. SOC Configuration Flag B Register Bit Definitions**

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
	FCCLEAR RSOC	FCSET RSOC	FCCLEARV	FCSETV	FDCLEAR RSOC	FDSET RSOC	FDCLEARV	FDSETV
<b>Default</b>	1	0	0	0	1	1	0	0
	<b>0x8C</b>							

- FCCLEARRSOC = Enables *BatteryStatus()[FC]* flag clear when *RelativeStateOfCharge() ≤ FC:Clear % RSOC Threshold*  
 0 = Disabled  
 1 = Enabled (default)
- FCSETRSOC = Enables *BatteryStatus()[FC]* flag set when *RelativeStateOfCharge() ≥ FC:Set % RSOC Threshold*  
 0 = Disabled (default)  
 1 = Enabled
- FCCLEARV = Enables *BatteryStatus()[FC]* flag clear when *Voltage() ≤ FC:Clear Voltage Threshold*  
 0 = Disabled (default)  
 1 = Enabled
- FCSETV = Enables *BatteryStatus()[FC]* flag set when *Voltage() ≥ FC:Set Voltage Threshold*  
 0 = Disabled (default)  
 1 = Enabled
- FDCLEARRSOC = Enables *BatteryStatus()[FD]* flag clear when *RelativeStateOfCharge() ≥ FD:Clear % RSOC Threshold*  
 0 = Disabled  
 1 = Enabled (default)
- FDSETRSOC = Enables *BatteryStatus()[FD]* flag set when *RelativeStateOfCharge() ≤ FD:Set % RSOC Threshold*  
 0 = Disabled  
 1 = Enabled (default)
- FDCLEARV = Enables *BatteryStatus()[FD]* flag clear when *Voltage() ≥ FD:Clear Voltage Threshold*  
 0 = Disabled (default)  
 1 = Enabled

FDSETV = Enables *BatteryStatus()*[FD] flag set when *Voltage()* ≤ **FD:Set Voltage Threshold**  
0 = Disabled (default)  
1 = Enabled

### 2.9.15 CEDV Gauging Configuration (CEDV Config) Register

**Table 2-9. CEDV Gauging Configuration Register Bit Definitions**

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
<b>High Byte</b>	RSVD	RSVD	RSVD	SME0	RSVD	FC_FOR_VDQ	RSVD	FCC_LIMIT
<b>Default</b>	0	0	0	0	0	0	0	0
<b>Low Byte</b>	RSVD	RSVD	FIXED_EDV0	SC	EDV_CMP	RSVD	CSYNC	CCT
<b>Default</b>	0	0	0	0	0	0	0	0

RSVD = Reserved

SME0 = Smoothing towards EDV0 enable. Used with SMEN and SMEXT.

0 = Default

1 = Disabled

RSVD = Reserved

FC\_FOR\_VDQ =

0 = FC is not required to get VDQ.

1 = FC is required to get VDQ.

RSVD = Reserved

FCC\_LIMIT = Learned FCC is not allowed to be higher than *DesignCapacity()*. Enabled when set.

RSVD = Reserved

FIXED\_EDV0 = This bit is used when **[EDV\_CMP]** = 1 to determine if EDV0 will use a fixed threshold.

When set to 1, **FIXED\_EDV0** will be used.

When set to 0, dynamic EDV0 will be used (default).

SC = This is a selection for learning cycle optimization for a smart charger or independent charger.

0 = Learning Cycle optimized for Smart Charger (default)

1 = Learning Cycle optimized for Independent Charger

EDV\_CMP = Method to calculate EDV compensation

0 = Use fixed EDV values.

1 = Use the EDV compensation to calculate the EDV values.

RSVD = Reserved

CSYNC = Sync *RemainingCapacity()* with *FullChargeCapacity()* at valid charge termination

0 = NOT Synchronized (default)

1 = Synchronized

CCT = Cycle Count Threshold

0 = Use CC % of *DesignCapacity()* (default).

1 = Use CC % of *FullChargeCapacity()*.

### 2.9.16 EMF

This value is the no-load cell voltage higher than the highest cell EDV threshold computed.

### 2.9.17 C0

This value is the no-load, capacity-related EDV adjustment factor.

**2.9.18 R0**

This value is the first order rate dependency factor, accounting for battery impedance adjustment.

**2.9.19 T0**

This value adjusts the variation of impedance with battery temperature.

**2.9.20 R1**

This value adjusts the variation of impedance with battery capacity.

**2.9.21 TC**

This value adjusts the variation of impedance for cold temperatures ( $T < 23^{\circ}\text{C}$ ).

**2.9.22 C1**

This value is the desired reserved battery capacity remaining at EDV0.

**2.9.23 Age Factor**

This value enables the bq34210-Q1 device to correct the EDV detection algorithm to compensate for cell aging.

**2.9.24 Fixed EDV0**

This value is the EDV0 threshold if **[CEDV]** is clear in **CEDV Config**.

**2.9.25 Fixed EDV1**

This value is the EDV1 threshold if **[CEDV]** is clear in **CEDV Config**.

**2.9.26 Fixed EDV2**

This value is the EDV2 threshold if **[CEDV]** is clear in **CEDV Config**.

**2.9.27 Battery Low %**

**Battery Low %** sets the EDV2 level—the highest of the EDV voltages.

**2.9.28 Learning Low Temp**

This value specifies the minimum temperature above which a discharge must maintain to qualify for capacity learning.

**2.9.29 Overload Current**

This value sets the upper current range for EDV detection beyond which EDV detection is halted.

**2.9.30 Self Discharge Rate**

This value is the estimated self-discharge rate of battery.

**2.9.31 Electronics Load**

This value should be set to a discharge rate determined by the battery electronics current consumption.

**2.9.32 Near Full**

This value sets the start of discharge condition for qualified capacity learning.

### 2.9.33 Reserve Capacity

This value determines how much actual remaining capacity exists when the fuel gauge reports 0 for *RemainingCapacity()* before reaching EDV0. This accommodates a controlled shutdown based on battery capacity rather than a specific voltage.

---

**NOTE:** If the **Reserve Capacity** is non-zero, then it should be added to the desired **Near Full** capacity as well.

---

### 2.9.34 Charge Efficiency (Chg Eff)

This is a value to compensate for efficiency loss during charging when estimating total capacity value. This is based on every coulomb counting charge period and adjusted to reflect the total charge efficiency of the battery pack.

### 2.9.35 Discharge Efficiency (Dsg Eff)

This is a value to compensate for efficiency loss during discharging when estimating total capacity value. This is based on every coulomb counting discharge period and adjusted to reflect the total discharge efficiency of the battery pack.

### 2.9.36 Depth of Discharge (DOD) at EDV2

This value is updated by the CEDV gauging algorithm when battery voltage reaches EDV2. If **Battery Low %** is altered, the **DOD at EDV2** value should be set to  $(1 - \text{Battery\_Low\%}) \times 16384$ , where  $\text{Battery\_Low\%} = \text{Battery Low \%} \div 100$ . The firmware default value is 15232, which corresponds to a **Battery Low % = 703 (.01 %)**.

### 2.9.37 Design Capacity

The *DesignCapacity()* function reports **Design Capacity mAh**.

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**NOTE:** There is only a single **Design Capacity** value for all battery profiles. When setting the battery profile in production, it may be necessary to update **Design Capacity** as well for accurate *StateOfHealth()* results.

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### 2.9.38 Design Voltage

The default value of *DesignVoltage()* is stored in **Design Voltage** and copied upon bq34210-Q1 initialization.

### 2.9.39 Cycle Count %

If the *[CCT]* bit is set, the cycle count function counts the accumulated discharge of (*FullChargeCapacity()* × **CC %**) as one cycle. If (*FullChargeCapacity()* × **CC %**) is smaller than **CC Threshold**, **CC Threshold** is used for counting.

### 2.9.40 Charge Inhibit Temp Low

The bq34210-Q1 device does not allow the battery pack to charge if *Temperature()* is below **Charge Inhibit Temp Low**. The *[CHGINH]* bit is set in *BatteryStatus()*. The default value is 0°C. Charging is allowed once the temperature is above **Charge Inhibit Temp Low** plus **Temp Hys** value. The *[CHGINH]* bit is reset in the *BatteryStatus()* register.

### 2.9.41 Charge Inhibit Temp High

The bq34210-Q1 device does not allow the battery pack to charge if *Temperature()* is above **Charge Inhibit Temp High**. The [CHGINH] bit is set in the *BatteryStatus()*. The default value is 45°C. Charging is allowed once the temperature is below **Charge Inhibit Temp High** plus **Temp Hys** value. The [CHGINH] bit is reset in the *BatteryStatus()* register.

### 2.9.42 Temp Hys

The bq34210-Q1 device has a temperature hysteresis for both **Charge Inhibit Temp High** and **Charge Inhibit Temp Low** conditions to prevent continuous charger ON/OFF behavior. The default value is 5°C. Charging is allowed once the temperature is below **Charge Inhibit Temp High** plus **Temp Hys** or above **Charge Inhibit Temp Low** plus **Temp Hys** value.

### 2.9.43 Charging and Charge Termination

The bq34210-Q1 does not directly control charging and charge termination, but its registers and commands create an interface to work with the charging system. For proper bq34210-Q1 operation, the battery cell charging voltage should be specified by the user in the 3 **Charge Voltage T#-T#** registers. These parameters should be set to the recommended charging voltage battery.

The bq34210-Q1 device includes multiple algorithms for charging and charge termination, including JEITA-based charging, negative temperature-based charging, and negative delta voltage-based charging.

The *ChargingVoltage()* and *ChargingCurrent()* will be selected by the bq34210-Q1 device following the JEITA method, depending on the [JEITA] bit setting. If this bit is set, the voltage and current are selected based on the settings in **Charge Voltage T#-T#**, **Charge Current T#-T#**, and **JEITA T# Temp**. The **JEITA T# Temp** provides temperature boundaries for the temperature category.

If  $Temperature() < JEITA\ T1\ Temp$ , then charging is inhibited,

$ChargingVoltage() = 0,$

$ChargingCurrent() = 0.$

If  $JEITA\ T1\ Temp \leq Temperature() \leq JEITA\ T2\ Temp$ , then

$ChargingVoltage() = Charge\ Voltage\ T1 - T2,$

$ChargingCurrent() = Charge\ Current\ T1 - T2.$

If  $JEITA\ T2\ Temp < Temperature() \leq JEITA\ T3\ Temp$ , then

$ChargingVoltage() = Charge\ Voltage\ T2 - T3,$

$ChargingCurrent() = Charge\ Current\ T2 - T3.$

If  $JEITA\ T3\ Temp < Temperature() \leq JEITA\ T4\ Temp$ , then

$ChargingVoltage() = Charge\ Voltage\ T3 - T4,$

$ChargingCurrent() = Charge\ Current\ T3 - T4.$

If  $JEITA\ T4\ Temp < Temperature()$ , then charging is inhibited,

$ChargingVoltage() = 0,$

$ChargingCurrent() = 0.$

If the [JEITA] bit is reset, then operation is as follows:

If  $Temperature() < JEITA\ T1\ Temp$ , then charging is inhibited,

$ChargingVoltage() = 0,$

$ChargingCurrent() = 0.$

If  $JEITA\ T1\ Temp \leq Temperature() \leq JEITA\ T4\ Temp$ , then

$ChargingVoltage() = Charge\ Voltage\ T2 - T3,$

$ChargingCurrent() = Charge\ Current\ T2 - T3.$

If  $JEITA\ T4\ Temp < Temperature()$ , then charging is inhibited,

$ChargingVoltage() = 0,$

$ChargingCurrent() = 0.$

The device detects valid charge termination in one of three ways:

1. Current Taper method:

1. During two consecutive periods of **Current Taper Window**, the *AverageCurrent()* is less than **Taper Current** AND
2. During the same periods, the accumulated change in capacity > **Minimum Taper Capacity** AND
3. *Voltage()* is > *ChargingVoltage()* – **Taper Voltage**. When this occurs, the [CHG] bit of *BatteryStatus()* is cleared. Also, if the [CSYNC] bit of **CEDV\_Gauging\_Configuration** is set, and *RemainingCapacity()* is set equal to *FullChargeCapacity()*.

2. **Delta Temperature** ( $\Delta T/\Delta t$ ) method:

For  $\Delta T/\Delta t$ , the bq34210-Q1 device detects an increase in temperature over many seconds. The  $\Delta T/\Delta t$  setting is programmable in the temperature step, **Delta Temperature** (0°C – 25.5°C), and the time step, **Delta Temperature Time** (0 s–1000 s). Typical settings for 1°C/minute include 2°C/120 s and 3°C/180 s (default). Longer times may be used for increased slope resolution.

In addition to the  $\Delta T/\Delta t$  timer, a holdoff timer starts (using **Holdoff Time**) when the battery is charged at more than **Holdoff Current** (default is 240 mA), and the temperature is above **Holdoff Temperature**. Until this timer expires,  $\Delta T/\Delta t$  detection is suspended. If *Current()* drops below **Holdoff Current** or *Temperature()* below **Holdoff Temperature**, the holdoff timer resets and restarts only when the current and temperature conditions are met again.

3. Negative Delta Voltage ( $-\Delta V$ ) method:

For negative delta voltage, the bq34210-Q1 device detects a charge termination when the pack voltage drops during charging by **Cell Negative Delta Voltage** for a period of **Cell Negative Delta Time**, during which time, *Voltage()* must be greater than **Cell Negative Delta Qual Voltage**.

When either condition occurs, the *GaugingStatus()*[FC] bit is set. Also, if the [CSYNC] bit of **CEDV\_Gauging\_Configuration** is set, and *RemainingCapacity()* is set equal to *FullChargeCapacity()*.

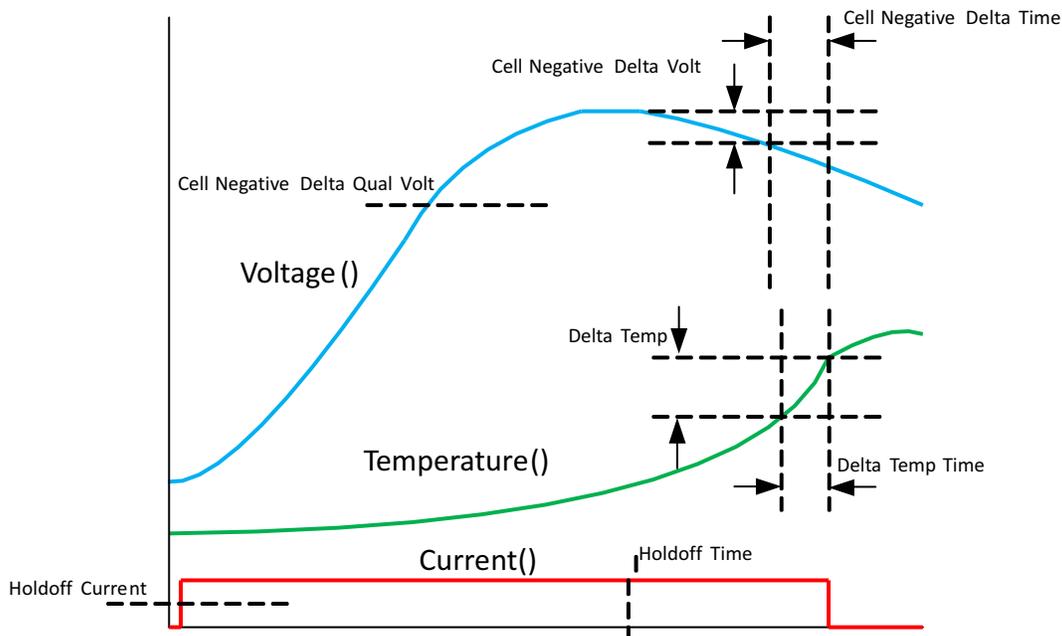


Figure 2-2. NiXX Termination

### 2.9.44 Fast Charge Current

The register sets the fast charging current for the battery pack. This information can be read by the MCU using commands 0x32 and 0x33, *ChargingCurrent()*. This information may be used to communicate the information to a battery charger. This value is set based on battery capacity of the pack and recommended maximum charging current by the cell manufacturers.

### 2.9.45 Charging Voltage

The bq34210-Q1 device sets the maximum cell charging voltage for the pack. This information can be read by the MCU using commands 0x30 and 0x31, *ChargingVoltage()*. This information may be used to communicate the information to a battery charger. This value is set based on battery capacity of the pack and recommended maximum charging voltage by the cell manufacturers.

### 2.9.46 Taper Current

During primary charge termination detection, one of the three requirements is that the accumulated change in capacity > 0.25 mAh per *Current Taper Window* for the bq34210-Q1 device to start trying to qualify a termination. It must be above this *Minimum Taper Capacity* before bq34210-Q1 starts trying to detect a primary charge termination.

The following conditions qualify for primary charge termination:

1. During two consecutive periods of **Current Taper Window**, the *Current()* is < **Taper Current**.
2. During the same periods, the accumulated change in capacity > 0.25 mAh per **Current Taper Window**.
3. *Voltage()* > **Charging Voltage – Taper Voltage**.

**Normal Setting:** If the value selected is too high, then it can cause no termination or late termination detection. An example value is 0.25 mAh or C/10 to C/20, based on battery cell characteristics and charger specification. Also, two current taper qualifications are required to prevent false current taper. False primary termination could occur with the pulse charging method and with random starting and resumption of the charge current, a condition that is important at the beginning or end of the qualification period.

### 2.9.47 Taper Voltage

During primary charge termination detection, one of the three requirements is that **Voltage** must be above (**Charging Voltage – Taper Voltage**) for the bq34210-Q1 device to start trying to qualify a termination. It must be above this voltage before bq34210-Q1 starts trying to detect a primary charge termination.

**Normal Setting:** This value depends on charger characteristics. It must be set so that ripple voltage, noise, and charger tolerances are taken into account. A high value selected can cause early termination. If the value selected is too low, then it can cause no termination or late termination detection. An example value is 100 mV (see [Taper Current](#)).

### 2.9.48 Sleep Current

The device is allowed to go into SLEEP mode if the charge or discharge current is below **Sleep Current**. SLEEP mode can be enabled with the **Operation Config A [SLEEP]** bit. If the absolute value of *Current()* is above **Sleep Current**, the bq34210-Q1 device will return to NORMAL mode.

### 2.9.49 Bus Low Time

The device is allowed to go into SLEEP mode if it is enabled with the **Operation Config A [SLEEP]** bit if the I<sup>2</sup>C lines are low for a period greater than **Bus Low Time**.

### 2.9.50 Offset Calibration Inhibit Temperature Low

The bq34210-Q1 device does not perform auto-calibration on entry to SLEEP mode if *Temperature()* is below **Cal Inhibit Temp Low**. The default is 5°C.

### 2.9.51 Offset Calibration Inhibit Temperature High

The bq34210-Q1 device does not perform auto-calibration on entry to SLEEP mode if *Temperature()* is above **Cal Inhibit Temp High**. The default value is 45°C.

### 2.9.52 Sleep Voltage Time

During SLEEP mode, temperature and voltage measurements will be taken in **Sleep Voltage Time** intervals. The default setting is 20 s.

### 2.9.53 Sleep Current Time

During SLEEP mode, current will be measured in **Sleep Current Time** intervals. The default value is 20 s.

### 2.9.54 Dsg Current Threshold (Discharge Detection Threshold)

The bq34210-Q1 device enters DISCHARGE mode from RELAXATION mode or CHARGE mode if  $Current() < (-) \text{ Dsg Current Threshold}$ .

### 2.9.55 Chg Current Threshold (Charge Detection Threshold)

The bq34210-Q1 device enters CHARGE mode from RELAXATION mode or DISCHARGE mode if  $Current() > \text{Chg Current Threshold}$ .

### 2.9.56 Quit Current

The bq34210-Q1 device enters RELAXATION mode from CHARGE mode if  $Current()$  goes below **Quit Current** for **Charge Relax Time**. The device enters RELAXATION mode from DISCHARGE mode if  $Current()$  goes above  $(-)\text{Quit Current}$  for **Discharge Relax Time**.

### 2.9.57 Discharge Relax Time

The bq34210-Q1 device enters RELAXATION mode from DISCHARGE mode if  $Current()$  goes above  $(-)\text{Quit Current}$  for at least **Discharge Relax Time**.

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**NOTE:** To optimize power consumption, it is recommended to set **Discharge Relax Time** to 0 so the device enters RELAXATION mode immediately when  $Current()$  rises above  $(-)\text{Quit Current}$ .

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### 2.9.58 Charge Relax Time

The bq34210-Q1 device enters RELAXATION mode from CHARGE mode if  $Current()$  goes below **Quit Current** for at least **Charge Relax Time**.

### 2.9.59 Quit Relax Time

The *Quit Relax Time* is the delay time to exit RELAXATION. If current is greater than **Chg Current Threshold** or less than **Dsg Current Threshold** and this condition is maintained for *Quit Relax Time*, then exiting RELAXATION is permitted. This is useful in applications with low duty cycle dynamic loads.

### 2.9.60 OT Charge

The bq34210-Q1 device sets the *[OTC]* flag in *BatteryStatus()* if the pack *Temperature()* is equal to or higher than the **Over Temp Chg** threshold.

#### 2.9.60.1 OT Charge Time

If the *[OTC]* condition exists for a time that exceeds the **OT Chg Time** period, the bq34210-Q1 device goes into an overtemperature charge condition. This function is disabled if **OT Chg Time** is set to 0.

In an overtemperature charge condition, the *ChargingVoltage()* and *ChargingCurrent()* are set to 0, and the *[OTC]* bit is set in the *BatteryStatus()* register.

### 2.9.61 OT Chg Recovery

The device recovers from an overtemperature charge condition if the *Temperature()* is equal to or lower than the **OT Chg Recovery** level. On recovery, the CHG FET returns to its normal operating state, the *ChargingCurrent()* and *ChargingVoltage()* are set to their appropriate values per the charging algorithm, and the [OTC] flag in *BatteryStatus()* is reset.

### 2.9.62 OT Discharge

The bq34210-Q1 device sets the [OTD] flag in *BatteryStatus()* if the pack *Temperature()* is equal to or higher than the **Over Temp Dsg** threshold.

#### 2.9.62.1 OT Discharge Time

If the [OTD] condition exists for a time period that exceeds the **OT Dsg Time**, the bq34210-Q1 device goes into an overtemperature discharge condition. This function is disabled if **OT Dsg Time** is set to 0.

In an overtemperature discharge condition the *ChargingCurrent()* is set to 0 and the [OTD] bit is set in the *BatteryStatus()* register.

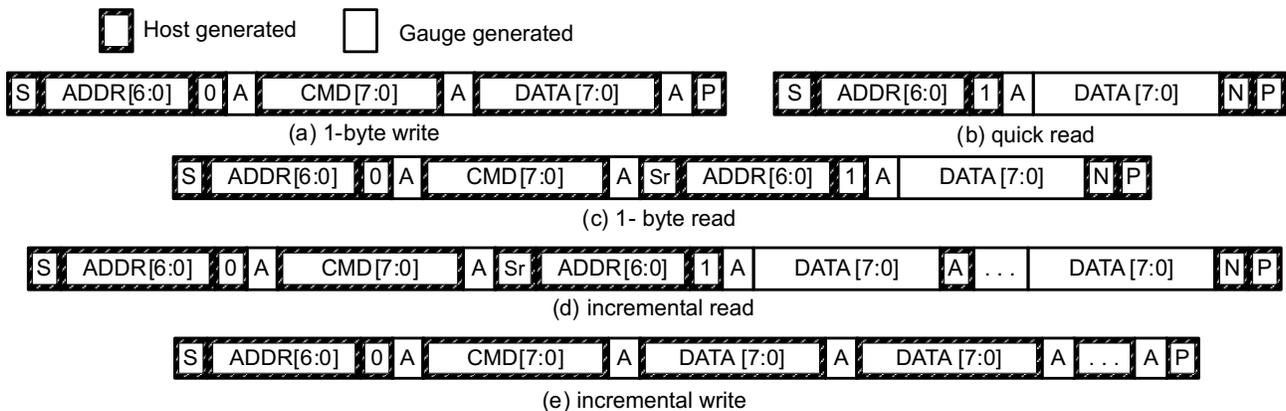
### 2.9.63 OT Dsg Recovery

The bq34210-Q1 device recovers from an overtemperature discharge condition if the *Temperature()* is equal to or lower than the **OT Dsg Recovery** level. On recovery, the DSG FET returns to its normal operating state, the *ChargingCurrent()* and *ChargingVoltage()* are set to their appropriate values per the charging algorithm, and the [OTD] flag in *BatteryStatus()* is reset.

## Communications

### 3.1 I<sup>2</sup>C Interface

The slave-only bq34210-Q1 fuel gauge supports the standard I<sup>2</sup>C read, incremental read, quick read, one byte write, and incremental write functions. The 7-bit device address (ADDR) is the most significant 7 bits of the hex address and is fixed as 1010101. The first 8-bits of the I<sup>2</sup>C protocol is, therefore, 0xAA or 0xAB for write or read, respectively.

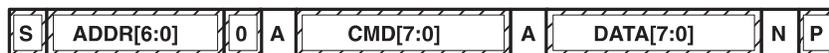


(S = Start, Sr = Repeated Start, A = Acknowledge, N = No Acknowledge, and P = Stop).

The “quick read” returns data at the address indicated by the address pointer. The address pointer, a register internal to the I<sup>2</sup>C communication engine, increments whenever data is acknowledged by the fuel gauge or the I<sup>2</sup>C master. “Quick writes” function in the same manner and are a convenient means of sending multiple bytes to consecutive command locations (such as two-byte commands that require two bytes of data).

The following command sequences are not supported:

Attempt to write a read-only address (NACK after data sent by master):



Attempt to read an address above 0x6B (NACK command):

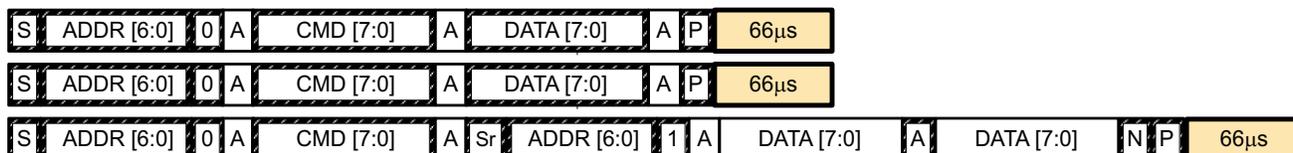


### 3.2 I<sup>2</sup>C Time Out

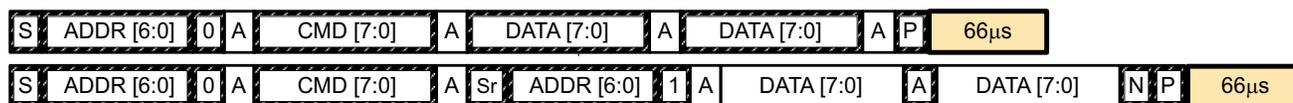
The I<sup>2</sup>C engine releases SDA and SCL if the I<sup>2</sup>C bus is held low for **Bus Low Time**. If the fuel gauge was holding the lines, releasing them frees them for the master to drive the lines. If an external condition is holding either of the lines low, the I<sup>2</sup>C engine enters the low-power SLEEP mode.

### 3.3 I<sup>2</sup>C Command Waiting Time

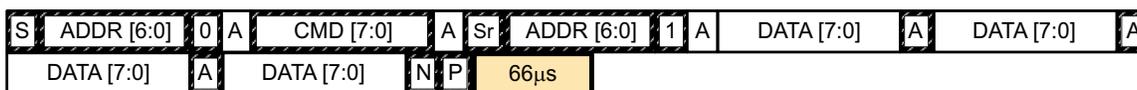
To ensure proper operation at 400 kHz, a  $t_{(BUF)} \geq 66 \mu\text{s}$ , bus-free waiting time must be inserted between all packets addressed to the fuel gauge. In addition, if the SCL clock frequency ( $f_{SCL}$ ) is  $> 100 \text{ kHz}$ , use individual 1-byte write commands for proper data flow control. The following diagram shows the standard waiting time required between issuing the control subcommand and reading the status result. A *DF\_CHECKSUM()* subcommand requires 100-ms minimum prior to reading the result. For read-write standard commands, a minimum of 2 s is required to get the result updated. For read-only standard commands, there is no waiting time required, but the host should not issue all standard commands more than two times per second; otherwise, the fuel gauge could result in a reset issue due to the expiration of the watchdog timer.



Waiting time inserted between two 1-byte write packets for a subcommand and reading results  
(required for  $100 \text{ kHz} < f_{SCL} \leq 400 \text{ kHz}$ )



Waiting time inserted between incremental 2-byte write packet for a subcommand and reading results  
(acceptable for  $f_{SCL} \leq 100 \text{ kHz}$ )



Waiting time inserted after incremental read

### 3.4 I<sup>2</sup>C Clock Stretching

A clock stretch can occur during all modes of fuel gauge operation. In SLEEP mode, a short  $\leq 100\text{-}\mu\text{s}$  clock stretch occurs on all I<sup>2</sup>C traffic as the device must wake-up to process the packet. In the other modes (INITIALIZATION, NORMAL), a  $\leq 4\text{-ms}$  clock stretching period may occur within packets addressed for the fuel gauge as the I<sup>2</sup>C interface performs normal data flow control.

## Data Commands

The bq34210-Q1 fuel gauge uses a series of data commands to enable system reading and writing of battery information. Each data command has an associated command-code pair, as shown in [Table 4-1](#). Because each command consists of two bytes of data, two consecutive I<sup>2</sup>C transmissions must be run to initiate the command function and to read or write the corresponding data. Additional options for transferring data are described in [Table 4-2](#), *Control()* commands. Read and write permissions depend on the active access mode, SEALED or UNSEALED. For details, see [Device Access Modes](#). For I<sup>2</sup>C details, see [Communications](#).

**Table 4-1. Data Commands**

NAME		COMMAND CODE	UNIT	SEALED ACCESS
<i>Control()/CONTROL_STATUS()</i>	CNTL	0x00 and 0x01	NA	RW
<i>Temperature()</i>	TEMP	0x06 and 0x07	0.1°K	RW
<i>Voltage()</i>	VOLT	0x08 and 0x09	mV	R
<i>BatteryStatus()</i>		0x0A and 0x0B	NA	R
<i>Current()</i>	<i>Current()</i>	0x0C and 0x0D	mAh	R
<i>RemainingCapacity()</i>	RC	0x10 and 0x11	mAh	R
<i>FullChargeCapacity()</i>	FCC	0x12 and 0x13	mAh	R
<i>AverageCurrent()</i>	AI	0x14 and 0x15	mA	R
<i>AverageTimeToEmpty()</i>	TTE	0x16 and 0x17	Minutes	R
<i>AverageTimeToFull()</i>	TTF	0x18 and 0x19	Minutes	R
<i>AccumulatedCharge()</i>		0x1A and 0x1B	mAh	R
<i>AccumulatedChargeTime()</i>		0x1C and 0x1D	5 Minutes	R
<i>LastAccumulatedCharge()</i>		0x1E and 0x1F	mA	R
<i>LastAccumulatedChargeTime()</i>		0x20 and 0x21	min	R
<i>AveragePower()</i>	AP	0x24 and 0x25	mW	R
<i>InternalTemperature()</i>	INTTEMP	0x28 and 0x29	0.1°K	R
<i>CycleCount()</i>	CC	0x2A and 0x2B	num	R
<i>RelativeStateOfCharge()</i>	SOC	0x2C and 0x2D	%	R
<i>StateOfHealth()</i>	SOH	0x2E and 0x2F	%/num	R
<i>ChargingVoltage()</i>	CV	0x30 and 0x31	mV	R
<i>ChargingCurrent()</i>	CC	0x32 and 0x33	mA	R
<i>BLTDischargeSet()</i>		0x34 and 0x35	mAh	RW
<i>BLTChargeSet()</i>		0x36 and 0x37	mAh	RW
<i>OperationStatus()</i>		0x3A and 0x3B	NA	R
<i>DesignCapacity()</i>	Design Cap	0x3C and 0x3D	mAh	R
<i>ManufacturerAccessControl()</i>	MAC	0x3E and 0x3F		RW
<i>MACData()</i>		0x40 through 0x5F		RW
<i>MACDataSum()</i>		0x60		RW
<i>MACDataLen()</i>		0x61		RW
<i>EOSLearnStatus()</i>		0x64 and 0x65		R
<i>EOSSafetyStatus()</i>		0x66 and 0x67		R
<i>EOSStatus()</i>		0x68		R

**Table 4-1. Data Commands (continued)**

NAME		COMMAND CODE	UNIT	SEALED ACCESS
<i>AnalogCount()</i>		0x79		R
<i>RawCurrent()</i>		0x7A and 0x7B	mA	R
<i>RawVoltage()</i>		0x7C and 0x7D	mV	R
<i>RawIntTemp()</i>		0x7E and 0x7F	0.1°K	R
<i>RawExtTemp()</i>		0x80 and 0x81	0.1°K	R

#### 4.1 **Control()/CONTROL\_STATUS(): 0x00 and 0x01**

Issuing a *Control()* Manufacturer Access Control (MAC) command requires a 2-byte subcommand. The subcommand specifies the particular MAC function desired. The *Control()* command enables the system to control specific features of the fuel gauge during normal operation and additional features when the device is in different access modes, as described in [Table 4-2](#). On this device, *Control()* commands may also be sent to *ManufacturerAccessControl()*. Any subcommand that has a data response will be read back on *MACData()*.

Reading the *Control()* registers will always report the *CONTROL\_STATUS()* data field except after the *DEVICE\_NUMBER()* and *FW\_VERSION()* subcommands. After these subcommands, *CONTROL\_STATUS()* will report the value 0xFFA5 one time before reverting to the normal data response. This is a flag to indicate that the data response was moved to *MACData()*. Writing a 0x0000 to *Control()* is no longer necessary to read the *CONTROL\_STATUS()*, although it is okay if it is done.

When executing commands that require data (such as data memory writes), the subcommand can be written to either *Control()* or *ManufacturerAccessControl()* registers; however, it is recommended to write using the *ManufacturerAccessControl()* registers, as this allows performing the full command in a single I<sup>2</sup>C transaction.

**Table 4-2. Control() MAC Subcommands**

CNTL/MAC FUNCTION	SUBCOMMAND CODE	SEALED ACCESS?	DESCRIPTION
CONTROL_STATUS	0x0000	Yes	Ignored by the gauge (in previous devices, would enable <i>CONTROL_STATUS()</i> read)
DEVICE_NUMBER	0x0001	Yes	Reports the value from Data Memory device type (The bq34210-Q1 reports 0x0210.)
FW_VERSION	0x0002	Yes	Reports the firmware version
BOARD_OFFSET	0x0009	Yes	Invokes the board offset correction
CC_OFFSET	0x000A	Yes	Invokes the CC offset correction
CC_OFFSET_SAVE	0x000B	Yes	Saves the results of the offset calibration process
SET_PROFILE_1	0x0015	Yes	Selects CEDV Profile 1
SET_PROFILE_2	0x0016	Yes	Selects CEDV Profile 2
SHUTDOWN_ENABLE	0x001B	No	Enables the SHUTDOWN command
SHUTDOWN	0x001C	No	Puts the device into SHUTDOWN mode
ACCUM_DSG_EN	0x001E	No	This MAC subcommand toggles the value of <i>ManufacturingStatus()[ACDSG_EN]</i> .
ACCUM_CHG_EN	0x001F	No	This MAC subcommand toggles the value of <i>ManufacturingStatus()[ACCHG_EN]</i> .
IGNORE_SELFDSG_EN	0x0020	No	This MAC subcommand toggles the value of <i>ManufacturingStatus()[IGNORE_SD_EN]</i> .
EOS_EN	0x0021	No	This MAC subcommand toggles the value of <i>ManufacturingStatus()[EOS_EN]</i> .
PIN_CONTROL_EN	0x0022	No	Toggles control of the ALERT pin.
CAL_TOGGLE	0x002D	No	Toggles <i>OperationStatus()[CALMD]</i>
SEAL	0x0030	No	Places the fuel gauge in SEALED access mode

**Table 4-2. Control() MAC Subcommands (continued)**

CNTL/MAC FUNCTION	SUBCOMMAND CODE	SEALED ACCESS?	DESCRIPTION
EOS_START_LEARN	0x0039	Yes	Initiates an EOS learning phase
EOS_ABORT_LEARN	0x003A	Yes	Aborts an EOS learning phase
EOS_RCELL_RRATE_LEARN	0x003B	No	Initiates the Initial <b>Rcell</b> and Initial <b>RRate</b> learning procedures
EOS_WARN_CLEAR	0x003C	Yes	Clears the EOS Warning flags
EOS_INITIAL_RCELL	0x003E	Yes	Used to read and write the EOS <b>Rcell</b> value
EOS_INITIAL_RRATE	0x003F	Yes	Used to read and write the EOS <b>RRate</b> value
RESET	0x0041	No	Resets the device (The should only be sent in CFG UPDATE mode.)
ACCUM_RESET	0x004B	Yes	Resets the accumulated charge registers
GAUGING_STATUS	0x0056	Yes	This MAC subcommand returns the information in the CEDV gauging status register.
ALERT_SET	0x0068	Yes	Forces ALERT pin to be set (when enabled)
ALERT_RESET	0x0069	Yes	Forces ALERT pin to be reset (when enabled)
EDV_THRESHOLD	0x0073	Yes	This MAC subcommand returns the value of the EDV Threshold.
EXIT_CAL	0x0080	No	Instructs the fuel gauge to exit CALIBRATION mode
ENTER_CAL	0x0081	No	Instructs the fuel gauge to enter CALIBRATION mode
ENTER_CFG_UPDATE	0x0090	Yes	Enter CONFIG UPDATE mode
EXIT_CFG_UPDATE_REINIT	0x0091	Yes	Exit CONFIG UPDATE mode and reinitialize
EXIT_CFG_UPDATE	0x0092	Yes	Exit CONFIG UPDATE mode without reinitialize

An example using the *DEVICE\_NUMBER()* subcommand:

- Write the data bytes 0x01 0x00 to the device address 0xAA starting at command 0x00.
- Then read the response using an incremental read. To the device address 0xAB, starting at command 0x3E, read four bytes. The result would be 0x01 0x00 0x10 0x02 with the first two bytes reflecting the subcommand, and the second two bytes representing **Device Type** in little endian order.

#### 4.1.1 CONTROL\_STATUS: 0x0000

A read on this command returns the 16-bit *CONTROL\_STATUS()* data. The status word includes the following information:

**Table 4-3. CONTROL\_STATUS Bit Definitions**

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
<b>High Byte</b>	RSVD	RSVD	RSVD	RSVD	RSVD	RSVD	RSVD	RSVD
<b>Low Byte</b>	SHUTDOWN_EN	RSVD	CCA	BCA	RSVD	RSVD	RSVD	BATT_ID0

##### High Byte

RSVD = Reserved

##### Low Byte

SHUTDOWN\_EN = Enables low power SHUTDOWN mode when subcommand **SHUTDOWN** is used.

RSVD = Reserved

CCA = Status bit indicating the fuel gauge Coulomb Counter Calibration routine is active. The CCA routine takes place approximately one minute after the initialization and periodically as gauging conditions change. Active when set. (See [Autocalibration](#).)

BCA = Status bit indicating the fuel gauge board calibration routine is active. Active when set.

RSVD = Reserved

RSVD = Reserved

RSVD = Reserved

BATT\_ID0 = Battery Identification Setting. Battery identification settings for different chemistries, used to select one of two chemistry IDs.  
 0 = CEDV Profile 1  
 1 = CEDV Profile 2  
 One of these CEDV profiles is loaded at initial power. The host can modify the memory parameters to fit the particular requirement of the system battery.

#### **4.1.2 DEVICE\_NUMBER: 0x0001**

This command instructs the fuel gauge to return **Device Type** 0x0210 to *MACData()*.

#### **4.1.3 FW\_VERSION: 0x0002**

This command instructs the fuel gauge to return the firmware revision on *MACData()* in the following format:

ddDDvvVVbbBBTTzzZZRREE, where

ddDD: Device Number

vvVV: Version

bbBB: Build number

ttTT: Firmware type.

#### **4.1.4 BOARD\_OFFSET: 0x0009**

This command instructs the fuel gauge to measure and store the board offset value.

#### **4.1.5 CC\_OFFSET: 0x000A**

This command instructs the fuel gauge to measure the internal CC offset value.

#### **4.1.6 CC\_OFFSET\_SAVE: 0x000B**

This command instructs the fuel gauge to store the internal CC offset value.

#### **4.1.7 SET\_PROFILE\_1: 0x0015**

This command selects CEDV Profile 1.

#### **4.1.8 SET\_PROFILE\_2: 0x0016**

This command selects CEDV Profile 2.

#### **4.1.9 SHUTDOWN\_ENABLE: 0x001B**

This command enables entry into SHUTDOWN mode with the SHUTDOWN command.

#### **4.1.10 SHUTDOWN: 0x001C**

This command puts the device into low power SHUTDOWN mode. Exit is done with a power cycle or through the ALERT pin.

#### **4.1.11 ACCUM\_DSG\_EN: 0x001E**

This MAC subcommand toggles the value of *ManufacturingStatus()[ACDSG\_EN]*.

#### **4.1.12 ACCUM\_CHG\_EN: 0x001F**

This MAC subcommand toggles the value of *ManufacturingStatus()[ACCHG\_EN]*.

#### 4.1.13 IGNORE\_SELFDSG\_EN: 0x0020

This MAC subcommand toggles the value of *ManufacturingStatus()*[*IGNORE\_SD\_EN*].

#### 4.1.14 PIN\_CONTROL\_EN: 0x0022

This command toggles control of the ALERT pin via the **ALERT\_SET** and **ALERT\_RESET** commands. It is indicated by *ManufacturingStatus*[*PCTL\_EN*]. Care must be taken when using this function when a true Alert might occur. Use may cause the system to miss the Alert.

#### 4.1.15 CAL\_TOGGLE: 0x002D

Toggles the *OperationStatus()*[*CALMD*] flag

#### 4.1.16 SEAL: 0x0030

This instructs the fuel gauge to transition from the UNSEALED state to the SEALED state. The fuel gauge must always be set to the SEALED state for use in end-equipment.

Sending the SEAL command will set **Operation Config A** [*DEFAULTSEAL*], which will cause the gauge to automatically reseal unless the **DEFAULTSEAL** bit is cleared.

#### 4.1.17 EOS\_START\_LEARN: 0x0039

This MAC subcommand instructs the bq34210-Q1 device to begin a learning phase.

#### 4.1.18 EOS\_ABORT\_LEARN: 0x003A

This MAC subcommand instructs the bq34210-Q1 device to stop a learning phase.

#### 4.1.19 EOS\_RCELL\_RRATE\_LEARN: 0x003B

This MAC subcommand instructs the bq34210-Q1 device to initiate an **Initial Rcell** and an **Initial RRate** measurement.

#### 4.1.20 EOS\_WARN\_CLEAR: 0x003C

This MAC subcommand instructs the bq34210-Q1 device to clear the EOS warning bits (this includes [*DRDWARN*], [*RSDWARN*], and [*RSDLWARN*]).

#### 4.1.21 EOS\_INITIAL\_RCELL: 0x003E

This MAC subcommand is used to read the stored **Initial Rcell** measurement or to overwrite the value with a previously measured value.

#### 4.1.22 EOS\_INITIAL\_RRATE: 0x003F

This MAC subcommand is used to read the stored **Initial RRate** measurement or to overwrite the value with a previously measured value.

#### 4.1.23 RESET: 0x0041

This instructs the fuel gauge to perform a full reset.

---

**NOTE:** This subcommand is available only when the fuel gauge is UNSEALED, and should be used *only* while in CONFIG UPDATE mode.

---

#### 4.1.24 ACCUM\_RESET: 0x004B

This command resets the accumulated charge registers.

#### 4.1.25 GAUGING\_STATUS: 0x0056

Returns the 16-bit internal gauging status register. The most often checked flags from this register are copied to the *OperationStatus()* direct read register for easier access.

**Table 4-4. Gauging Status Bit Definitions**

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
<b>High Byte</b>	VDQ	EDV2	EDV1	RSVD	RSVD	FCCX	RSVD	REST
<b>Low Byte</b>	CF	DSG	EDV	RSVD	TC	TD	FC	FD

##### High Byte

VDQ = Indicates if the current discharge cycle is NOT qualified or qualified for an FCC updated. Discharge cycle valid for FCC update is set.

EDV2 = Indicates if measured cell voltage is above or below EDV2 threshold. Below = true when set.

EDV1 = Indicates if measured cell voltage is above or below EDV1 threshold. Below = true when set.

RSVD = Reserved

RSVD = Reserved

FCCX = Control for fcc1hz clock going into CC.  
0 = fcc1hz = 1 Hz  
1 = fcc1hz = 16 Hz

RSVD = Reserved

REST = Indicates if the device is in RELAXATION mode.  
0 = The device has not reached relaxation.  
1 = The device has reached relaxation.

##### Low Byte

CF = Indicates if battery conditioning is needed.

DSG = Set when in DISCHARGE or RELAXATION modes. Clear when in CHARGE mode.

EDV = Indicates if measured cell voltage is above or below EDV0 threshold. Below = true when set.

RSVD = Reserved

TC = Terminate Charge. Controlled by settings in **SOC Flag Config A**. (This flag is identical to *BatteryStatus() [TCA]*.)

TD = Terminate Discharge. Controlled by settings in **SOC Flag Config A**. (This flag is identical to *BatteryStatus() [TDA]*.)

FC = Full Charge. Controlled by settings in **SOC Flag Config A** and **SOC Flag Config B**. (This flag is identical to *BatteryStatus() [FC]*.)

FD = Full Discharge. Controlled by settings in **SOC Flag Config B**. (This flag is identical to *BatteryStatus() [FD]*.)

#### 4.1.26 ManufacturingStatus(): 0x57

This function enables certain functions.

**Table 4-5. Manufacturing Status Bit Definitions**

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
<b>High Byte</b>	CAL_EN	RSVD	RSVD	RSVD	RSVD	RSVD	RSVD	RSVD
<b>Low Byte</b>	RSVD	RSVD	RSVD	PCTL_EN	EOS_EN	IGNORE_SD_EN	ACCHG_EN	ACDSG_EN

##### High Byte

CAL\_EN = Set and cleared by **CAL\_TOGGLE**, it enables calibration commands.

##### Low Byte

PCTL\_EN = Set and cleared by **PIN\_CONTROL\_EN**, it indicates if ALERT can be controlled via **ALERT\_SET** and **ALERT\_RESET** commands (1 = yes).

EOS\_EN = When set, the EOS Determination function is enabled.

IGNORE\_SD\_EN = Enables user to ignore cell self-discharge

ACCHG\_EN = Enables accumulated charge integration in charge direction

ACDSG\_EN = Enables accumulated charge integration in discharge direction

#### 4.1.27 ALERT\_SET: 0x0068

This command forces the ALERT pin to be set, no matter the conditions. The **PIN\_CONTROL\_EN** command must be run to enable this feature.

#### 4.1.28 ALERT\_RESET: 0x0069

This command forces a reset on the ALERT pin. The **PIN\_CONTROL\_EN** command must be run to enable this feature.

#### 4.1.29 EDV\_Threshold: 0x0073

This MAC subcommand returns the values of the EDV Threshold.

#### 4.1.30 EXIT\_CAL: 0x0080

This instructs the fuel gauge to exit CALIBRATION mode.

#### 4.1.31 ENTER\_CAL: 0x0081

This instructs the fuel gauge to enter CALIBRATION mode and reset *AnalogCount()* to 0 if *OperationStatus()[CALMD]* is set. *[CALMD]* is controlled by the *CAL\_MODE()* command. Voltage must be above 2.9 V for accurate calibration.

#### 4.1.32 ENTER\_CFG\_UPDATE: 0x0090

Instructs the fuel gauge to set the *OperationStatus()[DFGUPDATE]* bit to 1 and enter CONFIG UPDATE mode. This command is only available when the fuel gauge is UNSEALED.

---

**NOTE:** To read the flag, the host must wait at least 2 seconds.

---

#### 4.1.33 EXIT\_CFG\_UPDATE\_REINIT: 0x0091

This command instructs the fuel gauge to exit CONFIG UPDATE mode and the gauge is reinitialized.

#### 4.1.34 EXIT\_CFG\_UPDATE: 0x0092

This command instructs the fuel gauge to exit CONFIG UPDATE mode and the gauge is not reinitialized.

### 4.2 Temperature(): 0x06 and 0x07

This read- and write-word function returns an unsigned integer value of the temperature in units of 0.1°K measured by the fuel gauge. See [Table 4-6, Temperature Measurement Options](#), and [Temperature Measurement](#).

**Table 4-6. Temperature Measurement Options**

Operation Config A [TEMPS]	<i>Temperature()</i> Read Command	<i>Temperature()</i> Write Command
0	Returns internal temperature as read from an internal sensor. This data is also available using the <i>InternalTemperature()</i> function.	The data is ignored.
1	Returns external temperature read from an external thermistor.	
X	Returns the <i>Temperature()</i> value previously written.	Sets the <i>Temperature()</i> to be used for gauging calculations.

### 4.3 Voltage(): 0x08 and 0x09

This read-word function returns an unsigned integer value of the measured cell-pack voltage in mV with a range of 0 to 6000 mV.

### 4.4 BatteryStatus(): 0x0A and 0x0B

This read-word function returns the contents of the gas gauge status register, depicting the current battery status.

**Table 4-7. Battery Status Bit Definitions**

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
<b>High Byte</b>	RSVD	SOCLOW	UTC	UTD	OTC	OTD	BATHIGH	BATLOW
<b>Low Byte</b>	SLEEP	CHGINH	FD	FC	TCA	TDA	CHG	DSG

#### High Byte

- RSVD = Reserved
- SOCLOW = State-of-charge
- UTC = Undertemperature Charge
- UTD = Undertemperature Discharge
- OTC = Overtemperature in charge condition is detected (**Alert\_1 [OTC]** bit must be set).
- OTD = Overtemperature in discharge condition is detected. True when set (**Alert\_1 [OTD]** bit = 1).
- BATHIGH = Battery voltage above high threshold
- BATLOW = Battery voltage below low threshold

#### Low Byte

- SLEEP = The device is operating in SLEEP mode when set. This will clear temporarily during AD measurements in SLEEP mode.
- CHGINH = Charge inhibit: If set, indicates that charging should not begin because *Temperature()* is outside the range [**Charge Inhibit Temp Low, Charge Inhibit Temp High**]. True when set.
- FD = Full discharge is detected. This flag is set and cleared based on the selected **SOC Flag Config B** options.
- FC = Full charged is detected. This flag is set and cleared based on the selected **SOC Flag Config A** and **SOC Flag Config B** options.
- TCA = Terminate Charge Alarm. This flag is set and cleared based on the selected **SOC Flag Config A** options.
- TDA = Terminate Discharge Alarm. This flag is set and cleared based on the selected **SOC Flag Config A** options.
- CHG = The device has detected charge current when set.
- DSG = The device is in DISCHARGE mode when set; CHARGE or RELAXATION mode when clear.

### 4.5 Current(): 0x0C and 0x0D

This read-only function returns a signed integer value that is the instantaneous current flow through the sense resistor. It is updated every second. Units are mA.

### 4.6 RemainingCapacity(): 0x10 and 0x11

This read-only command pair returns the battery remaining capacity. When CEDV **Smoothing Config [SMEN]** is set, this will be the result of the smoothing engine. Otherwise, the unfiltered remaining capacity is returned.

### 4.7 FullChargeCapacity(): 0x12 and 0x13

This read-only command pair returns the compensated capacity of a fully charged battery. Units are mAh. *FullChargeCapacity()* is updated at regular intervals, as specified by the CEDV algorithm.

#### 4.8 AverageCurrent(): 0x14 and 0x15

This read-word function returns a signed integer value that approximates a one-minute rolling average of the current being supplied (or accepted) through the battery terminals in mA with a range of –32,768 to 32,767.

*AverageCurrent()* is calculated by a rolling IIR filtered average of *Current()* function data with a period of 14.5 s. During the time after a reset or when switching between charge and discharge currents and before 14.5 s has elapsed, the reported *AverageCurrent()* = *Current()* function value.

**Table 4-8. AverageCurrent()**

Name	Access			Protocol	Type	Min	Max	Unit
	SE	US	FA					
AverageCurrent	R	R	R	Word	I2	-32768	32769	mA

The data value **Filter** determines the time constant of the filter operation used in the calculation of *AverageCurrent()* as follows:

$AverageCurrent() = a \times AverageCurrent() \text{ old} + (1-a) \times Current()$  with:

$a = Filter/256$ ; time constant =  $(1 \text{ s}) / \ln(1/a)$  (default = 14.5 s)

#### 4.9 AverageTimeToEmpty(): 0x16 and 0x17

This read-only function returns an unsigned integer value of the predicted remaining battery life at the present rate of discharge, in minutes. A value of 65,535 indicates battery is not being discharged.

**Table 4-9. AverageTimeToEmpty()**

Name	Access			Protocol	Type	Min	Max	Unit
	SE	US	FA					
AverageTimeToEmpty	R	R	R	Word	U2	0	65535	min

#### 4.10 AverageTimeToFull(): 0x18 and 0x19

This read-only function returns an unsigned integer value of the predicted remaining time until battery reaches full charge, in minutes, based upon *AverageCurrent()*. The computation accounts for the taper current time extension for the linear TTF computation based on a fixed *AverageCurrent()* rate-of-charge accumulation. A value of 65,535 indicates the battery is not being charged.

**Table 4-10. AverageTimeToFull()**

Name	Access			Protocol	Type	Min	Max	Unit
	SE	US	FA					
AverageTimeToFull	R	R	R	Word	U2	0	65535	min

#### 4.11 AccumulatedCharge(): 0x1A and 0x1B

*AccumulatedCharge()* is covered in detail in [Accumulated Charge Measurement](#).

#### 4.12 AccumulatedChargeTime(): 0x1C and 0x1D

*AccumulatedChargeTime()* is covered in detail in [Accumulated Charge Measurement](#).

#### 4.13 LastAccumulatedCharge(): 0x1E and 0x1F

*LastAccumulatedCharge()* is covered in detail in [Accumulated Charge Measurement](#).

#### 4.14 LastAccumulatedChargeTime(): 0x20 and 0x21

*LastAccumulatedChargeTime()* is covered in detail in [Accumulated Charge Measurement](#).

#### 4.15 AveragePower(): 0x24 and 0x25

This read-only function returns a signed integer value of the average power during battery charging and discharging. It is negative during discharge and positive during charge. A value of 0 indicates that the battery is not being discharged. The value is reported in units of mW.

#### 4.16 InternalTemperature(): 0x28 and 0x29

This read-only function returns an unsigned integer value of the internal temperature sensor in units of 0.1°K measured by the fuel gauge. This function can be useful as an additional system-level temperature monitor if the main *Temperature()* function is configured for external or host-reported temperature.

#### 4.17 CycleCount(): 0x2A and 0x2B

This read-only function returns an unsigned integer value of the number of cycles that the active cell has experienced with a range of 0 to 65535. One cycle occurs when accumulated discharge  $\geq$  cycle threshold. The cycle threshold is calculated based on **CEDV Gauging Configuration [CCT]**:

1 = Cycle Count Percentage  $\times$  *FullChargeCapacity()*

0 = Cycle Count Percentage  $\times$  *DesignCapacity()*.

#### 4.18 RelativeStateOfCharge(): 0x2C and 0x2D

This read-only function returns an unsigned integer value of the predicted remaining battery capacity expressed as a percentage of *FullChargeCapacity()*, with a range of 0 to 100%. *RelativeStateOfCharge()* = *RemainingCapacity()*  $\div$  *FullChargeCapacity()* rounded up to the nearest whole percentage point.

#### 4.19 StateOfHealth(): 0x2E and 0x2F

The *StateOfHealth()* (SOH) read-only function returns an unsigned integer value, expressed as a percentage of the ratio of *FullChargeCapacity()* over the *DesignCapacity()*, with a range of 0 to 100%. *StateOfHealth()* = *FullChargeCapacity()*  $\div$  *DesignCapacity()* rounded up to the nearest whole percentage point.

#### 4.20 ChargingVoltage(): 0x30 and 0x31

This read-only function returns an unsigned integer value of the desired charging voltage of the battery. A value of 65,535 indicates that the battery is requesting the maximum voltage from the battery charger.

#### 4.21 ChargingCurrent(): 0x32 and 0x33

This read-only function returns an unsigned integer value of the desired charging current of the battery. A value of 65,535 indicates that the battery is requesting the maximum current from the battery charger.

#### 4.22 BLTDischargeSet(): 0x34 and 0x35

This read/write word command updates the BLT set threshold that triggers the BLT interrupt in discharge direction, and sets the *OperationStatus()*[BLTINT] bit.

#### 4.23 BLTChargeSet(): 0x36 and 0x37

The read/write word command updates the BLT set threshold that triggers the BLT interrupt in charge direction, and sets the *OperationStatus()*[BLTINT] bit.

#### 4.24 OperationStatus(): 0x3A and 0x3B

This read-word function returns the contents of the internal status register.

**Table 4-11. Operation Status Bit Definitions**

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
<b>High Byte</b>	RSVD	RSVD	RSVD	RSVD	INITCOMP	CFGUPDATE	RSVD	RSVD
<b>Low Byte</b>	BLT	SMTH	ACTHR	VDQ	EDV2	SEC1	SEC0	CALMD

##### High Byte

INITCOMP = Indicates if fuel gauge initialization is complete. This bit can only be set with battery presence. True when set.

CFGUPDATE = Gauge is in CONFIG UPDATE mode. Gauging is suspended.

##### Low Byte

BLT = Battery Level Threshold Flag

Setting and clearing this flag depends upon various conditions. See [Battery Level Threshold](#) for details.

SMTH = Indicates that *RemainingCapacity()* accumulation is currently scaled by the smoothing engine.

ACTHR = Accumulated Charge Threshold Flag

1 = The accumulated charge was detected passing a threshold.

0 = The accumulated charge was not detected passing a threshold.

VDQ = Indicates if the current discharge cycle is NOT qualified or qualified for an FCC updated. A discharge cycle valid for FCC update is set.

EDV2 = Indicates if measured cell voltage is above or below EDV2 threshold. Below = true when set.

SEC[1:0] = Defines Current Security Access

11 = Sealed Access

10 = Unsealed Access

01 = Full Access

00 = Unused

CALMD = Toggles with 0x2D command to enable/disable CALIBRATION mode

#### 4.25 DesignCapacity(): 0x3C and 0x3D

This read-only function returns the value stored in **Design Capacity mAh**. This is intended to be the theoretical or nominal capacity of a new pack, and is used for the calculation of *StateOfHealth()*.

#### 4.26 ManufacturerAccessControl(): 0x3E and 0x3F

This read-write word function returns the subcommand that is currently active for reads on *MACData()*.

Word writes to this function will set a subcommand. Commands that do not require data will run immediately (identical to writes to *Control()*).

#### 4.27 MACData(): 0x40 through 0x5F

This read-write block will return the result data for the currently active subcommand. It is recommended to start the read at *ManufacturerAccessControl()* to verify the active subcommand.

Writes to this block are used to provide data to a subcommand when required.

#### 4.28 MACDataSum(): 0x60

This read-write function returns the checksum of the current subcommand and data block.

Writes to this register provide the checksum necessary in order to run subcommands that require data.

The checksum is calculated as the complement of the sum of the *ManufacturerAccessControl()* and the *MACData()* bytes. *MACDataLen()* determines the number of bytes of *MACData()* that are included in the checksum.

#### 4.29 MACDataLen(): 0x61

This read-write function returns the number of bytes of *MACData()* that are part of the response and included in *MACDataSum()*.

Writes to this register provide the number of bytes in *MACData()* that should be processed as part of the subcommand.

Subcommands that require block data are not run until *MACDataSum()* and *MACDataLen()* are written together as a word.

#### 4.30 EOSLearnStatus(): 0x64 and 0x65

This command returns various flags providing information on the EOS Determination function.

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
LSB	LCTO	LFAULT	LABRT	LCMD	LPER	LRLX	LCHG	LDSG
MSB	LDONE	LRES	LRSTOR	LCTLEDGE	LUCD	LDPAM	LDPAT	LDPAI

RSVD = Reserved. Do not use.

LCTO = Learn Charge Time Out

This bit is set = 1 if the bq34210-Q1 device is in LEARN CHARGE mode and detects the charging time has exceeded **Learn Charge Time Limit**. This bit is reset to 0 when a new learning phase begins.

1 = A learn excessive charge time was detected.

0 = A learn excessive charge time was not detected.

LFAULT = Learn Fault Flag

This bit is set = 1 whenever a learning phase is terminated for any reason other than a valid termination, and also if any other fault (such as in *GaugingStatus()* or *BatteryStatus()*) occurred during the learning phase. The bit will be reset to 0 when a new learning phase begins.

1 = A learning phase was stopped.

0 = A learning phase was not stopped.

LABRT = Learn Abort on Command

This bit is set = 1 whenever a learning phase was stopped by the host. A bit that was set = 1 will be reset to 0 when a new learning phase begins.

1 = A requested learning phase was stopped.

0 = A requested learning phase was not stopped.

LCMD = Learn Command

This bit is set = 1 if learning is activated and a learning phase was started by a command. The bit will remain high until the learning phase is complete (including charging, learning, discharging, and related calculations).

1 = The device is in a command-initiated learning phase.

0 = The device is not in a command-initiated learning phase.

LPER = Learn Periodic Mode

This bit is set = 1 if learning is activated and the bq34210-Q1 device is in PERIODIC LEARN mode. This bit is only set while the device is in a learning phase.

1 = The device is in PERIODIC LEARN mode.

0 = The device is not in PERIODIC LEARN mode.

LRLX = Learn RELAXATION mode

This bit is set = 1 if learning is activated and the bq34210-Q1 device is in a RELAXATION mode during learning. This means the cell is waiting to detect a relaxed condition; it may not have achieved relaxation yet.

- 1 = The device is in RELAXATION mode during learning.
- 0 = The device is not in RELAXATION mode during learning.

**LCHG = Learn CHARGE mode**

This bit is set = 1 if the bq34210-Q1 device is in learn CHARGE mode. If the device is controlling a charger directly through a device pin, then the value of this signal will be reflected on the selected pin. If instead the host is controlling the charger, then this bit can be used to signal the host to initiate charging.

- 1 = A LEARN CHARGE mode is in progress.
- 0 = A LEARN CHARGE mode is not in progress.

**LDSG = Learn DISCHARGE mode**

This bit is set = 1 if the bq34210-Q1 device is in automatic END-OF-SERVICE DETERMINATION mode and the device intends to begin a Learn Discharge Phase. It is set = 0 when the device intends the Learn Discharge Phase to end. If the device is controlling the discharge directly using the LEN pin, then the LEN pin will reflect the value of LDSG. If instead the host is controlling the **Learn Discharge Current**, this bit will signal the host to enable the **Learn Discharge Current**.

- 1 = A Learn Discharge Phase was requested or is in progress.
- 0 = A Learn Discharge Phase is requested to stop or was stopped.

**LDONE = Learn Done**

This bit is set = 1 when a valid learning phase has completed.

- 1 = A valid learning phase was completed.
- 0 = A valid learning phase was not completed.

**LRES = Learned *Rcell***

This bit is set = 1 when the bq34210-Q1 device has completed the computation of a new **Rcell** value during the present learning phase. This bit is cleared when the learning phase is complete.

- 1 = A new value of **Rcell** was acquired.
- 0 = A new value of **Rcell** has not yet been acquired.

**LRSTOR = Learn Voltage Restore**

This bit is set = 1 if whenever the Learn Discharge Phase is complete and the voltage can be restored back to its original level. This bit is cleared when the learning phase is complete.

- 1 = A Learning Discharge Phase has completed, and the voltage can be restored.
- 0 = The device has completed the learning phase.

**LCTLEDGE = Learn Discharge Flag Edge Detected**

This bit is set = 1 if whenever LDSG changes state. This can be used by the host as an interrupt to recognize when a learning load should be activated and when it should be disabled. This bit clears when the register is read.

- 1 = A change in LDSG was detected (this is only applicable when LENCTL=0).
- 0 = A change in LDSG was not detected.

**LUCD = Learn Unexpected Current Detected**

This bit is set when the device is in LEARNING mode (but not in the Learn Discharge Phase), and a current is detected differently than what is expected. It is set if the device is attempting to charge or relax, and a discharge current in excess of **Discharge Detection Threshold** is detected. It is also set if the device is in a RELAXATION mode and a charging current in excess of **Charge Detection Threshold** is detected. This detection also terminates the learning phase, and this bit will remain set as a flag to the host as to why the learning phase was stopped. This bit will be reset to 0 when a new learning phase begins.

- 1 = An unexpected system-related current was detected during a learning charge or learning relax period.
- 0 = An unexpected system-related current was not detected.

**LDPAM = Learn Discharge Phase Abort on Timer**

This bit is set = 1 when a Learn Discharge Phase was requested by the host but was declined due to the time since the last Learn Discharge Phase was less than the interval specified in **Minimum Learn Time**. A bit that was set = 1 will be reset to 0 when **Minimum Learn Time** has passed.

1 = A requested Learn Discharge Phase was declined.

0 = A requested Learn Discharge Phase was not declined.

**LDPAT = Learn Discharge Phase Abort on Temperature**

This bit is set = 1 when a Learn Discharge Phase was initiated but was stopped due to **Temperature()** measured outside the range allowed by **Learn Min Temperature** and **Learn Max Temperature**. A bit that was set = 1 will be reset to 0 when a new Learn Discharge Phase begins.

1 = A Learn Discharge Phase was stopped.

0 = A Learn Discharge Phase was not stopped.

**LDPAI = Learn Discharge Phase Abort on Current**

This bit is set = 1 when a Learn Discharge Phase was initiated but was stopped due to **Current()** measured outside the range allowed by **Learn Discharge Current** and **Learn Discharge Current Boundary**. A bit that was set = 1 will be reset to 0 when a new Learn Discharge Phase begins.

1 = A Learn Discharge Phase was stopped.

0 = A Learn Discharge Phase was not stopped.

### 4.31 EOSSafetySatus(): 0x66 and 0x67

This command returns flags generated by the EOS Determination function.

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
LSB	RSVD	RSVD	RSVD	RSVD	RSVD	RSDL ALERT	RSDALERT	DRDALERT
MSB	RSVD	RSVD	RSVD	RSVD	RSVD	RSDLWARN	RSDWARN	DRDWARN

Legend = RSVD = Reserved. Do not use.

**RSDLALERT = Resistance Slope Decisioning Long-Term Alert**

This bit is set = 1 if the bq34210-Q1 EOS Determination function detects the condition described above to trigger the **[RSDLALERT]** signal. This signal is cleared when the register is read or if a new learning phase begins.

1 = An RSDLALERT was detected.

0 = An RSDLALERT was not detected.

**RSDALERT = Resistance Slope Decisioning Alert**

This bit is set = 1 if the bq34210-Q1 EOS Determination function detects the condition described above to trigger the **[RSDALERT]** signal. This signal is cleared when the register is read or if a new learning phase begins.

1 = An RSDALERT was detected.

0 = An RSDALERT was not detected.

**DRDALERT = Direct Resistance Decisioning Alert**

This bit is set = 1 if the bq34210-Q1 EOS Determination function detects the condition described above to trigger the **[DRDALERT]** signal. This signal is cleared when the register is read or if a new learning phase begins.

1 = A DRDALERT was detected.

0 = A DRDALERT was not detected.

**RSDLWARN = Resistance Slope Decisioning Long-Term Warning**

This bit is set = 1 if the bq34210-Q1 EOS Determination function detects the condition described above to trigger the *[RSDLWARN]* signal. This signal is NOT cleared when the register is read. It can only be cleared using the command *EOS\_WARNCLR()*.

- 1 = An RSDLWARN was detected.
- 0 = An RSDLWARN was not detected.

**RSDWARN = Resistance Slope Decisioning Warning**

This bit is set = 1 if the bq34210-Q1 EOS Determination function detects the condition described above to trigger the *[RSDWARN]* signal. This signal is NOT cleared when the register is read. It can only be cleared using the command *EOS\_WARNCLR()*.

- 1 = An RSDWARN was detected.
- 0 = An RSDWARN was not detected.

**DRDWARN = Direct Resistance Decisioning Warning**

This bit is set = 1 if the bq34210-Q1 EOS Determination function detects the condition described above to trigger the *[DRDWARN]* signal. This signal is NOT cleared when the register is read. It can only be cleared using the command *EOS\_WARNCLR()*.

- 1 = A DRDWARN was detected.
- 0 = A DRDWARN was not detected.

### 4.32 EOSStatus(): 0x68

This command returns additional flags that provide information related to the EOS Determination function.

	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
	SRRL	SRCL	RSVD	LTI	RSDLI	RCELLR	IRRCOMP	IRCOMP

Legend = RSVD = Reserved. Do not use.

**SRRL = Initial RRate Learning in Progress**

This bit is set = 1 if the bq34210-Q1 EOS Determination function begins the required learning phases to calculate a value of **Initial RRate**, generally after an *EOS\_RCELL\_RRATE\_LEARN()* command was issued. The bit will clear when the **Initial RRate** learning and computation is complete.

**SRCL = Initial Rcell Learning in Progress**

This bit is set = 1 if the bq34210-Q1 EOS Determination function begins the required learning phases to calculate a value of **Initial Rcell**, generally after an *EOS\_RCELL\_RRATE\_LEARN()* command was issued. The bit will clear when the **Initial Rcell** learning and computation is complete.

**LTI = Learn Timer Invalid**

This bit is set = 1 if the bq34210-Q1 EOS Determination function detects that the timer was interrupted since the most recent **Rcell** was calculated. In this case, the RSD algorithm must capture two new **Rcell** values separated in time to calculate a new value of **RRate** and evaluate this for corresponding alerts and warnings.

- 1 = A timer interruption was detected.
- 0 = A timer interruption was not detected.

**RSDLI = Resistance Slope Decisioning Long-Term Invalid**

This bit is set = 1 if the bq34210-Q1 EOS Determination function detects that the timer was interrupted since the **Initial RRate** was calculated. In this case, the RSDL algorithm will no longer trigger an alert or warning.

- 1 = A timer interruption was detected.
- 0 = A timer interruption was not detected.

**RCELLR = Rcell Reduction Alert**

This bit is set = 1 if the bq34210-Q1 EOS Determination function detects a value of Rcell that is more than 2% below the previous value of **Rcell**. This signal is cleared when the register is read or if a new learning phase begins.

1 = A reduction in **Rcell** was detected.

0 = A reduction in **Rcell** was not detected.

**IRRCOMP = Initial RRate Calculation Complete**

This bit is set = 1 if the bq34210-Q1 EOS Determination function has completed the required learning phases to calculate a value of **Initial RRate**. This bit is reset when a new **Initial RRate** calculation is triggered until the new calculation is complete. This bit can be written by the host through loading data flash if the host chooses to initialize the device with previously calculated **Initial RRate** data and not trigger a new **Initial RRate** calculation.

1 = **Initial RRate** was obtained.

0 = **Initial RRate** was not obtained.

**IRCOMP = Initial Rcell Calculation Complete**

This bit is set = 1 if the bq34210-Q1 EOS Determination function has completed the required learning phases to calculate a value of **Initial Rcell**. This bit is reset when a new **Initial Rcell** calculation is triggered until the new calculation is complete. This bit can be written by the host through loading data flash if the host chooses to initialize the device with previously calculated **Initial Rcell** data and not trigger a new **Initial Rcell** calculation.

1 = **Initial Rcell** was obtained.

0 = **Initial Rcell** was not obtained.

### 4.33 AnalogCount(): 0x79

This read-only function returns the analog counter. The value is incremented every time the analog data for calibration was updated.

### 4.34 RawCurrent(): 0x7A and 0x7B

This read-only function returns the raw data from the coulomb counter.

### 4.35 RawVoltage(): 0x7C and 0x7D

This read-only function returns the raw data from the cell voltage reading.

### 4.36 RawIntTemp(): 0x7E and 0x7F

This read-only function returns the raw data from the internal temperature measurement.

### 4.37 RawExtTemp(): 0x80 and 0x81

This read-only function returns the raw data from the external temperature measurement.

## Data Memory Interface

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### 5.1 Accessing the Data Memory

The data memory contains initialization, default, cell status, calibration, configuration, and user information. Most data memory parameters reside in volatile RAM initialized by associated parameters from ROM. The data memory can be accessed two different ways, depending in which mode the fuel gauge is operating and what data is being accessed.

Most data memory locations are only accessible in the UNSEALED mode by use of the evaluation software ([bqStudio](#) + EV2400) or by data memory block transfers. These locations should be optimized and/or fixed during the development and manufacturing processes. They become part of a golden image file and then can be written to multiple battery packs. Once established, the values generally remain unchanged during end-equipment operation.

### 5.2 Device Access Modes

The fuel gauge provides two access modes, UNSEALED and SEALED, that control the data memory access permissions. The default access mode of the fuel gauge is UNSEALED, so the system processor must send a SEALED subcommand after a gauge reset to use the data protection feature.

### 5.3 Sealing and Unsealing Data Memory Access

The fuel gauge implements a key-access scheme to transition from SEALED to UNSEALED mode. Once SEALED via the associated subcommand, a unique set of two keys must be sent to the fuel gauge via the *Control()* command to return to UNSEALED mode. The keys must be sent consecutively, with no other data being written to the *Control()* register in between. When in SEALED mode, the *OperationStatus[SEC]* bits (*SEC1, SEC0*) are set to 11; but when the Sealed to Unsealed keys are correctly received by the fuel gauge, the *[SEC]* bits (*SEC1, SEC0*) transition to 10.

The unseal code is 0x1404 followed by 0x7236 and must be sent in little endian order.

Write 0xAA 0x00 0x04 0x14

Write 0xAA 0x00 0x36 0x72

The two commands must be run within 4 seconds and with no other commands in between them or the device will remain sealed.

## Data Memory Summary

The [Data Memory Table](#) shows the data memory locations, including their defaults and minimum and maximum values, that are available to customers.

**Table 6-1. Data Type Decoder**

Type	Min Value	Max Value
F4	$\pm 9.8603 \times 10^{-39}$	$\pm 5.707267 \times 10^{37}$
H1	0x00	0xFF
H2	0x00	0xFFFF
H4	0x00	0xFFFF FFFF
I1	-128	127
I2	-32768	32767
I4	-2,147,483,648	2,147,483,647
Sx	1-byte string	x-byte string
U1	0	255
U2	0	65535
U4	0	4,294,967,295

**Table 6-2. Data Memory Table**

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
Calibration	Offset	0x91F2	Board Offset	I1	-128	127	0	Counts
Calibration	Offset	0x91F3	Int Temp Offset	I1	-128	127	0	0.1°C
Calibration	Offset	0x91F4	Ext Temp Offset	I1	-128	127	0	0.1°C
Calibration	Offset	0x91F5	Pack V Offset	I1	-128	127	0	mV
Calibration	Temperature	0x91F6	Internal Model Coefficient 1	I2	-32768	32767	0	Num
Calibration	Temperature	0x91F8	Internal Model Coefficient 2	I2	-32768	32767	0	Num
Calibration	Temperature	0x91FA	Internal Model Coefficient 3	I2	-32768	32767	-13356	Num
Calibration	Temperature	0x91FC	Internal Model Coefficient 4	I2	-32768	32767	6661	Num
Calibration	Temperature	0x91FE	External Model Coefficient 1	I2	-32768	32767	-11130	Num
Calibration	Temperature	0x9200	External Model Coefficient 2	I2	-32768	32767	19142	Num
Calibration	Temperature	0x9202	External Model Coefficient 3	I2	-32768	32767	-19262	Num
Calibration	Temperature	0x9204	External Model Coefficient 4	I2	-32768	32767	28203	Num
Calibration	Temperature	0x9206	External Model Coefficient 5	I2	-32768	32767	892	Num
Calibration	Temperature	0x9208	External Model Coefficient b <sub>1</sub>	I2	-32768	32767	328	Num
Calibration	Temperature	0x920A	External Model Coefficient b <sub>2</sub>	I2	-32768	32767	-605	Num
Calibration	Temperature	0x920C	External Model Coefficient b <sub>3</sub>	I2	-32768	32767	-2443	Num
Calibration	Temperature	0x920E	External Model Coefficient b <sub>4</sub>	I2	-32768	32767	4696	Num
Calibration	Temperature	0x9210	RC0	I2	-32768	32767	11703	Counts
Calibration	Temperature	0x9212	Voltage Comp Coefficient 1	I2	-32768	32767	7320	Num
Calibration	Temperature	0x9214	Voltage Comp Coefficient 2	I2	-32768	32767	723	Num
Calibration	Temperature	0x9216	Voltage Comp Coefficient 3	I2	-32768	32767	-71	Num

**Table 6-2. Data Memory Table (continued)**

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
Calibration	Temperature	0x9218	Voltage Comp Input Multiplier	U1	0	255	48	Num
Calibration	Temperature	0x9219	Voltage Comp Output Divisor	I2	-32768	32767	256	Num
Calibration	Current	0x921B	Filter	U1	0	255	239	Num
Calibration	Current	0x921C	Deadband	U1	0	255	5	mA
Calibration	Current	0x921D	CC Deadband	U1	0	255	68	73 nV
Calibration	Current	0x9233	CC Offset	I2	-32767	32767	0	Counts
Calibration	Current	0x9237	CC Gain	F4	-4.0e+00	4.0e+00	-0.231	—
Calibration	Current	0x923B	CC Delta	F4	-3.0e+06	3.0e+06	-283945.0625	—
Charger Control	Charge Inhibit Cfg	0x923F	Chg Inhibit Temp Low	I2	-400	1200	0	0.1°C
Charger Control	Charge Inhibit Cfg	0x9241	Chg Inhibit Temp High	I2	-400	1200	450	0.1°C
Charger Control	Charge Inhibit Cfg	0x9243	Temp Hys	I2	0	100	50	0.1°C
Charger Control	JEITA Temperature	0x9245	T1 Temp	I2	-400	1200	0	0.1°C
Charger Control	JEITA Temperature	0x9247	T2 Temp	I2	-400	1200	100	0.1°C
Charger Control	JEITA Temperature	0x9249	T3 Temp	I2	-400	1200	450	0.1°C
Charger Control	JEITA Temperature	0x924B	T4 Temp	I2	-400	1200	550	0.1°C
Charger Control	Charge Termination	0x924D	Maintenance Current	I2	0	1000	0	mA
Charger Control	Charge Termination	0x924F	Taper Current	I2	0	1000	100	mA
Charger Control	Charge Termination	0x9251	Minimum Taper Capacity	I2	0	1000	25	0.01 mAh
Charger Control	Charge Termination	0x9253	Current Taper Window	U1	0	60	40	s
Charger Control	NiMH Charge Termination	0x9254	Delta Temperature	I2	-400	1200	30	0.1°C
Charger Control	NiMH Charge Termination	0x9256	Delta Temperature Time	U2	0	255	100	s
Charger Control	NiMH Charge Termination	0x9258	Holdoff Time	U2	0	255	180	s
Charger Control	NiMH Charge Termination	0x925A	Holdoff Current	I2	0	32767	240	mA
Charger Control	NiMH Charge Termination	0x925C	Holdoff Temperature	I2	-400	1200	250	0.1°C
Charger Control	NiMH Charge Termination	0x925E	Cell Negative Delta Voltage	I2	0	32767	17	mV
Charger Control	NiMH Charge Termination	0x9260	Cell Negative Delta Time	U1	0	255	16	s
Charger Control	NiMH Charge Termination	0x9261	Cell Negative Delta Qual Voltage	I2	0	32767	2400	mV
Safety	OTC	0x9292	OT Chg	I2	0	1200	550	0.1°C
Safety	OTC	0x9294	OT Chg Time	U1	0	60	2	s
Safety	OTC	0x9295	OT Chg Recovery	I2	0	1200	500	0.1°C
Safety	OTD	0x9297	OT Dsg	I2	0	1200	600	0.1°C
Safety	OTD	0x9299	OT Dsg Time	U1	0	60	2	s
Safety	OTD	0x929A	OT Dsg Recovery	I2	0	1200	550	0.1°C
Safety	UTC	0x929C	UT Chg	I2	-400	1200	0	0.1°C
Safety	UTC	0x929E	UT Chg Time	U1	0	60	2	s
Safety	UTC	0x929F	UT Chg Recovery	I2	-400	1200	50	0.1°C
Safety	UTD	0x92A1	UT Dsg	I2	-400	1200	0	0.1°C
Safety	UTD	0x92A3	UT Dsg Time	U1	0	60	2	s
Safety	UTD	0x92A4	UT Dsg Recovery	I2	-400	1200	50	0.1°C
Safety	BATLOW	0x92A6	Battery Low Set Threshold	I2	0	5000	3150	mV

**Table 6-2. Data Memory Table (continued)**

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
Safety	BATLOW	0x92A8	Battery Low Time	U1	0	60	2	s
Safety	BATLOW	0x92A9	Battery Low Clear Threshold	I2	0	5000	3400	mV
Safety	BATHIGH	0x92AB	Battery High Set Threshold	I2	0	5000	4300	mV
Safety	BATHIGH	0x92AD	Battery High Time	U1	0	60	2	s
Safety	BATHIGH	0x92AE	Battery High Clear Threshold	I2	0	5000	4200	mV
Safety	SOCLOW	0x92B0	SOC Low Threshold	U1	0	100	10	%
Safety	SOCLOW	0x92B1	SOC Low Recovery	U1	0	100	30	%
Configuration	Registers	0x9263	Operation Config A	H2	0x0000	0xFFFF	0x0484	Hex
Configuration	Registers	0x9272	Device Type	H2	0x0000	0xFFFF	0x0210	Hex
Configuration	Power	0x9277	Sleep Current	I2	0	100	10	mA
Configuration	Power	0x9279	Bus Low Time	U1	0	255	5	s
Configuration	Power	0x927A	Offset Cal Inhibit Temp Low	I2	-400	1200	50	0.1°C
Configuration	Power	0x927C	Offset Cal Inhibit Temp High	I2	-400	1200	450	0.1°C
Configuration	Power	0x927E	Sleep Voltage Time	U1	0	100	20	s
Configuration	Power	0x927F	Sleep Current Time	U1	0	255	20	s
Configuration	Current Thresholds	0x9284	Discharge Detection Threshold	I2	0	2000	60	mA
Configuration	Current Thresholds	0x9286	Charge Detection Threshold	I2	0	2000	75	mA
Configuration	Current Thresholds	0x9288	Quit Current	I2	0	1000	40	mA
Configuration	Current Thresholds	0x928A	Discharge Relax Time	U2	0	8191	60	s
Configuration	Current Thresholds	0x928C	Charge Relax Time	U1	0	255	60	s
Configuration	Current Thresholds	0x928D	Quit Relax Time	U1	0	63	1	s
Configuration	SOC	0x92ED	Flag Config A	H2	0x0	0x0FFF	0x0C8C	Hex
Configuration	SOC	0x92EF	Flag Config B	H1	0x0	0xFF	0x8C	Hex
Settings	Configuration	0x9266	Alert_0 Config	H1	0x00	0xFF	0x00	Hex
Settings	Configuration	0x9267	Alert_1 Config	H1	0x00	0xFF	0x00	Hex
Settings	Configuration	0x9268	Alert_2 Config	H1	0x00	0xFF	0x00	Hex
Settings	Configuration	0x9269	Alert_3 Config	H1	0x00	0xFF	0x00	Hex
Settings	Configuration	0x926A	Alert_4 Config	H1	0x00	0xFF	0x00	Hex
Settings	Configuration	0x926B	Alert_5 Config	H1	0x00	0xFF	0x00	Hex
Settings	Configuration	0x926C	Alert_6 Config	H1	0x00	0xFF	0x00	Hex
Settings	Configuration	0x930A	EOS Configuration	H1	0x0	0x0F	0x00	Hex
Settings	Accumulated Charge	0x928E	Accum Charge Positive Threshold	I2	0	32767	1000	mAh
Settings	Accumulated Charge	0x9290	Accum Charge Negative Threshold	I2	0	32767	1000	mAh
Settings	Manufacturing	0x9308	Mfg Status Init	H2	0x0	0xFFFF	0x0007	Hex
Gas Gauging	Cycle	0x92EB	Cycle Count Percentage	U1	0	100	90	%
Gas Gauging	FD	0x92F0	Set Voltage Threshold	I2	0	5000	3000	mV
Gas Gauging	FD	0x92F2	Clear Voltage Threshold	I2	0	5000	3100	mV
Gas Gauging	FD	0x92F4	Set % RSOC Threshold	U1	0	100	0	%
Gas Gauging	FD	0x92F5	Clear % RSOC Threshold	U1	0	100	5	%
Gas Gauging	FC	0x92F6	Set Voltage Threshold	I2	0	5000	4200	mV
Gas Gauging	FC	0x92F8	Clear Voltage Threshold	I2	0	5000	4100	mV
Gas Gauging	FC	0x92FA	Set % RSOC Threshold	U1	0	100	100	%
Gas Gauging	FC	0x92FB	Clear % RSOC Threshold	U1	0	100	95	%
Gas Gauging	TD	0x92FC	Set Voltage Threshold	I2	0	5000	3200	mV
Gas Gauging	TD	0x92FE	Clear Voltage Threshold	I2	0	5000	3300	mV
Gas Gauging	TD	0x9300	Set % RSOC Threshold	U1	0	100	6	%

**Table 6-2. Data Memory Table (continued)**

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
Gas Gauging	TD	0x9301	Clear % RSOC Threshold	U1	0	100	8	%
Gas Gauging	TC	0x9302	Set Voltage Threshold	I2	0	5000	4200	mV
Gas Gauging	TC	0x9304	Clear Voltage Threshold	I2	0	5000	4100	mV
Gas Gauging	TC	0x9306	Set % RSOC Threshold	U1	0	100	100	%
Gas Gauging	TC	0x9307	Clear % RSOC Threshold	U1	0	100	95	%
Gas Gauging	CEDV Configuration	0x92BE	Battery Low %	U2	0	65535	700	.01%
Gas Gauging	CEDV Configuration	0x92C8	Learning Low Temp	U1	0	255	119	0.1°C
Gas Gauging	CEDV Configuration	0x92D1	OverLoad Current	I2	0	32767	3400	mA
Gas Gauging	CEDV Configuration	0x92D5	Self Discharge Rate	U1	0	255	20	0.01%/day
Gas Gauging	CEDV Configuration	0x92D6	Electronics Load	I2	0	255	0	3 μA
Gas Gauging	CEDV Configuration	0x92D8	Near Full	I2	0	32767	200	mAh
Gas Gauging	CEDV Configuration	0x92DA	Reserve Capacity	I2	0	32767	0	mAh
Gas Gauging	CEDV Configuration	0x92DC	Chg Eff	U1	0	100	100	%
Gas Gauging	CEDV Configuration	0x92DD	Dsg Eff	U1	0	100	100	%
Gas Gauging	CEDV Cfg	0x92DE	RemCap Init Percent	U1	0	110	100	%
Gas Gauging	CEDV Profile 1	0x9345	Gauging Configuration	H2	0x0	0x1FFF	0x102A	Hex
Gas Gauging	CEDV Profile 1	0x9347	Full Charge Capacity	I2	0	32767	3000	mAh
Gas Gauging	CEDV Profile 1	0x9349	Design Capacity	I2	0	32767	2200	mAh
Gas Gauging	CEDV Profile 1	0x934D	Design Voltage	I2	0	32767	3700	mV
Gas Gauging	CEDV Profile 1	0x934F	Charge Termination Voltage	I2	0	1000	100	mV
Gas Gauging	CEDV Profile 1	0x9351	EMF	U2	0	65535	3743	—
Gas Gauging	CEDV Profile 1	0x9353	C0	U2	0	65535	149	—
Gas Gauging	CEDV Profile 1	0x9355	R0	U2	0	65535	867	—
Gas Gauging	CEDV Profile 1	0x9357	T0	U2	0	65535	4030	—
Gas Gauging	CEDV Profile 1	0x9359	R1	U2	0	65535	316	—
Gas Gauging	CEDV Profile 1	0x935B	TC	U1	0	255	9	—
Gas Gauging	CEDV Profile 1	0x935C	C1	U1	0	255	0	—
Gas Gauging	CEDV Profile 1	0x935D	Age Factor	U1	0	255	0	—
Gas Gauging	CEDV Profile 1	0x935E	Fixed EDV 0	I2	0	32767	3031	mV
Gas Gauging	CEDV Profile 1	0x9360	EDV 0 Hold Time	U1	1	255	1	s
Gas Gauging	CEDV Profile 1	0x9361	Fixed EDV 1	I2	0	32767	3385	mV
Gas Gauging	CEDV Profile 1	0x9363	EDV 1 Hold Time	U1	1	255	1	s
Gas Gauging	CEDV Profile 1	0x9364	Fixed EDV 2	I2	0	32767	3501	mV
Gas Gauging	CEDV Profile 1	0x9366	EDV 2 Hold Time	U1	1	255	1	s
Gas Gauging	CEDV Profile 1	0x9367	Voltage 0% DOD	I2	-32768	32767	4173	mV
Gas Gauging	CEDV Profile 1	0x9369	Voltage 10% DOD	I2	-32768	32767	4043	mV
Gas Gauging	CEDV Profile 1	0x936B	Voltage 20% DOD	I2	-32768	32767	3925	mV
Gas Gauging	CEDV Profile 1	0x936D	Voltage 30% DOD	I2	-32768	32767	3821	mV
Gas Gauging	CEDV Profile 1	0x936F	Voltage 40% DOD	I2	-32768	32767	3725	mV
Gas Gauging	CEDV Profile 1	0x9371	Voltage 50% DOD	I2	-32768	32767	3656	mV
Gas Gauging	CEDV Profile 1	0x9373	Voltage 60% DOD	I2	-32768	32767	3619	mV
Gas Gauging	CEDV Profile 1	0x9375	Voltage 70% DOD	I2	-32768	32767	3582	mV
Gas Gauging	CEDV Profile 1	0x9377	Voltage 80% DOD	I2	-32768	32767	3515	mV
Gas Gauging	CEDV Profile 1	0x9379	Voltage 90% DOD	I2	-32768	32767	3439	mV
Gas Gauging	CEDV Profile 1	0x937B	Voltage 100% DOD	I2	-32768	32767	2713	mV

**Table 6-2. Data Memory Table (continued)**

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
Gas Gauging	CEDV Profile 1	0x937D	JEITA Charge Current T1-T2	I2	0	32767	300	mA
Gas Gauging	CEDV Profile 1	0x937F	JEITA Charge Current T2-T3	I2	0	32767	1100	mA
Gas Gauging	CEDV Profile 1	0x9381	JEITA Charge Current T3-T4	I2	0	32767	660	mA
Gas Gauging	CEDV Profile 1	0x9383	JEITA Charge Voltage T1-T2	I2	0	32767	4100	mV
Gas Gauging	CEDV Profile 1	0x9385	JEITA Charge Voltage T2-T3	I2	0	32767	4200	mV
Gas Gauging	CEDV Profile 1	0x9387	JEITA Charge Voltage T3-T4	I2	0	32767	4100	mV
Gas Gauging	CEDV Smoothing Config	0x92DF	Smoothing Config	H1	0x00	0xFF	0x08	Hex
Gas Gauging	CEDV Smoothing Config	0x92E0	Smoothing Start Voltage	I2	0	5000	3700	mV
Gas Gauging	CEDV Smoothing Config	0x92E2	Smoothing Delta Voltage	I2	0	5000	100	mV
Gas Gauging	CEDV Smoothing Config	0x92E4	Max Smoothing Current	U2	0	65535	8000	mA
Gas Gauging	CEDV Smoothing Config	0x92E9	EOC Smooth Current	U1	0	10	2	0.1%
Gas Gauging	CEDV Smoothing Config	0x92EA	EOC Smooth Current Time	U1	0	255	60	s
End Of Service	Resistance Learning	0x930B	Auto Learn Time	U2	0	65535	1500	Hours
End Of Service	Resistance Learning	0x930D	Auto Learn Retry Time	U1	0	255	1	Hours
End Of Service	Resistance Learning	0x930E	Minimum Learn Time	U2	0	65535	750	Hours
End Of Service	Resistance Learning	0x9310	Alert-Warn Learn Time	U2	0	65535	750	Hours
End Of Service	Resistance Learning	0x9312	Initial Learn Pulse Number	U1	0	255	1	Counts
End Of Service	Resistance Learning	0x9313	Learn Charge Voltage Delta	I2	0	32767	100	mV
End Of Service	Resistance Learning	0x9315	Learn Charge Time Limit	U2	0	65535	3600	s
End Of Service	Resistance Learning	0x9317	Learn Discharge Current	I2	0	32767	220	mA
End Of Service	Resistance Learning	0x9319	Learn Discharge Current Boundary	I2	0	100	25	%
End Of Service	Resistance Learning	0x931B	Learn Discharge Time	U2	0	65535	500	s
End Of Service	Resistance Learning	0x931D	Learn Request Timeout	U1	0	255	4	s
End Of Service	Resistance Learning	0x931E	Learn Min Temperature	I2	-400	1500	100	0.1°C
End Of Service	Resistance Learning	0x9320	Learn Max Temperature	I2	-400	1500	400	0.1°C
End Of Service	Resistance Learning	0x9322	Learn Target Temperature	I2	-400	1500	250	0.1°C
End Of Service	Resistance Learning	0x9324	Rcell High Temp Coefficient	I2	-32768	32767	0	$2^{-16}$ /0.1°C
End Of Service	Resistance Learning	0x9326	Rcell Low Temp Coefficient	I2	-32768	32767	0	$2^{-16}$ /0.1°C
End Of Service	Direct Resistance Decision	0x932B	DRD Alert Level	U2	0	65535	45	%
End Of Service	Direct Resistance Decision	0x932D	DRD Alert Counts	U1	0	255	3	Counts
End Of Service	Direct Resistance Decision	0x932E	DRD Warning Level	U2	0	65535	60	%
End Of Service	Direct Resistance Decision	0x9330	DRD Warning Counts	U1	0	255	3	Counts
End Of Service	Direct Resistance Decision	0x933D	Initial Rcell	I2	0	32767	0	mΩ

**Table 6-2. Data Memory Table (continued)**

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
End Of Service	Direct Resistance Decision	0x933F	Initial Rcell Learned	U1	0	1	0	—
End Of Service	Resistance Slope Decision	0x9331	RSD Alert Level	U2	0	65535	15	%
End Of Service	Resistance Slope Decision	0x9333	RSD Alert Counts	U1	0	255	3	Counts
End Of Service	Resistance Slope Decision	0x9334	RSD Warning Level	U2	0	65535	30	%
End Of Service	Resistance Slope Decision	0x9336	RSD Warning Counts	U1	0	255	3	Counts
End Of Service	Resistance Slope Decision	0x9337	RSDL Alert Level	U2	0	65535	15	%
End Of Service	Resistance Slope Decision	0x9339	RSDL Warning Level	U2	0	65535	30	%
End Of Service	Resistance Slope Decision	0x9340	Initial RRate	I2	0	32767	0	—
End Of Service	Resistance Slope Decision	0x9342	Initial RRate Learned	U1	0	1	0	—
Calibration (ROM Default)	Offset	0x4800	Board Offset	I1	-128	127	0	Counts
Calibration (ROM Default)	Offset	0x4801	Int Temp Offset	I1	-128	127	0	0.1°C
Calibration (ROM Default)	Offset	0x4802	Ext Temp Offset	I1	-128	127	0	0.1°C
Calibration (ROM Default)	Offset	0x4803	Pack V Offset	I1	-128	127	0	mV
Calibration (ROM Default)	Temperature	0x4804	Internal Model Coefficient 1	I2	-32768	32767	0	Num
Calibration (ROM Default)	Temperature	0x4806	Internal Model Coefficient 2	I2	-32768	32767	0	Num
Calibration (ROM Default)	Temperature	0x4808	Internal Model Coefficient 3	I2	-32768	32767	-13356	Num
Calibration (ROM Default)	Temperature	0x480A	Internal Model Coefficient 4	I2	-32768	32767	6661	Num
Calibration (ROM Default)	Temperature	0x480C	External Model Coefficient 1	I2	-32768	32767	-11130	Num
Calibration (ROM Default)	Temperature	0x480E	External Model Coefficient 2	I2	-32768	32767	19142	Num
Calibration (ROM Default)	Temperature	0x4810	External Model Coefficient 3	I2	-32768	32767	-19262	Num
Calibration (ROM Default)	Temperature	0x4812	External Model Coefficient 4	I2	-32768	32767	28203	Num
Calibration (ROM Default)	Temperature	0x4814	External Model Coefficient 5	I2	-32768	32767	892	Num
Calibration (ROM Default)	Temperature	0x4816	External Model Coefficient b 1	I2	-32768	32767	328	Num
Calibration (ROM Default)	Temperature	0x4818	External Model Coefficient b 2	I2	-32768	32767	-605	Num
Calibration (ROM Default)	Temperature	0x481A	External Model Coefficient b 3	I2	-32768	32767	-2443	Num
Calibration (ROM Default)	Temperature	0x481C	External Model Coefficient b 4	I2	-32768	32767	4696	Num
Calibration (ROM Default)	Temperature	0x481E	RC0	I2	-32768	32767	11703	Counts
Calibration (ROM Default)	Temperature	0x4820	Voltage Comp Coefficient 1	I2	-32768	32767	7320	Num
Calibration (ROM Default)	Temperature	0x4822	Voltage Comp Coefficient 2	I2	-32768	32767	723	Num
Calibration (ROM Default)	Temperature	0x4824	Voltage Comp Coefficient 3	I2	-32768	32767	-71	Num
Calibration (ROM Default)	Temperature	0x4826	Voltage Comp Input Multiplier	U1	0	255	48	Num

**Table 6-2. Data Memory Table (continued)**

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
Calibration (ROM Default)	Temperature	0x4827	Voltage Comp Output Divisor	I2	-32768	32767	256	Num
Calibration (ROM Default)	Current	0x4829	Filter	U1	0	255	239	Num
Calibration (ROM Default)	Current	0x482A	Deadband	U1	0	255	5	mA
Calibration (ROM Default)	Current	0x482B	CC Deadband	U1	0	255	68	73 nV
Charger Control (ROM Default)	Charge Inhibit Cfg	0x4841	Chg Inhibit Temp Low	I2	-400	1200	0	0.1°C
Charger Control (ROM Default)	Charge Inhibit Cfg	0x4843	Chg Inhibit Temp High	I2	-400	1200	450	0.1°C
Charger Control (ROM Default)	Charge Inhibit Cfg	0x4845	Temp Hys	I2	0	100	50	0.1°C
Charger Control (ROM Default)	JEITA Temperature	0x4847	T1 Temp	I2	-400	1200	0	0.1°C
Charger Control (ROM Default)	JEITA Temperature	0x4849	T2 Temp	I2	-400	1200	100	0.1°C
Charger Control (ROM Default)	JEITA Temperature	0x484B	T3 Temp	I2	-400	1200	450	0.1°C
Charger Control (ROM Default)	JEITA Temperature	0x484D	T4 Temp	I2	-400	1200	550	0.1°C
Charger Control (ROM Default)	Charge Termination	0x484F	Maintenance Current	I2	0	1000	0	mA
Charger Control (ROM Default)	Charge Termination	0x4851	Taper Current	I2	0	1000	100	mA
Charger Control (ROM Default)	Charge Termination	0x4853	Minimum Taper Capacity	I2	0	1000	25	0.01 mAh
Charger Control (ROM Default)	Charge Termination	0x4855	Current Taper Window	U1	0	60	40	s
Charger Control (ROM Default)	NiMH Charge Termination	0x4856	Delta Temperature	I2	-400	1200	30	0.1°C
Charger Control (ROM Default)	NiMH Charge Termination	0x4858	Delta Temperature Time	U2	0	255	100	s
Charger Control (ROM Default)	NiMH Charge Termination	0x485A	Holdoff Time	U2	0	255	180	s
Charger Control (ROM Default)	NiMH Charge Termination	0x485C	Holdoff Current	I2	0	32767	240	mA
Charger Control (ROM Default)	NiMH Charge Termination	0x485E	Holdoff Temperature	I2	-400	1200	250	0.1°C
Charger Control (ROM Default)	NiMH Charge Termination	0x4860	Cell Negative Delta Voltage	I2	0	32767	17	mV
Charger Control (ROM Default)	NiMH Charge Termination	0x4862	Cell Negative Delta Time	U1	0	255	16	s
Charger Control (ROM Default)	NiMH Charge Termination	0x4863	Cell Negative Delta Qual Voltage	I2	0	32767	2400	mV
Safety (ROM Default)	OTC	0x4894	OT Chg	I2	0	1200	550	0.1°C
Safety (ROM Default)	OTC	0x4896	OT Chg Time	U1	0	60	2	s
Safety (ROM Default)	OTC	0x4897	OT Chg Recovery	I2	0	1200	500	0.1°C
Safety (ROM Default)	OTD	0x4899	OT Dsg	I2	0	1200	600	0.1°C
Safety (ROM Default)	OTD	0x489B	OT Dsg Time	U1	0	60	2	s
Safety (ROM Default)	OTD	0x489C	OT Dsg Recovery	I2	0	1200	550	0.1°C
Safety (ROM Default)	UTC	0x489E	UT Chg	I2	-400	1200	0	0.1°C
Safety (ROM Default)	UTC	0x48A0	UT Chg Time	U1	0	60	2	s

**Table 6-2. Data Memory Table (continued)**

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
Safety (ROM Default)	UTC	0x48A1	UT Chg Recovery	I2	-400	1200	50	0.1°C
Safety (ROM Default)	UTD	0x48A3	UT Dsg	I2	-400	1200	0	0.1°C
Safety (ROM Default)	UTD	0x48A5	UT Dsg Time	U1	0	60	2	s
Safety (ROM Default)	UTD	0x48A6	UT Dsg Recovery	I2	-400	1200	50	0.1°C
Safety (ROM Default)	BATLOW	0x48A8	Battery Low Set Threshold	I2	0	5000	3150	mV
Safety (ROM Default)	BATLOW	0x48AA	Battery Low Time	U1	0	60	2	s
Safety (ROM Default)	BATLOW	0x48AB	Battery Low Clear Threshold	I2	0	5000	3400	mV
Safety (ROM Default)	BATHIGH	0x48AD	Battery High Set Threshold	I2	0	5000	4300	mV
Safety (ROM Default)	BATHIGH	0x48AF	Battery High Time	U1	0	60	2	s
Safety (ROM Default)	BATHIGH	0x48B0	Battery High Clear Threshold	I2	0	5000	4200	mV
Safety (ROM Default)	SOCLOW	0x48B2	SOC Low Threshold	U1	0	100	10	%
Safety (ROM Default)	SOCLOW	0x48B3	SOC Low Recovery	U1	0	100	30	%
Configuration (ROM Default)	Registers	0x4865	Operation Config A	H2	0x0000	0xFFFF	0x0484	Hex
Configuration (ROM Default)	Registers	0x4874	Device Type	H2	0x0000	0xFFFF	0x0210	Hex
Configuration (ROM Default)	BLT	0x4870	Init Discharge Set	I2	0	32767	150	mAh
Configuration (ROM Default)	BLT	0x4872	Init Charge Set	I2	0	32767	175	mAh
Configuration (ROM Default)	Power	0x4879	Sleep Current	I2	0	100	10	mA
Configuration (ROM Default)	Power	0x487B	Bus Low Time	U1	0	255	5	s
Configuration (ROM Default)	Power	0x487C	Offset Cal Inhibit Temp Low	I2	-400	1200	50	0.1°C
Configuration (ROM Default)	Power	0x487E	Offset Cal Inhibit Temp High	I2	-400	1200	450	0.1°C
Configuration (ROM Default)	Power	0x4880	Sleep Voltage Time	U1	0	100	20	s
Configuration (ROM Default)	Power	0x4881	Sleep Current Time	U1	0	255	20	s
Configuration (ROM Default)	Current Thresholds	0x4886	Discharge Detection Threshold	I2	0	2000	60	mA
Configuration (ROM Default)	Current Thresholds	0x4888	Charge Detection Threshold	I2	0	2000	75	mA
Configuration (ROM Default)	Current Thresholds	0x488A	Quit Current	I2	0	1000	40	mA
Configuration (ROM Default)	Current Thresholds	0x488C	Discharge Relax Time	U2	0	8191	60	s
Configuration (ROM Default)	Current Thresholds	0x488E	Charge Relax Time	U1	0	255	60	s
Configuration (ROM Default)	Current Thresholds	0x488F	Quit Relax Time	U1	0	63	1	s
Configuration (ROM Default)	SOC	0x48EF	Flag Config A	H2	0x0	0xFFFF	0x0C8C	Hex
Configuration (ROM Default)	SOC	0x48F1	Flag Config B	H1	0x0	0xFF	0x8C	Hex
Settings (ROM Default)	Configuration	0x4868	Alert_0 Config	H1	0x00	0xFF	0x00	Hex

**Table 6-2. Data Memory Table (continued)**

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
Settings (ROM Default)	Configuration	0x4869	Alert_1 Config	H1	0x00	0xFF	0x00	Hex
Settings (ROM Default)	Configuration	0x486A	Alert_2 Config	H1	0x00	0xFF	0x00	Hex
Settings (ROM Default)	Configuration	0x486B	Alert_3 Config	H1	0x00	0xFF	0x00	Hex
Settings (ROM Default)	Configuration	0x486C	Alert_4 Config	H1	0x00	0xFF	0x00	Hex
Settings (ROM Default)	Configuration	0x486D	Alert_5 Config	H1	0x00	0xFF	0x00	Hex
Settings (ROM Default)	Configuration	0x486E	Alert_6 Config	H1	0x00	0xFF	0x00	Hex
Settings (ROM Default)	Configuration	0x490C	EOS Configuration	H1	0x0	0x0F	0x00	Hex
Settings (ROM Default)	Accumulated Charge	0x4890	Accum Charge Positive Threshold	I2	0	32767	1000	mAh
Settings (ROM Default)	Accumulated Charge	0x4892	Accum Charge Negative Threshold	I2	0	32767	1000	mAh
Settings (ROM Default)	Manufacturing	0x490A	Mfg Status Init	H2	0x0	0xFFFF	0x0007	Hex
Gas Gauging (ROM Default)	Cycle	0x48ED	Cycle Count Percentage	U1	0	100	90	%
Gas Gauging (ROM Default)	FD	0x48F2	Set Voltage Threshold	I2	0	5000	3000	mV
Gas Gauging (ROM Default)	FD	0x48F4	Clear Voltage Threshold	I2	0	5000	3100	mV
Gas Gauging (ROM Default)	FD	0x48F6	Set % RSOC Threshold	U1	0	100	0	%
Gas Gauging (ROM Default)	FD	0x48F7	Clear % RSOC Threshold	U1	0	100	5	%
Gas Gauging (ROM Default)	FC	0x48F8	Set Voltage Threshold	I2	0	5000	4200	mV
Gas Gauging (ROM Default)	FC	0x48FA	Clear Voltage Threshold	I2	0	5000	4100	mV
Gas Gauging (ROM Default)	FC	0x48FC	Set % RSOC Threshold	U1	0	100	100	%
Gas Gauging (ROM Default)	FC	0x48FD	Clear % RSOC Threshold	U1	0	100	95	%
Gas Gauging (ROM Default)	TD	0x48FE	Set Voltage Threshold	I2	0	5000	3200	mV
Gas Gauging (ROM Default)	TD	0x4900	Clear Voltage Threshold	I2	0	5000	3300	mV
Gas Gauging (ROM Default)	TD	0x4902	Set % RSOC Threshold	U1	0	100	6	%
Gas Gauging (ROM Default)	TD	0x4903	Clear % RSOC Threshold	U1	0	100	8	%
Gas Gauging (ROM Default)	TC	0x4904	Set Voltage Threshold	I2	0	5000	4200	mV
Gas Gauging (ROM Default)	TC	0x4906	Clear Voltage Threshold	I2	0	5000	4100	mV
Gas Gauging (ROM Default)	TC	0x4908	Set % RSOC Threshold	U1	0	100	100	%
Gas Gauging (ROM Default)	TC	0x4909	Clear % RSOC Threshold	U1	0	100	95	%
Gas Gauging (ROM Default)	CEDV Configuration	0x48C0	Battery Low %	U2	0	65535	700	.01%
Gas Gauging (ROM Default)	CEDV Configuration	0x48CA	Learning Low Temp	U1	0	255	119	0.1°C
Gas Gauging (ROM Default)	CEDV Configuration	0x48D3	OverLoad Current	I2	0	32767	3400	mA
Gas Gauging (ROM Default)	CEDV Configuration	0x48D7	Self Discharge Rate	U1	0	255	20	0.01%/day

**Table 6-2. Data Memory Table (continued)**

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
Gas Gauging (ROM Default)	CEDV Configuration	0x48D8	Electronics Load	I2	0	255	0	3 $\mu$ A
Gas Gauging (ROM Default)	CEDV Configuration	0x48DA	Near Full	I2	0	32767	200	mAh
Gas Gauging (ROM Default)	CEDV Configuration	0x48DC	Reserve Capacity	I2	0	32767	0	mAh
Gas Gauging (ROM Default)	CEDV Configuration	0x48DE	Chg Eff	U1	0	100	100	%
Gas Gauging (ROM Default)	CEDV Configuration	0x48DF	Dsg Eff	U1	0	100	100	%
Gas Gauging (ROM Default)	CEDV Cfg	0x48E0	RemCap Init Percent	U1	0	110	100	%
Gas Gauging (ROM Default)	CEDV Profile 1	0x4947	Gauging Configuration	H2	0x0	0x1FFF	0x102A	Hex
Gas Gauging (ROM Default)	CEDV Profile 1	0x4949	Full Charge Capacity	I2	0	32767	2200	mAh
Gas Gauging (ROM Default)	CEDV Profile 1	0x494B	Design Capacity	I2	0	32767	2200	mAh
Gas Gauging (ROM Default)	CEDV Profile 1	0x494F	Design Voltage	I2	0	32767	3700	mV
Gas Gauging (ROM Default)	CEDV Profile 1	0x4951	Charge Termination Voltage	I2	0	1000	100	mV
Gas Gauging (ROM Default)	CEDV Profile 1	0x4953	EMF	U2	0	65535	3743	—
Gas Gauging (ROM Default)	CEDV Profile 1	0x4955	C0	U2	0	65535	149	—
Gas Gauging (ROM Default)	CEDV Profile 1	0x4957	R0	U2	0	65535	867	—
Gas Gauging (ROM Default)	CEDV Profile 1	0x4959	T0	U2	0	65535	4030	—
Gas Gauging (ROM Default)	CEDV Profile 1	0x495B	R1	U2	0	65535	316	—
Gas Gauging (ROM Default)	CEDV Profile 1	0x495D	TC	U1	0	255	9	—
Gas Gauging (ROM Default)	CEDV Profile 1	0x495E	C1	U1	0	255	0	—
Gas Gauging (ROM Default)	CEDV Profile 1	0x495F	Age Factor	U1	0	255	0	—
Gas Gauging (ROM Default)	CEDV Profile 1	0x4960	Fixed EDV 0	I2	0	32767	3031	mV
Gas Gauging (ROM Default)	CEDV Profile 1	0x4962	EDV 0 Hold Time	U1	1	255	1	s
Gas Gauging (ROM Default)	CEDV Profile 1	0x4963	Fixed EDV 1	I2	0	32767	3385	mV
Gas Gauging (ROM Default)	CEDV Profile 1	0x4965	EDV 1 Hold Time	U1	1	255	1	s
Gas Gauging (ROM Default)	CEDV Profile 1	0x4966	Fixed EDV 2	I2	0	32767	3501	mV
Gas Gauging (ROM Default)	CEDV Profile 1	0x4968	EDV 2 Hold Time	U1	1	255	1	s
Gas Gauging (ROM Default)	CEDV Profile 1	0x4969	Voltage 0% DOD	I2	-32768	32767	4173	mV
Gas Gauging (ROM Default)	CEDV Profile 1	0x496B	Voltage 10% DOD	I2	-32768	32767	4043	mV
Gas Gauging (ROM Default)	CEDV Profile 1	0x496D	Voltage 20% DOD	I2	-32768	32767	3925	mV
Gas Gauging (ROM Default)	CEDV Profile 1	0x496F	Voltage 30% DOD	I2	-32768	32767	3821	mV
Gas Gauging (ROM Default)	CEDV Profile 1	0x4971	Voltage 40% DOD	I2	-32768	32767	3725	mV
Gas Gauging (ROM Default)	CEDV Profile 1	0x4973	Voltage 50% DOD	I2	-32768	32767	3656	mV

**Table 6-2. Data Memory Table (continued)**

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
Gas Gauging (ROM Default)	CEDV Profile 1	0x4975	Voltage 60% DOD	I2	-32768	32767	3619	mV
Gas Gauging (ROM Default)	CEDV Profile 1	0x4977	Voltage 70% DOD	I2	-32768	32767	3582	mV
Gas Gauging (ROM Default)	CEDV Profile 1	0x4979	Voltage 80% DOD	I2	-32768	32767	3515	mV
Gas Gauging (ROM Default)	CEDV Profile 1	0x497B	Voltage 90% DOD	I2	-32768	32767	3439	mV
Gas Gauging (ROM Default)	CEDV Profile 1	0x497D	Voltage 100% DOD	I2	-32768	32767	2713	mV
Gas Gauging (ROM Default)	CEDV Profile 1	0x497F	JEITA Charge Current T1-T2	I2	0	32767	300	mA
Gas Gauging (ROM Default)	CEDV Profile 1	0x4981	JEITA Charge Current T2-T3	I2	0	32767	1100	mA
Gas Gauging (ROM Default)	CEDV Profile 1	0x4983	JEITA Charge Current T3-T4	I2	0	32767	660	mA
Gas Gauging (ROM Default)	CEDV Profile 1	0x4985	JEITA Charge Voltage T1-T2	I2	0	32767	4100	mV
Gas Gauging (ROM Default)	CEDV Profile 1	0x4987	JEITA Charge Voltage T2-T3	I2	0	32767	4200	mV
Gas Gauging (ROM Default)	CEDV Profile 1	0x4989	JEITA Charge Voltage T3-T4	I2	0	32767	4100	mV
Gas Gauging (ROM Default)	CEDV Profile 2	0x498B	Gauging Configuration	H2	0x0	0x1FFF	0x102A	Hex
Gas Gauging (ROM Default)	CEDV Profile 2	0x498D	Full Charge Capacity	I2	0	32767	1450	mAh
Gas Gauging (ROM Default)	CEDV Profile 2	0x498F	Design Capacity	I2	0	32767	1450	mAh
Gas Gauging (ROM Default)	CEDV Profile 2	0x4993	Design Voltage	I2	0	32767	3200	mV
Gas Gauging (ROM Default)	CEDV Profile 2	0x4995	Charge Termination Voltage	I2	0	1000	100	mV
Gas Gauging (ROM Default)	CEDV Profile 2	0x4997	EMF	U2	0	65535	3616	—
Gas Gauging (ROM Default)	CEDV Profile 2	0x4999	C0	U2	0	65535	640	—
Gas Gauging (ROM Default)	CEDV Profile 2	0x499B	R0	U2	0	65535	7956	—
Gas Gauging (ROM Default)	CEDV Profile 2	0x499D	T0	U2	0	65535	4931	—
Gas Gauging (ROM Default)	CEDV Profile 2	0x499F	R1	U2	0	65535	650	—
Gas Gauging (ROM Default)	CEDV Profile 2	0x49A1	TC	U1	0	255	6	—
Gas Gauging (ROM Default)	CEDV Profile 2	0x49A2	C1	U1	0	255	0	—
Gas Gauging (ROM Default)	CEDV Profile 2	0x49A3	Age Factor	U1	0	255	0	—
Gas Gauging (ROM Default)	CEDV Profile 2	0x49A4	Fixed EDV 0	I2	0	32767	2008	mV
Gas Gauging (ROM Default)	CEDV Profile 2	0x49A6	EDV 0 Hold Time	U1	1	255	1	s
Gas Gauging (ROM Default)	CEDV Profile 2	0x49A7	Fixed EDV 1	I2	0	32767	2876	mV
Gas Gauging (ROM Default)	CEDV Profile 2	0x49A9	EDV 1 Hold Time	U1	1	255	1	s
Gas Gauging (ROM Default)	CEDV Profile 2	0x49AA	Fixed EDV 2	I2	0	32767	3108	mV
Gas Gauging (ROM Default)	CEDV Profile 2	0x49AC	EDV 2 Hold Time	U1	1	255	1	s
Gas Gauging (ROM Default)	CEDV Profile 2	0x49AD	Voltage 0% DOD	I2	-32768	32767	3355	mV

**Table 6-2. Data Memory Table (continued)**

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
Gas Gauging (ROM Default)	CEDV Profile 2	0x49AF	Voltage 10% DOD	I2	-32768	32767	3284	mV
Gas Gauging (ROM Default)	CEDV Profile 2	0x49B1	Voltage 20% DOD	I2	-32768	32767	3283	mV
Gas Gauging (ROM Default)	CEDV Profile 2	0x49B3	Voltage 30% DOD	I2	-32768	32767	3277	mV
Gas Gauging (ROM Default)	CEDV Profile 2	0x49B5	Voltage 40% DOD	I2	-32768	32767	3248	mV
Gas Gauging (ROM Default)	CEDV Profile 2	0x49B7	Voltage 50% DOD	I2	-32768	32767	3242	mV
Gas Gauging (ROM Default)	CEDV Profile 2	0x49B9	Voltage 60% DOD	I2	-32768	32767	3238	mV
Gas Gauging (ROM Default)	CEDV Profile 2	0x49BB	Voltage 70% DOD	I2	-32768	32767	3229	mV
Gas Gauging (ROM Default)	CEDV Profile 2	0x49BD	Voltage 80% DOD	I2	-32768	32767	3184	mV
Gas Gauging (ROM Default)	CEDV Profile 2	0x49BF	Voltage 90% DOD	I2	-32768	32767	3146	mV
Gas Gauging (ROM Default)	CEDV Profile 2	0x49C1	Voltage 100% DOD	I2	-32768	32767	2008	mV
Gas Gauging (ROM Default)	CEDV Profile 2	0x49C3	JEITA Charge Current T1-T2	I2	0	32767	198	mA
Gas Gauging (ROM Default)	CEDV Profile 2	0x49C5	JEITA Charge Current T2-T3	I2	0	32767	725	mA
Gas Gauging (ROM Default)	CEDV Profile 2	0x49C7	JEITA Charge Current T3-T4	I2	0	32767	435	mA
Gas Gauging (ROM Default)	CEDV Profile 2	0x49C9	JEITA Charge Voltage T1-T2	I2	0	32767	3550	mV
Gas Gauging (ROM Default)	CEDV Profile 2	0x49CB	JEITA Charge Voltage T2-T3	I2	0	32767	3650	mV
Gas Gauging (ROM Default)	CEDV Profile 2	0x49CD	JEITA Charge Voltage T3-T4	I2	0	32767	3550	mV
Gas Gauging (ROM Default)	CEDV Smoothing Config	0x48E1	Smoothing Config	H1	0x00	0xFF	0x08	Hex
Gas Gauging (ROM Default)	CEDV Smoothing Config	0x48E2	Smoothing Start Voltage	I2	0	5000	3700	mV
Gas Gauging (ROM Default)	CEDV Smoothing Config	0x48E4	Smoothing Delta Voltage	I2	0	5000	100	mV
Gas Gauging (ROM Default)	CEDV Smoothing Config	0x48E6	Max Smoothing Current	U2	0	65535	8000	mA
Gas Gauging (ROM Default)	CEDV Smoothing Config	0x48EB	EOC Smooth Current	U1	0	10	2	0.1%
Gas Gauging (ROM Default)	CEDV Smoothing Config	0x48EC	EOC Smooth Current Time	U1	0	255	60	s
End Of Service (ROM Default)	Resistance Learning	0x490D	Auto Learn Time	U2	0	65535	1500	Hours
End Of Service (ROM Default)	Resistance Learning	0x490F	Auto Learn Retry Time	U1	0	255	1	Hours
End Of Service (ROM Default)	Resistance Learning	0x4910	Minimum Learn Time	U2	0	65535	750	Hours
End Of Service (ROM Default)	Resistance Learning	0x4912	Alert-Warn Learn Time	U2	0	65535	750	Hours
End Of Service (ROM Default)	Resistance Learning	0x4914	Initial Learn Pulse Number	U1	0	255	1	Counts
End Of Service (ROM Default)	Resistance Learning	0x4915	Learn Charge Voltage Delta	I2	0	32767	100	mV
End Of Service (ROM Default)	Resistance Learning	0x4917	Learn Charge Time Limit	U2	0	65535	3600	s
End Of Service (ROM Default)	Resistance Learning	0x4919	Learn Discharge Current	I2	0	32767	220	mA
End Of Service (ROM Default)	Resistance Learning	0x491B	Learn Discharge Current Boundary	I2	0	100	25	%

**Table 6-2. Data Memory Table (continued)**

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
End Of Service (ROM Default)	Resistance Learning	0x491D	Learn Discharge Time	U2	0	65535	500	s
End Of Service (ROM Default)	Resistance Learning	0x491F	Learn Request Timeout	U1	0	255	4	s
End Of Service (ROM Default)	Resistance Learning	0x4920	Learn Min Temperature	I2	-400	1500	100	0.1°C
End Of Service (ROM Default)	Resistance Learning	0x4922	Learn Max Temperature	I2	-400	1500	400	0.1°C
End Of Service (ROM Default)	Resistance Learning	0x4924	Learn Target Temperature	I2	-400	1500	250	0.1°C
End Of Service (ROM Default)	Resistance Learning	0x4926	Rcell High Temp Coefficient	I2	-32768	32767	0	$2^{-16}$ /0.1°C
End Of Service (ROM Default)	Resistance Learning	0x4928	Rcell Low Temp Coefficient	I2	-32768	32767	0	$2^{-16}$ /0.1°C
End Of Service (ROM Default)	Direct Resistance Decision	0x492D	DRD Alert Level	U2	0	65535	45	%
End Of Service (ROM Default)	Direct Resistance Decision	0x492F	DRD Alert Counts	U1	0	255	3	Counts
End Of Service (ROM Default)	Direct Resistance Decision	0x4930	DRD Warning Level	U2	0	65535	60	%
End Of Service (ROM Default)	Direct Resistance Decision	0x4932	DRD Warning Counts	U1	0	255	3	Counts
End Of Service (ROM Default)	Resistance Slope Decision	0x4933	RSD Alert Level	U2	0	65535	15	%
End Of Service (ROM Default)	Resistance Slope Decision	0x4935	RSD Alert Counts	U1	0	255	3	Counts
End Of Service (ROM Default)	Resistance Slope Decision	0x4936	RSD Warning Level	U2	0	65535	30	%
End Of Service (ROM Default)	Resistance Slope Decision	0x4938	RSD Warning Counts	U1	0	255	3	Counts
End Of Service (ROM Default)	Resistance Slope Decision	0x4939	RSDL Alert Level	U2	0	65535	15	%
End Of Service (ROM Default)	Resistance Slope Decision	0x493B	RSDL Warning Level	U2	0	65535	30	%

## Application Example

### 7.1 Data Memory Parameter Update Example

The following example shows the command sequence needed to modify a data memory parameter in RAM. For this example, the default Design Capacity is updated from 2200 mAh to 1200 mAh. All device writes (wr) and reads (rd) refer to the I<sup>2</sup>C 8-bit addresses 0xAA and 0xAB, respectively.

Step	Description	Pseudo Code
1	If the device was previously SEALED, UNSEAL it by sending the appropriate keys to <i>Control()</i> (0x00 and 0x01).	//Two-byte incremental method wr 0x00 0x14 0x04; wr 0x00 0x72 0x36; //Alternative single byte method wr 0x00 0x14; wr 0x01 0x04; wr 0x00 0x72; wr 0x01 0x36;
2	Send ENTER_CFG_UPDATE command (0x0090).	wr 0x00 0x90 0x00;
3	Confirm CFGUPDATE mode by polling <i>OperationStatus()</i> register until bit 2 is set. May take up to 1 second.	rd 0x3B <i>OperationStatus()</i> ;
4	Write 0x49 to 0x3E to access the MSB of <b>Design Capacity</b> .	wr 0x3E 0x49;
5	Write 0x93 to 0x3F to access the LSB of <b>Design Capacity</b> .	wr 0x3F 0x93;
6	Read the 1-byte checksum using <i>MACDataSum()</i> command (0x60).	rd 0x60 Old_Chksum; (0x6F)
7	Read the 1-byte block length using the <i>MACDataLen()</i> command (0x61).	rd 0x61 Data_len; (0x24)
8	Write 0x49 to 0x3E to access the MSB of <b>Design Capacity</b> .	wr 0x3E 0x49;
9	Write 0x93 to 0x3F to access the LSB of <b>Design Capacity</b> .	wr 0x3F 0x93;
10	Read both <b>Design Capacity</b> bytes starting at 0x40.	rd 0x40 Old_DC_MSB; (0x08) rd 0x41 Old_DC_LSB; (0x98)
11	Write both <b>Design Capacity</b> bytes starting at 0x40. For this example, the new value is 1200 mAh. (0x04B0 in hex)	wr 0x40 0x04; wr 0x41 0xB0;
12	Calculate the new checksum. The checksum is (255 – x) where x is the 8-bit summation of the <i>BlockData()</i> (0x40 to 0x5F) on a byte-by-byte basis. A quick way to calculate the new checksum uses a data replacement method with the old and new data summation bytes. Refer to the code for the indicated method.	Temp = mod(255 – Old_Chksum – OLD_DC_MSB – OLD_DC_LSB, 256); New_Chksum = 255 – mod(temp + 0x04 + 0xB0, 256); (0x5B)
13	Write new checksum. For this example, New_Chksum is 0xB0;	wr 0x60 New_Chksum; //Example: wr 0x60 0x5B;
14	Write the block length. The data is actually transferred to the RAM when the correct checksum and length for the whole block is written. For this example, Data_len is 0x24;	wr 0x61 Data_len; //Example: wr 0x61 0x24;
15	Exit CFGUPDATE mode by sending either EXIT_CFG_UPDATE_REINIT (0x0091) or EXIT_CFG_UPDATE (0x0092) commands.	wr 0x00 0x91 0x00; or wr 0x00 0x92 0x00;
16	Confirm CFGUPDATE mode by polling <i>OperationStatus()</i> register until bit 2 is clear. May take up to 1 second.	rd 0x3B <i>OperationStatus()</i> ;
17	If the device was previously SEALED, return to SEALED mode by sending the Control (0x0030) subcommand.	wr 0x00 0x30 0x00;

## 7.2 GAUGEPARCAL

GAUGEPARCAL, the Gauge Parameter Calculator (sometimes called GPC), helps battery designers obtain matching Compensated End of Discharge Voltage (CEDV) coefficients for the specific battery profile. The GPC tool enables a user to increase the accuracy of the fuel gauge IC over temperature. For more information and detailed documents, go to the [GAUGEPARCAL](#) product page.

### Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Date	Revision	Notes
September 2018	*	Initial Release

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